



Interaction between Beams and Vacuum System Walls.

R. Cimino,
LNF INFN, Frascati, Italy.

Interaction between Beams and Vacuum System Walls.

- Phenomenology:

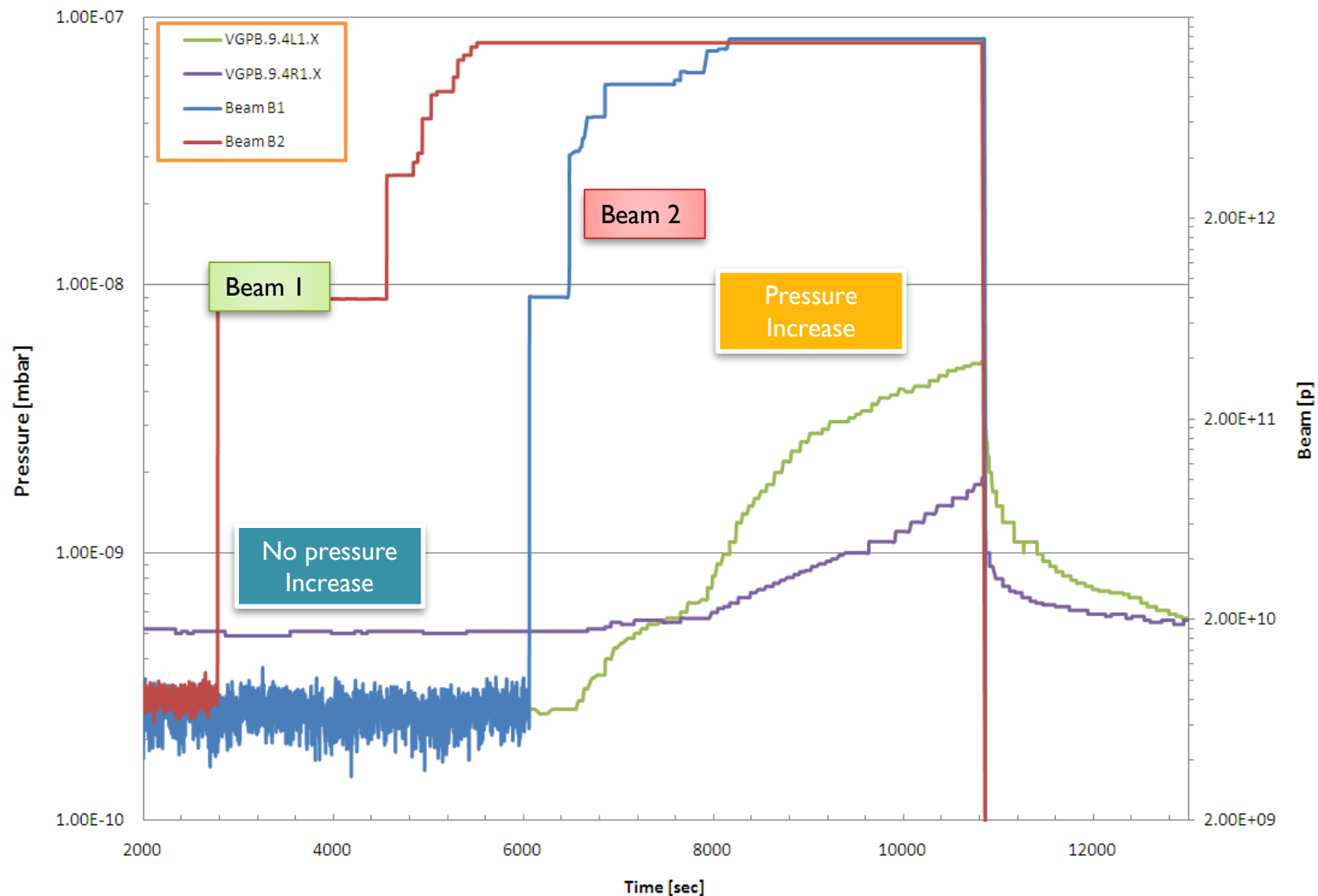
What happens to the Vacuum beam pipe in presence of the beam?

- Synchrotron radiation: Heat Load, Photo-electrons and electron induced desorption
- Ion induced desorption and associated instability.
- Desorption yields and conditioning.
- “Electron cloud” effects and associated instabilities
- Additional materials → Addendum
- Mitigation strategies
- Conclusion

One real example to see what the beam does to Vacuum: 8-10-2010

**450 GeV – 150 ns bunch spacing:
Merged vacuum @ LHC**

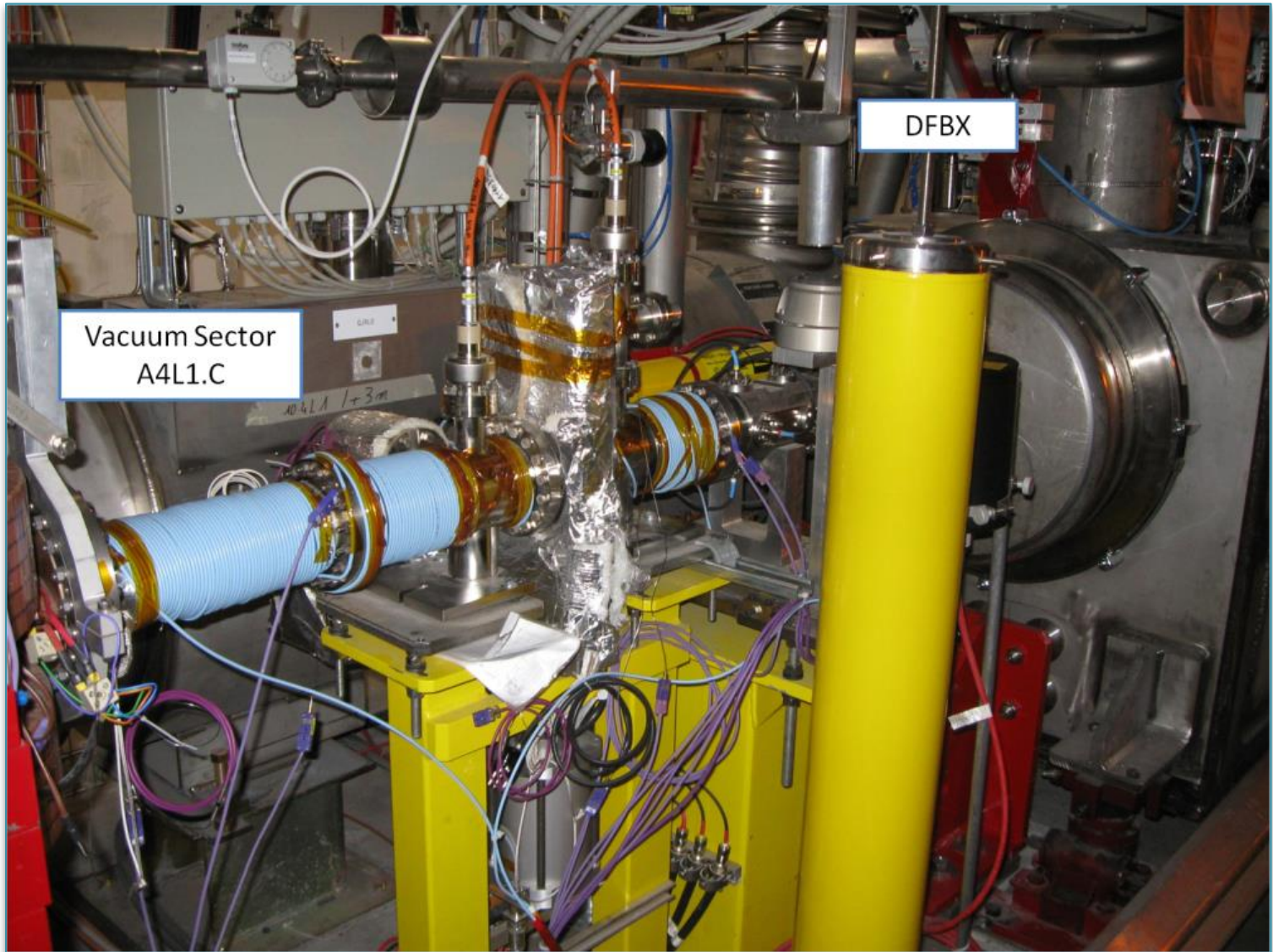
Exotic Vacuum behavior @ LHC:



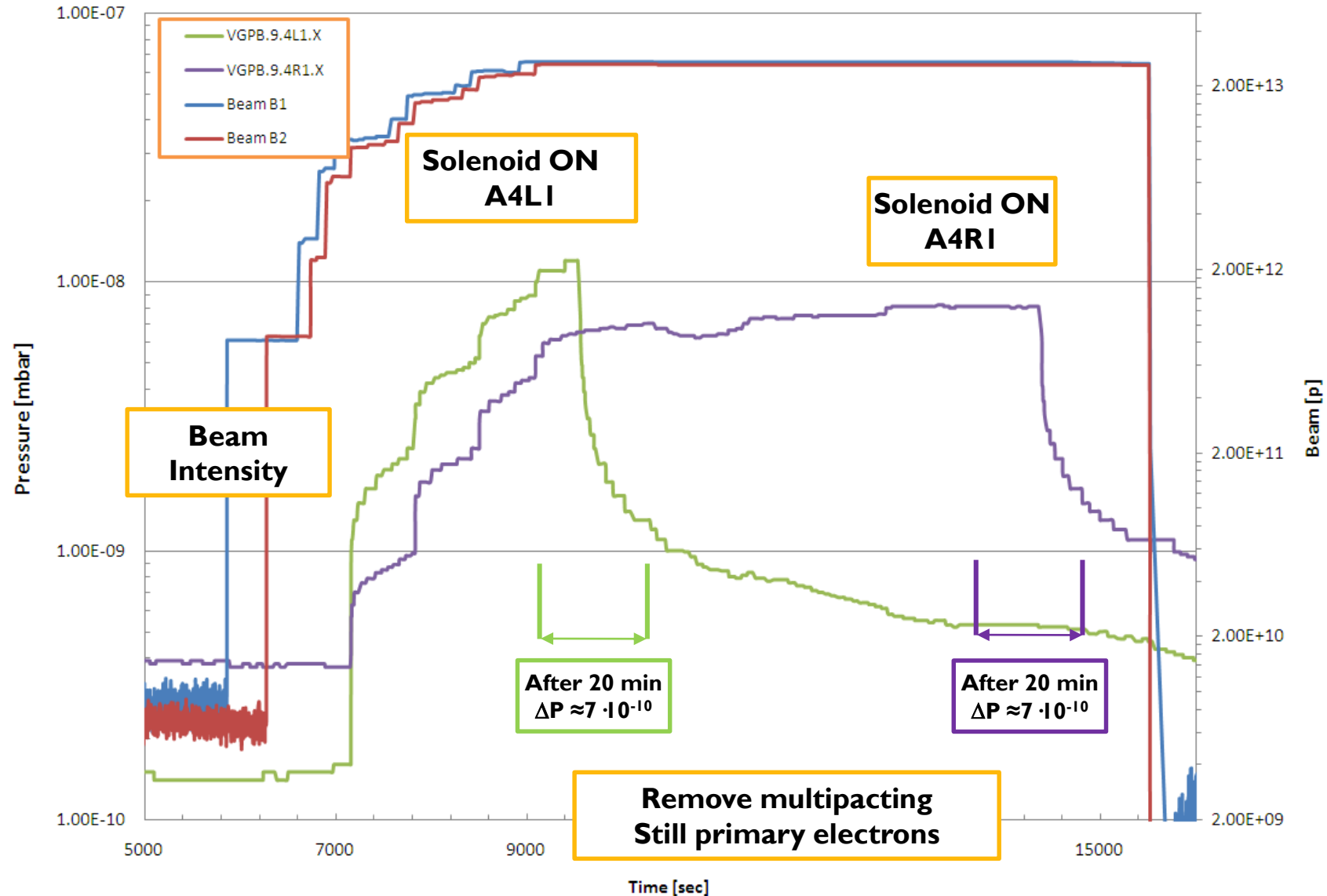
450 GeV – 150 ns bunch spacing: Merged vacuum

8-10-2010

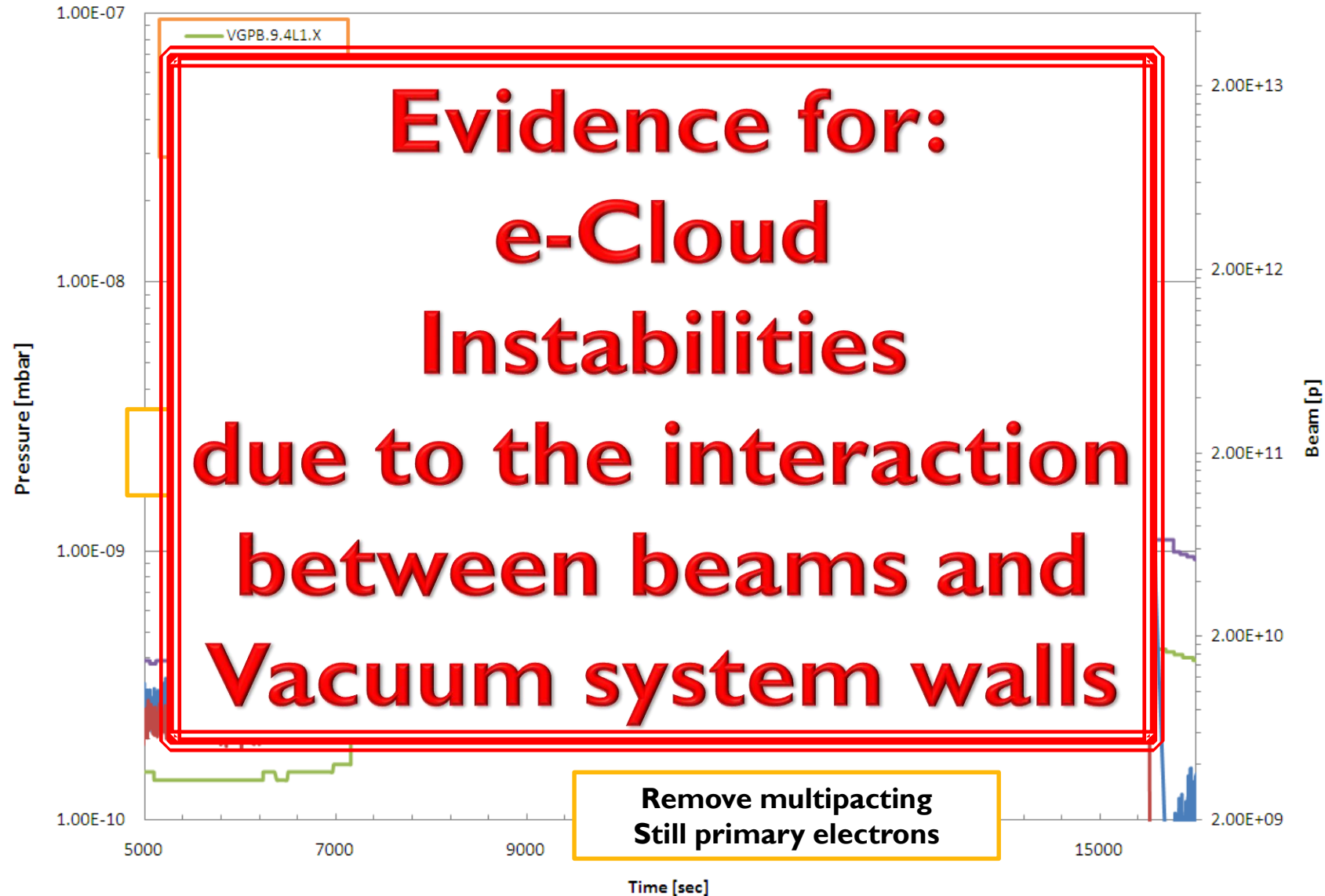
Easily solved: Installation of Solenoids



Solenoids have effect on pressure!!!



Solenoids have effect on pressure!!!



Vacuum in new generation accelerators is much “more” than a technical issue!

- Let us see what may cause such beam and/or pressure instabilities.
- The case of the:

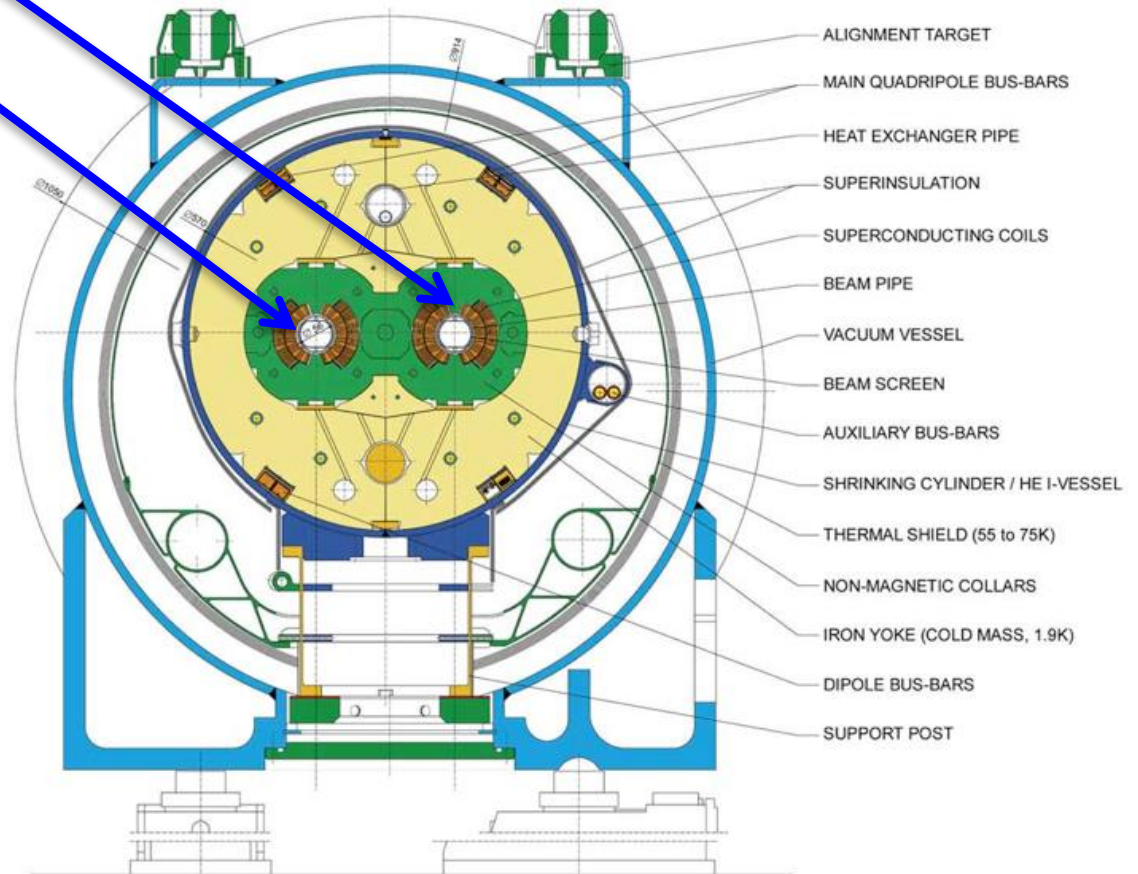
LHC arcs

Cold Bore @ 1.9 K

Static

LHC DIPOLE : STANDARD CROSS-SECTION

CERN Accelerator School - HE107 - 30-04-1999



Extreme High Static Vacuum ($\ll 10^{-13}$ Torr)

Static

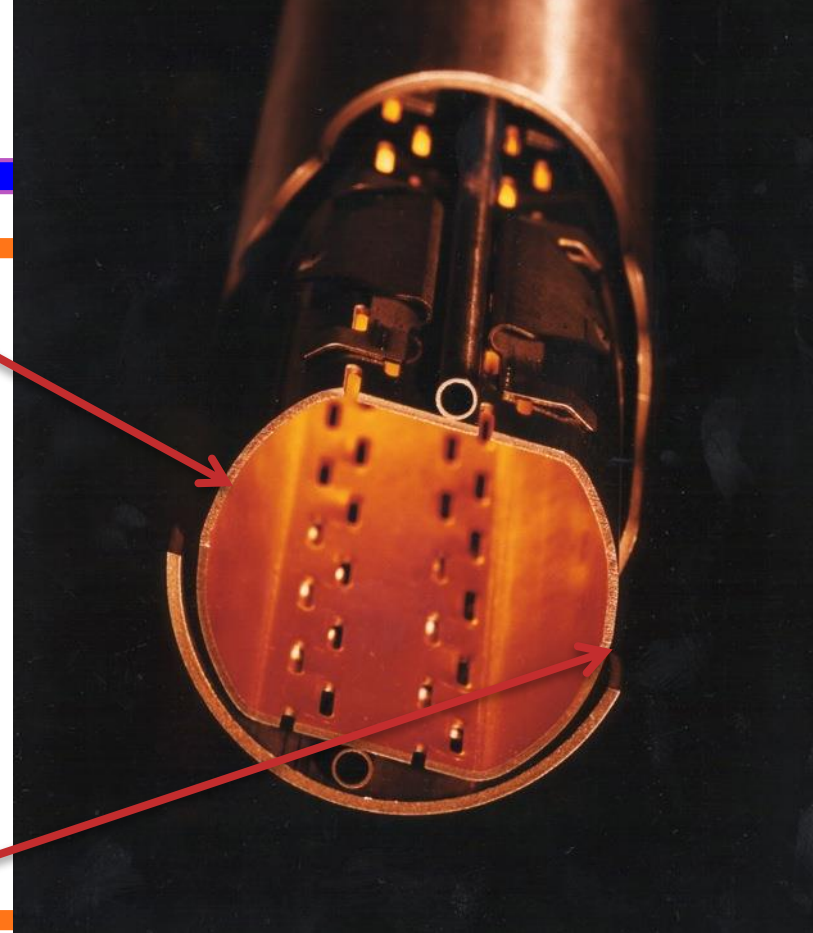
Cold Bore @ 1.9 K

Radial Distance

Need of a Beam Screen

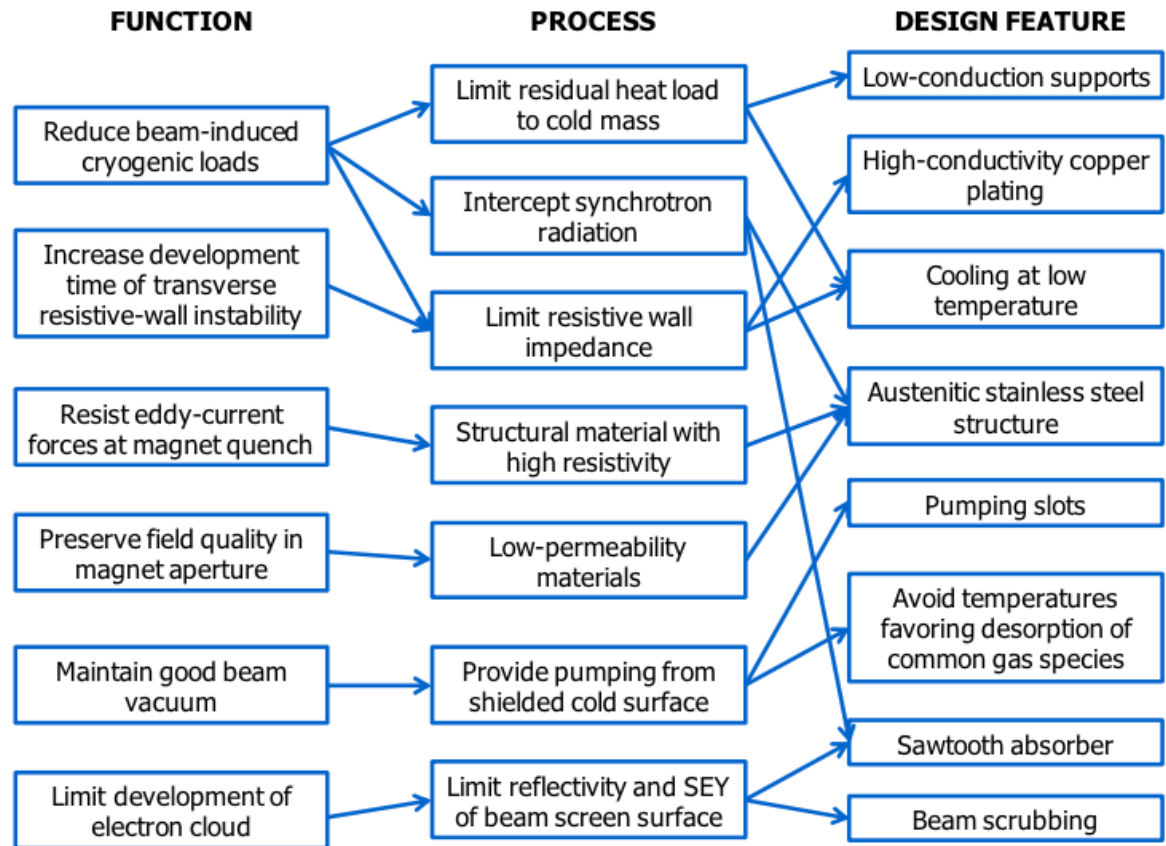
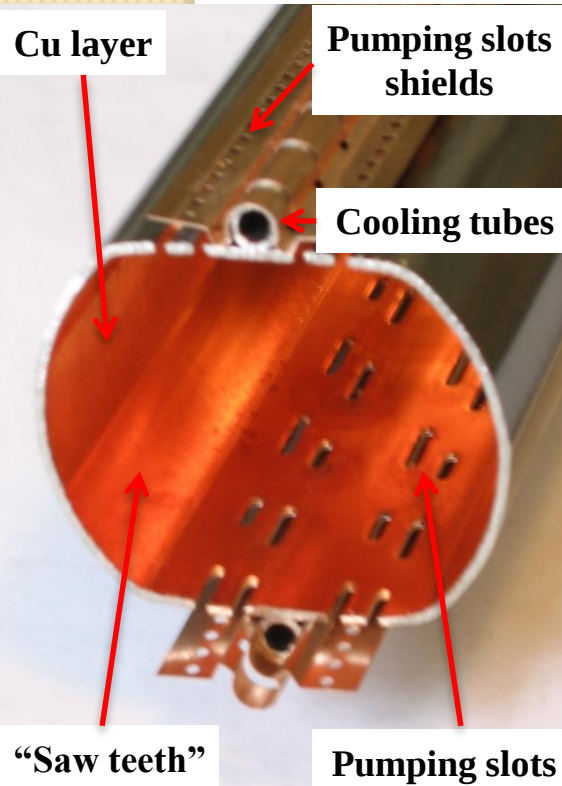
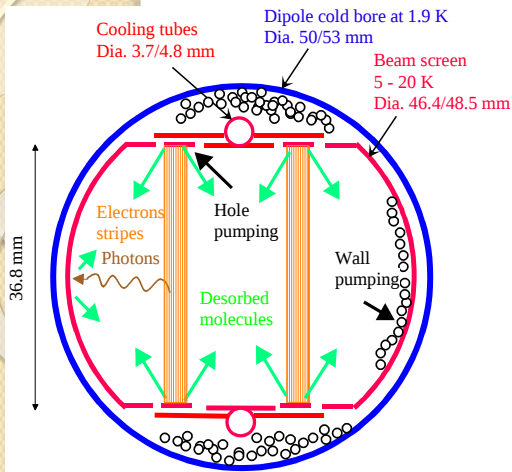
@ $5\text{K} < T < 20\text{K}$

to reduce heat load (SR,
Eddy current, Impedance,
etc...) on Cold bore for
thermal load issues



$T=0$, without beam

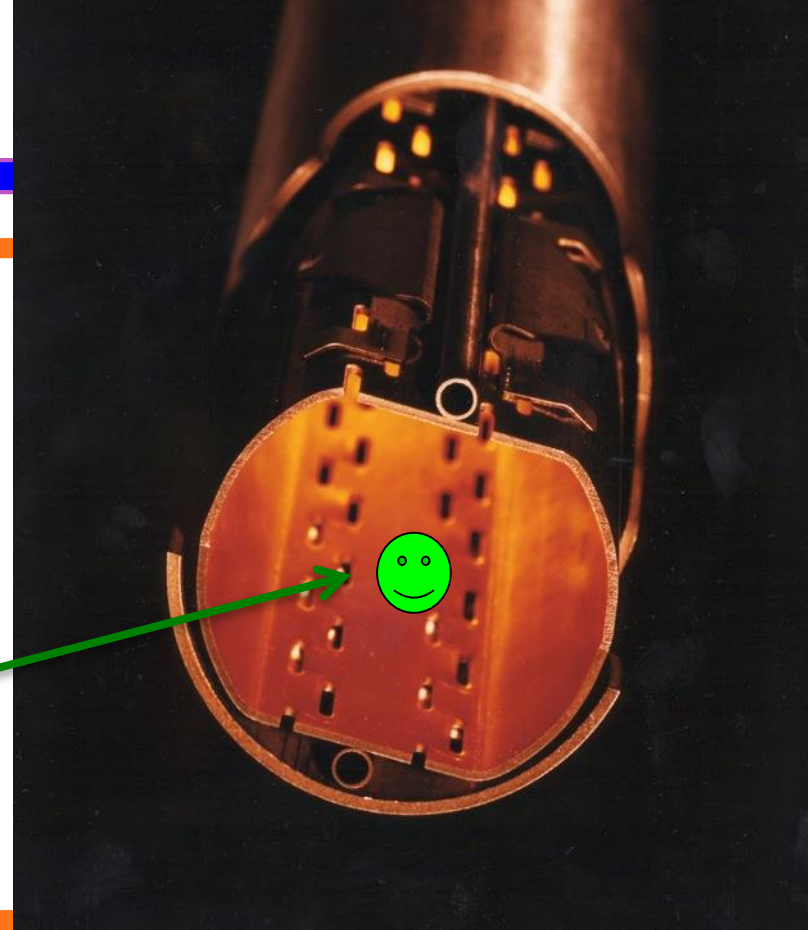
The Beam Screen is a complex technological product!



Static Cold Bore @ 1.9 K

Let us see what happens during operation and beam passage to:

- The vacuum system
- the Beam screen Surface



$T=0$, without beam

Beam – Gas Interactions

CB

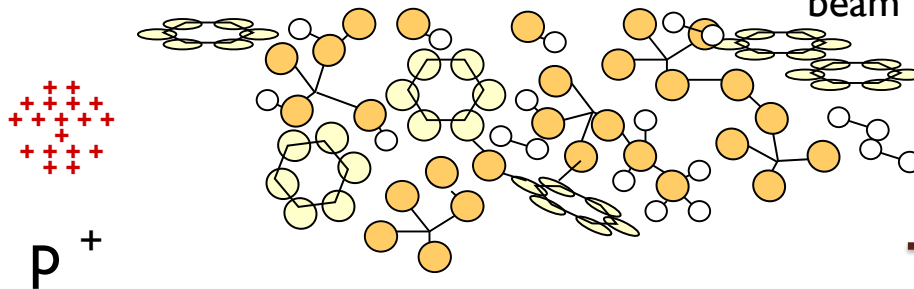
BS

The beam interacts with the residual gas:

$$dI = -I \sigma n dx \rightarrow \frac{dI}{dt} = -I n v \sigma$$

•Where:

- σ is the cross section i.e. the **probability** the beam interacts with the atoms of target
- I is the beam intensity
- n is the atomic density of a target of thickness dx
- v is the beam velocity



$$I = I_0 e^{-\frac{t}{\tau}}$$

This define: Vacuum Beam Life time (τ)

$$\tau = \frac{1}{n \sigma v}$$

For a vacuum system:

$$\frac{1}{\tau} = \frac{1}{\tau_{H_2}} + \frac{1}{\tau_{CH_4}} + \frac{1}{\tau_{H_2O}} + \frac{1}{\tau_{CO}} + \frac{1}{\tau_{CO_2}}$$

The vacuum life time must be much larger (i.e. $\gg 24$ h) than other life times such as e.g. the particle loss due to the collisions



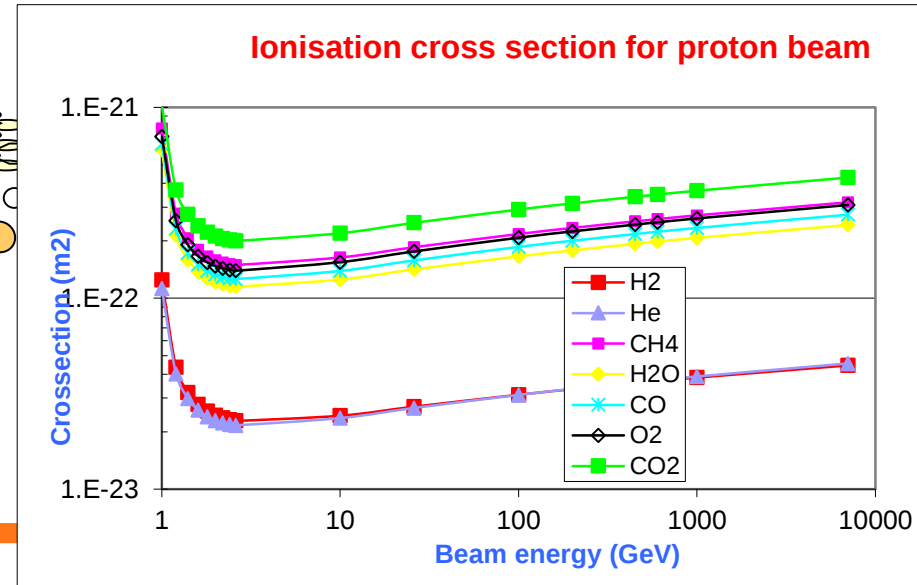
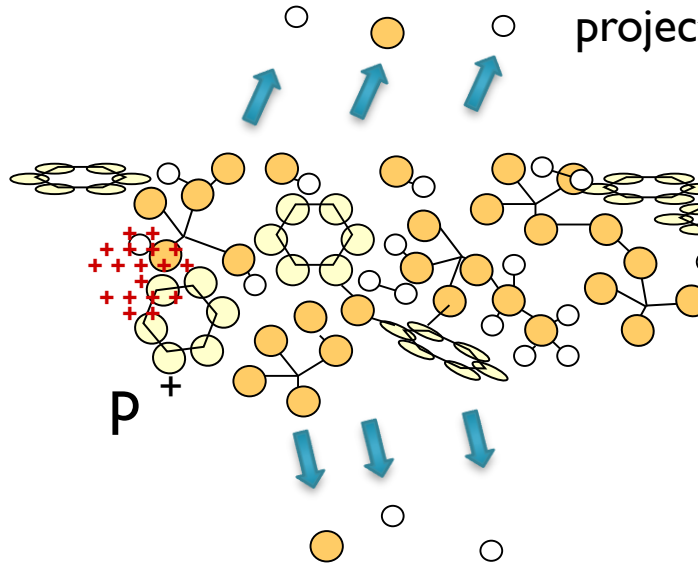
Beam – Gas Interactions: ion production

Radial Distance

CB

BS

Ionisation cross section is a function of the speed & the charge of the projectile and of the nature of the residual gas



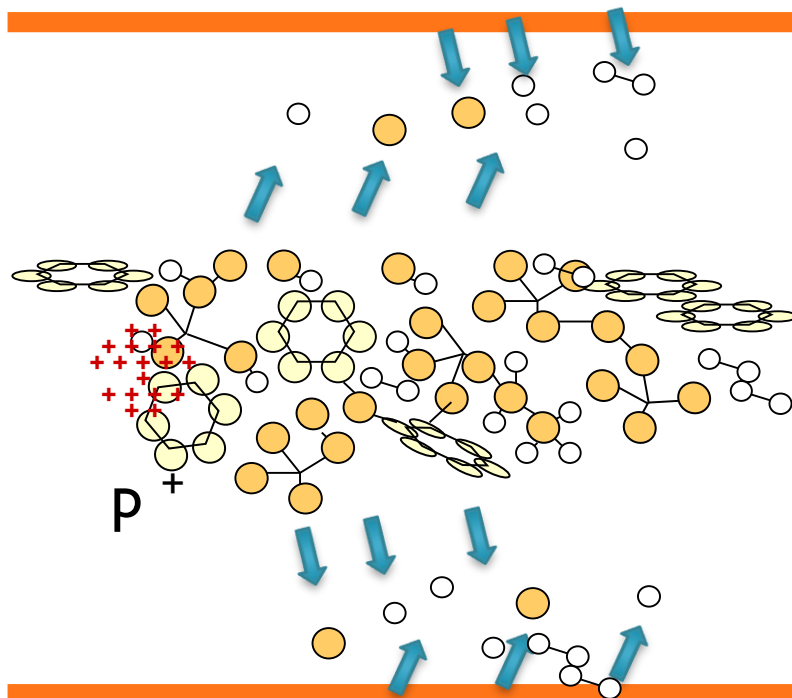
→ Heavy gas must be avoided

Ions interact with accelerator wall: Ion desorption yield

Radial Distance

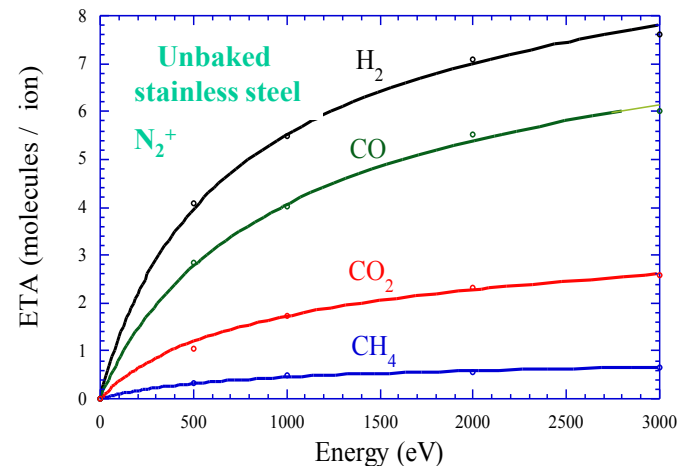
CB

BS



Varies with:

- the material,
- the ion energy
- and ion species



A.G. Mathewson, CERN ISR-VA/76-5

• Several molecules can be desorbed per ion → Sputtering

- Ionised gas will hit the Accelerator wall and induce ion desorption.
- Pressure and beam ion interaction will increase, increasing desorption
- Such a resonant phenomenon will cause Vacuum instability and there will be a critical beam current, at which the pressure increases to infinity.

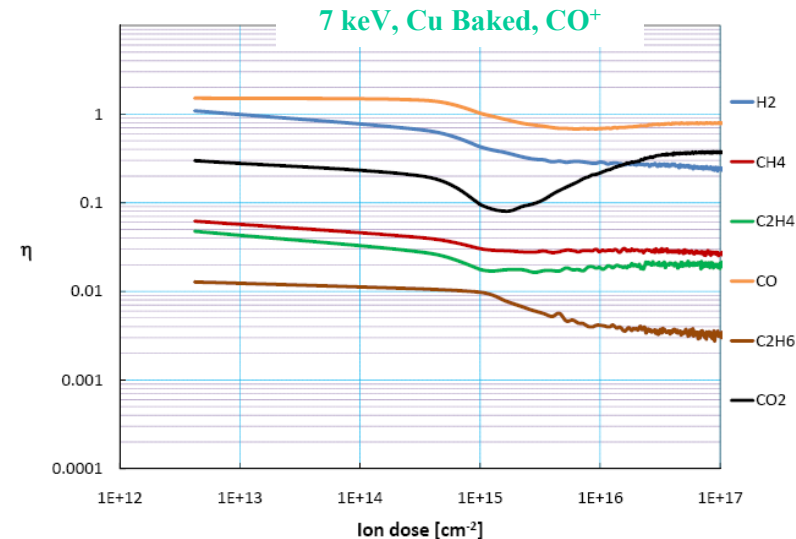
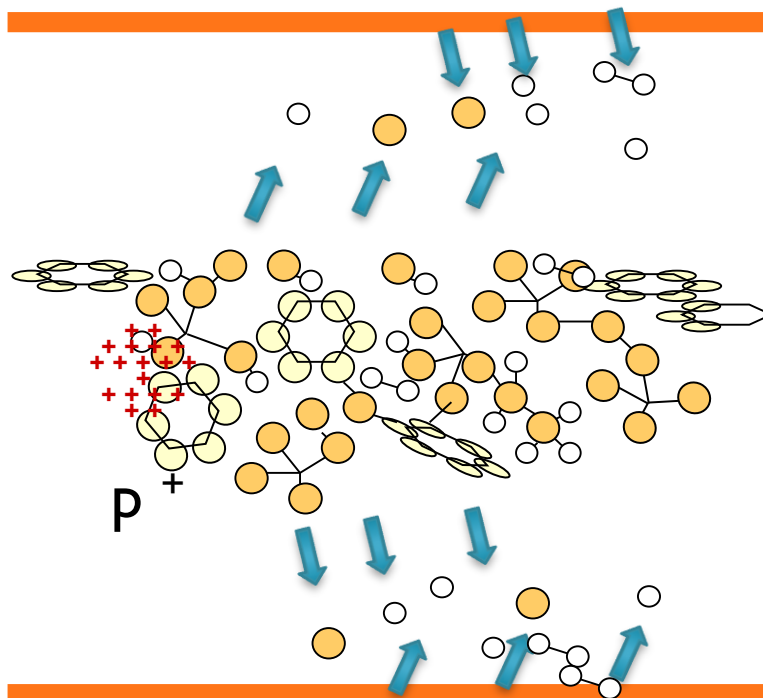
Ions interact with accelerator wall: Ion desorption yield.

Conditioning and implantation

Radial Distance

CB

BS



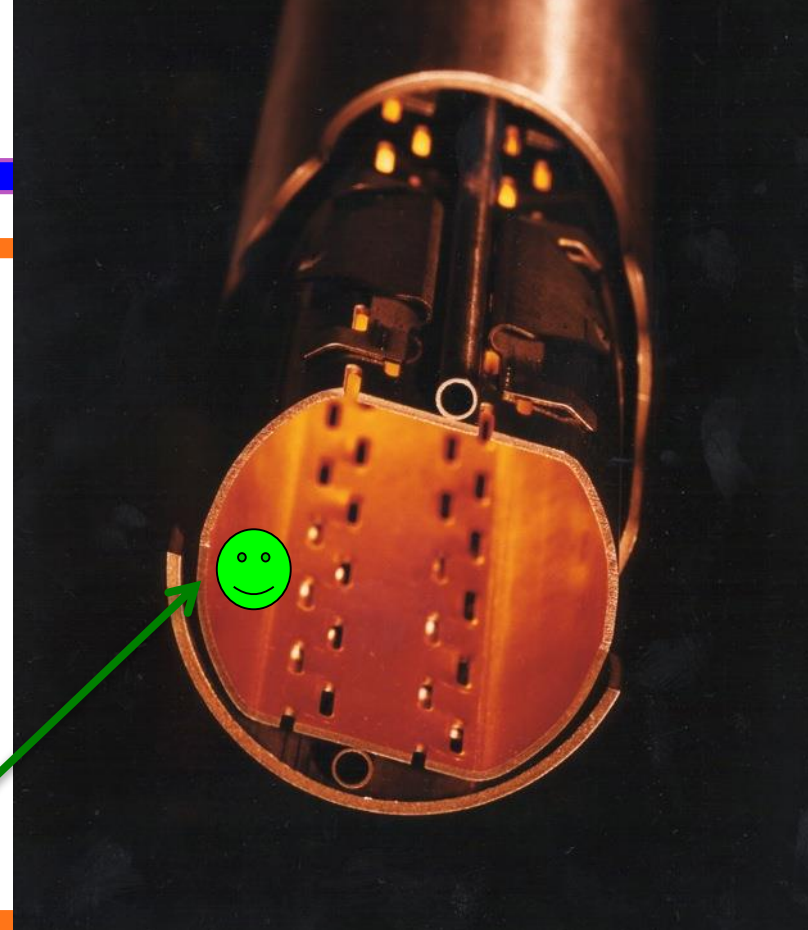
G. Hulla, PhD Thesis, Vienna Tech. U, 2009

- In the LHC : the maximum flux is about $3 \cdot 10^8$ ions/(cm².s) i.e. a dose of $3 \cdot 10^{15}$ ions/(cm².year)
- In the LHC, there is no conditioning due to ion bombardment

Static Cold Bore @ 1.9 K

Let us see what happens during operation and beam passage to:

- The vacuum system
- the Beam screen Surface



$T=0$, without beam

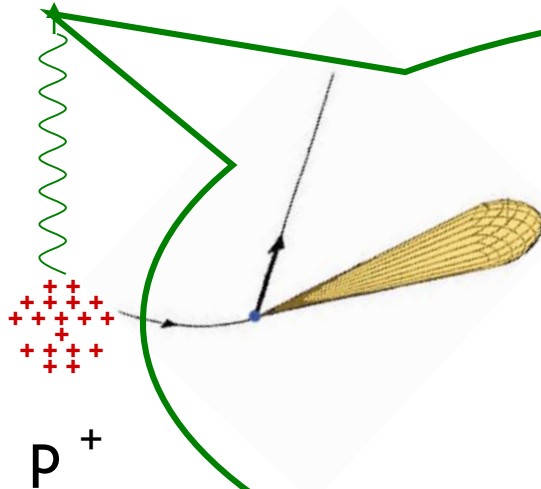
Synchrotron Radiation

calculation

Radial Distance

CB

BS



- A charged particle which is accelerated produce radiation
- The power of the centripetal radiation is larger than the longitudinal radiation (factor γ^2)
- For a relativistic particle, the radiation is highly peaked (opening angle $\sim 1/\gamma$)



Time = 0

Critical energy: divide the power spectrum in two equal parts

$$\varepsilon_c = \frac{3}{2} \frac{hc}{2\pi} \frac{\gamma^3}{\rho}$$

$$\text{Electrons : } \varepsilon_c [\text{eV}] = 2.218 \cdot 10^3 \frac{E[\text{GeV}]^3}{\rho[\text{m}]}$$

$$\text{Protons : } \varepsilon_c [\text{eV}] = 3.5835 \cdot 10^{-7} \frac{E[\text{GeV}]^3}{\rho[\text{m}]}$$

Synchrotron Radiation: $E_c = 44 \text{ eV} @ \text{LHC}$

Radial Distance

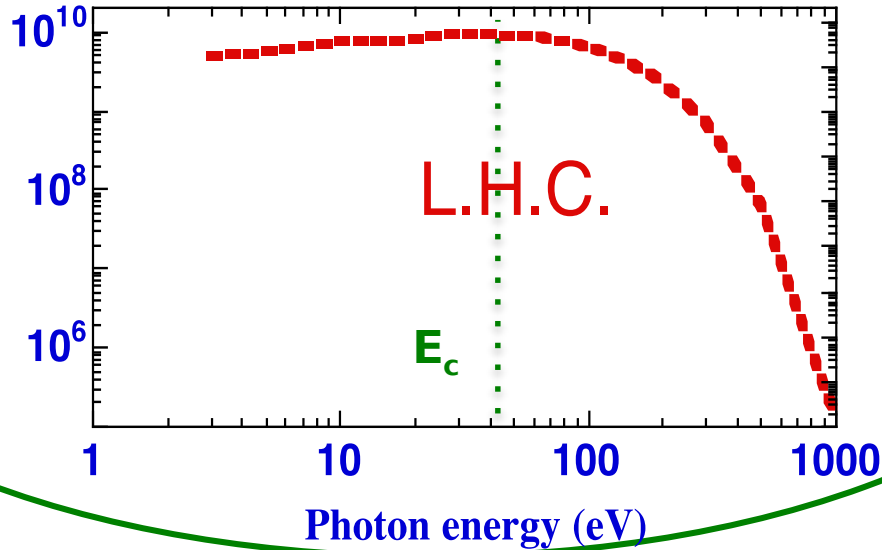
CB

BS

p^+

Photon Flux

$[\text{ph}/(\text{mm}^2 \text{ s } 0.1 \% \text{ BW})]$



Time = 0

- The average power emitted by the beam per unit length is:

For LHC: $P_{SR} = 0.17 \text{ W/m/apert.}$

$$P_0 \propto \frac{E^4}{\rho^2} I \propto B^2 E^2 I$$



Photo-desorption:

SR & Surface Science

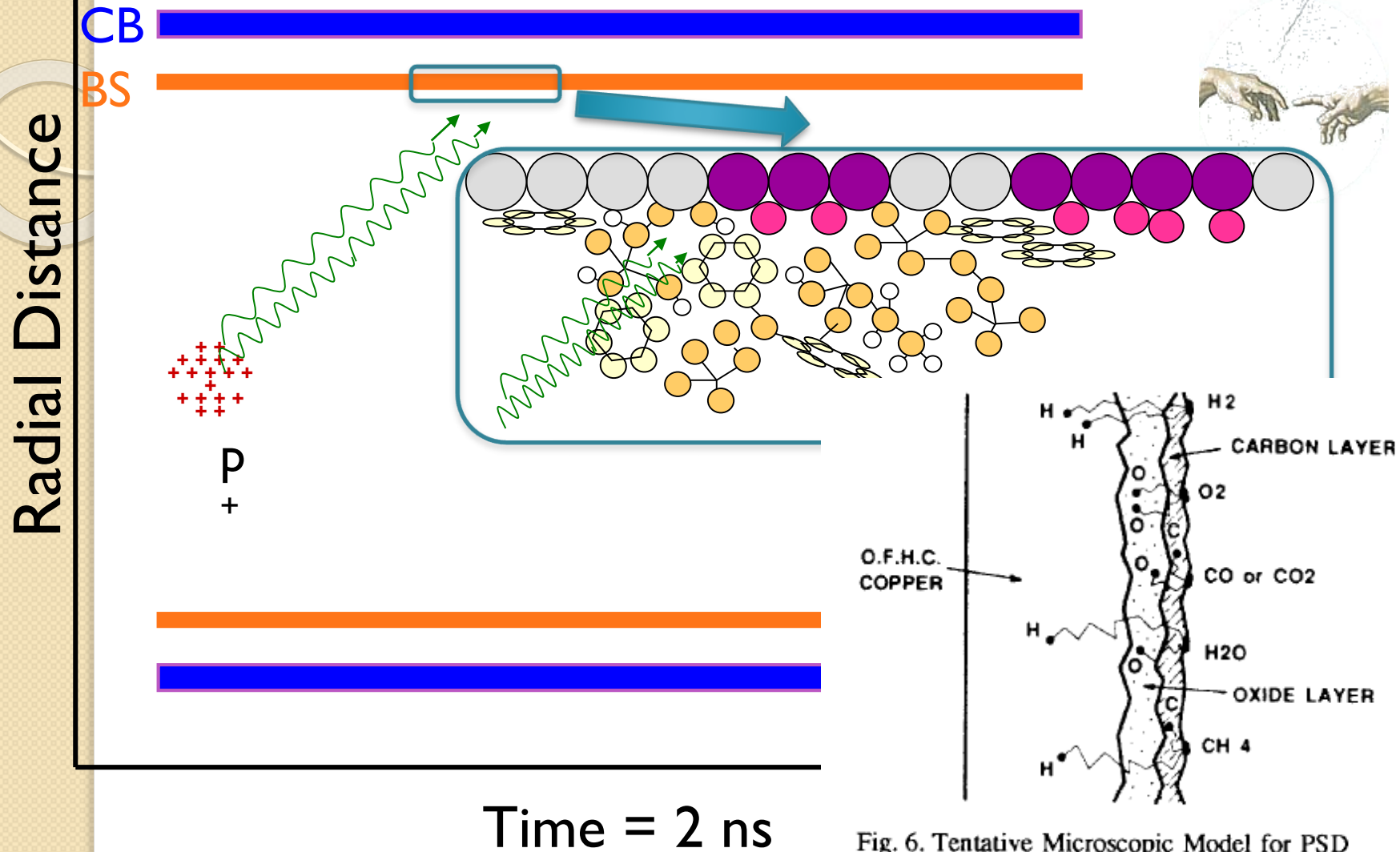


Fig. 6. Tentative Microscopic Model for PSD from OFHC Copper.

O. Gröbner et. al. EPAC 1992

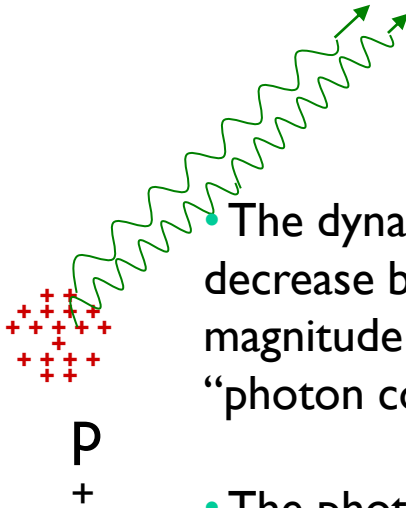
Photo-desorption:

SR & Surface Science

Radial Distance

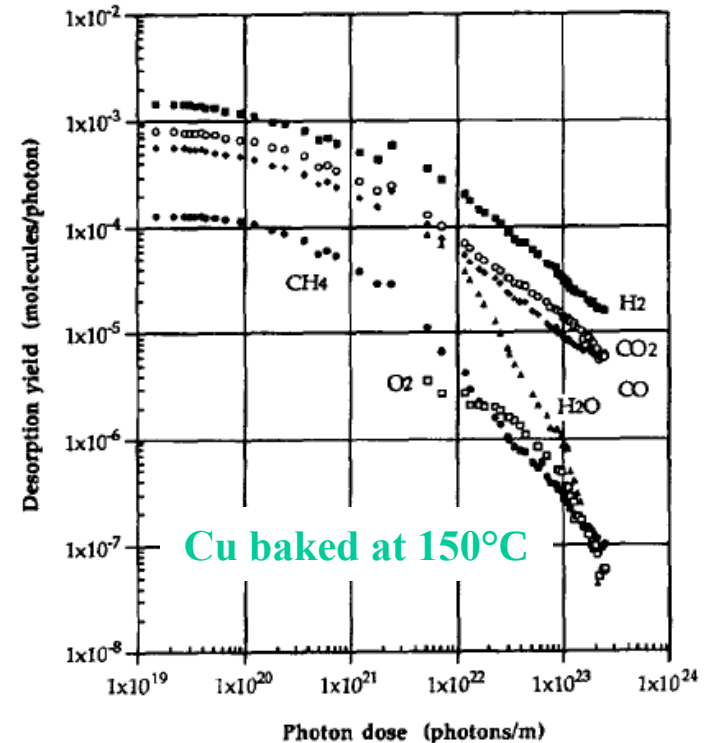
CB

BS



• The dynamic pressure decrease by several orders of magnitude with photon dose: “photon conditioning”

• The photon desorption yield is characterised by η_{photon}



O. Gröbner et al.
J.Vac.Sci. 12(3), May/Jun 1994, 846-853

Time = 2 ns

See: talk from **O. Malyshev**

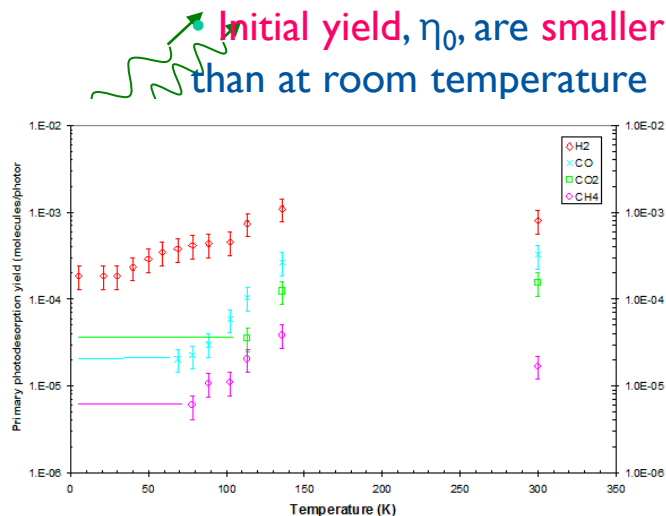
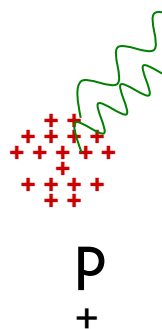
Photo-desorption at LT:

SR & Surface Science

Radial Distance

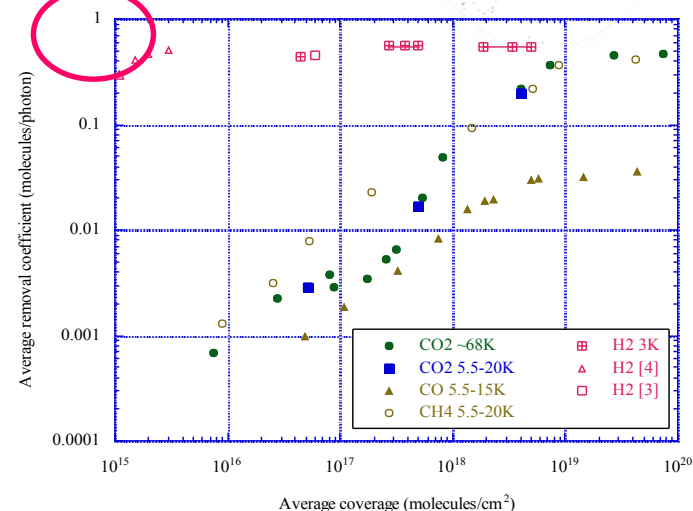
CB

BS



V. Baglin et al., Vacuum 67 (2002) 421-428

BUT at LT:
presence of physisorbed molecule



V. Anashin et al., Vacuum 53 (1-2), 269, (1999)

Time = 2 ns

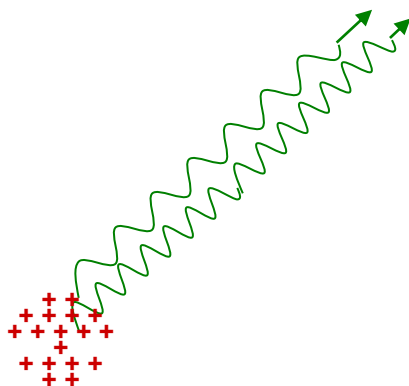
See: talk from **V. Baglin**

Photons induce Heat load:

Radial Distance

CB

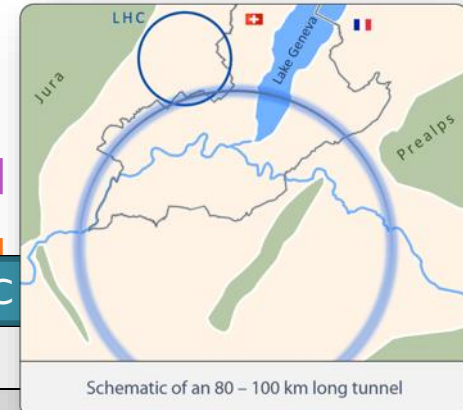
BS



P
+

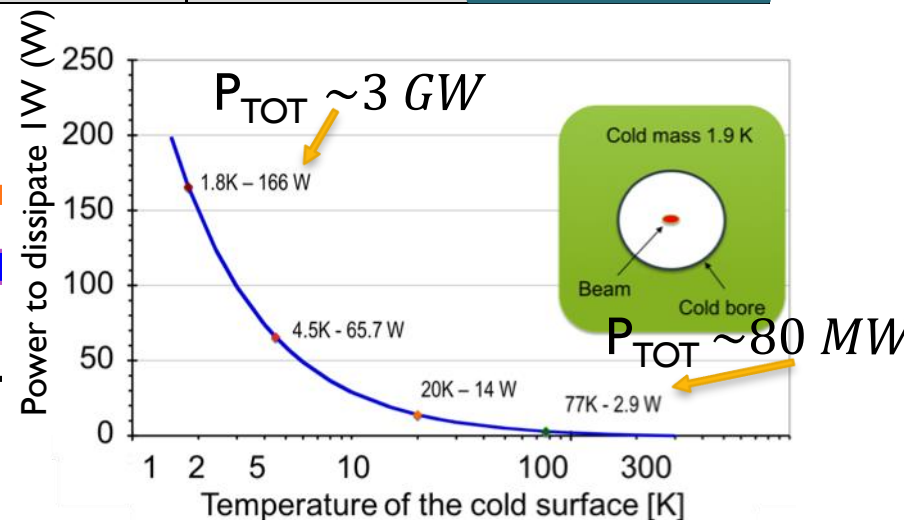
Parameters	LHC		H-L LHC	FCC-hh
c.m. Energy [TeV]	14			100 (33)
Circumference C [km]	26.7			100 (33)
Dipole field [T]	8.33			16 (20)
Injection energy [TeV]	0.45			3.3 (5.0)
Peak luminosity [$10^{34} \text{ cm}^{-2} \text{ s}^{-1}$]	1.0	5.0		5.0
Stored beam energy [GJ]	0.392	0.694		8.4 (7.0)
SR power per ring [MW]	0.0036	0.0073		2.4 (2.9)
Arc SR heat load [W/m/aperture]	0.17	0.33		28.4 (44.3)
Critical photon energy [keV]	0.044			4.3 (5.5)

Version 1.0 (2014-02-11)



In FCC-hh

Time = 2 ns



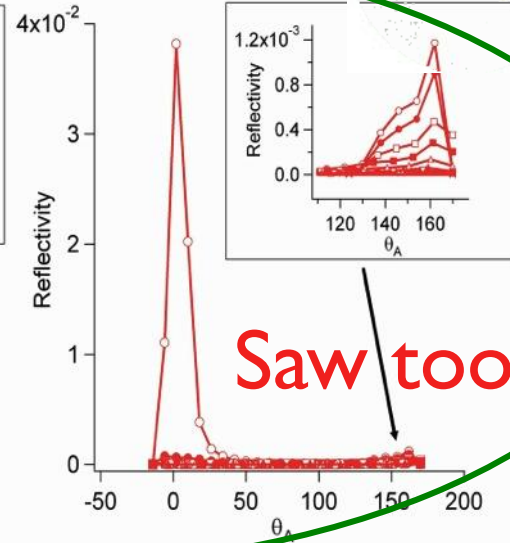
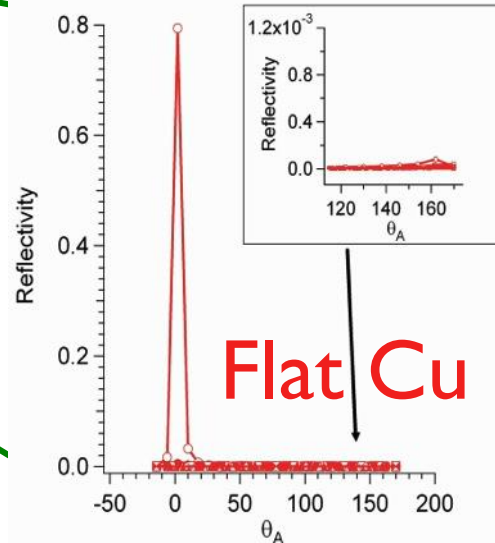
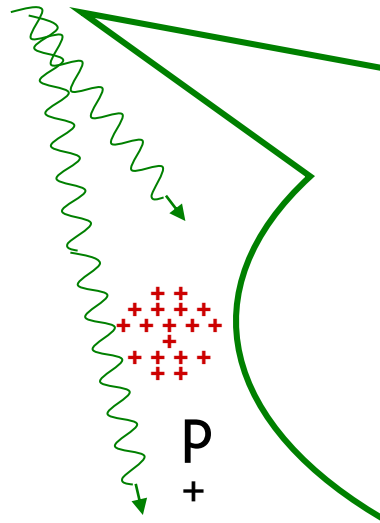
Credits: R. Kersevan -- Beam Dynamics meets Vacuum, Collimations, and Surfaces 2017

Photon reflectivity:

Radial Distance

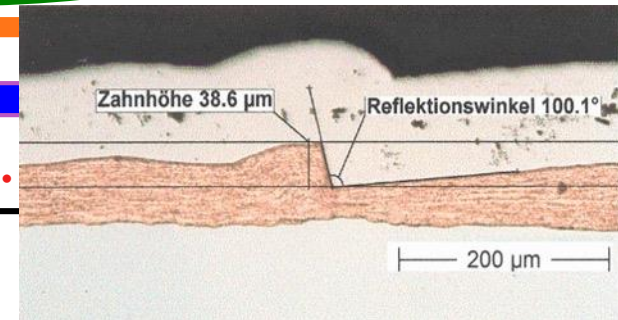
CB

BS



N. Mahne et al. App. Surf. Sci. 235, 221-226, (2004).

Time = 2 ns



PS: reflected photons do NOT induce HL.

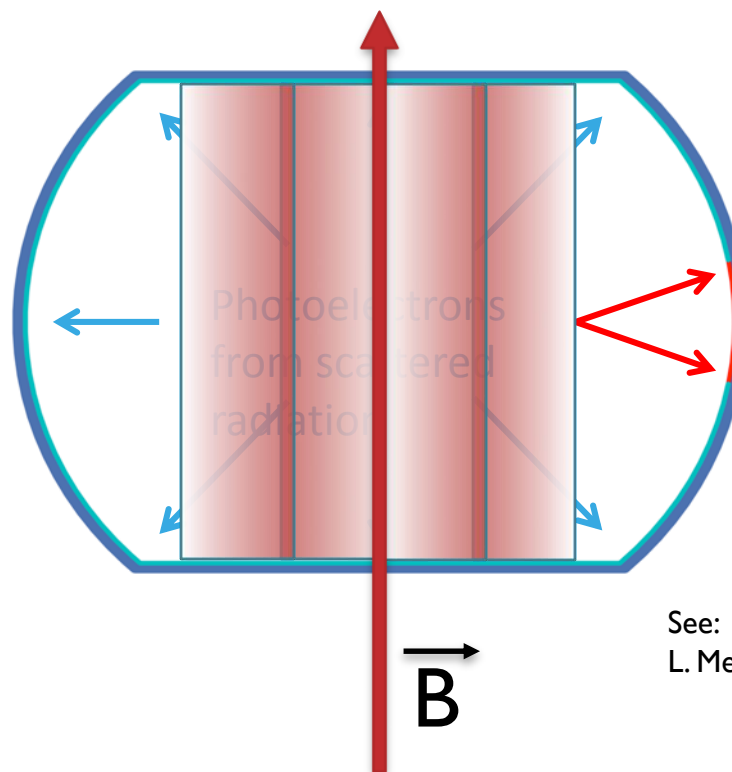
See: R. Cimino V. Baglin and F. Schäfers PRL 2015

Photon reflectivity: where photons go?

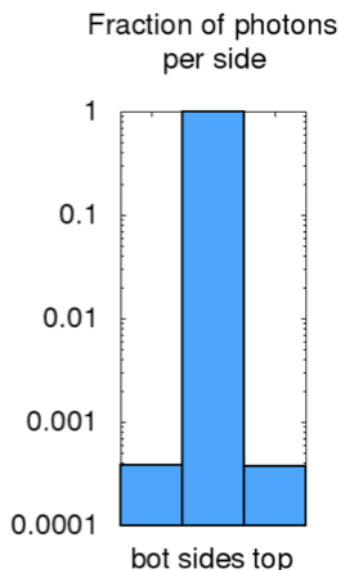
In the dipoles we are in presence of a strong Magnetic field



Photoelectrons contributing to e-cloud build-up mainly from scattered photons



Photoelectrons from direct impacts

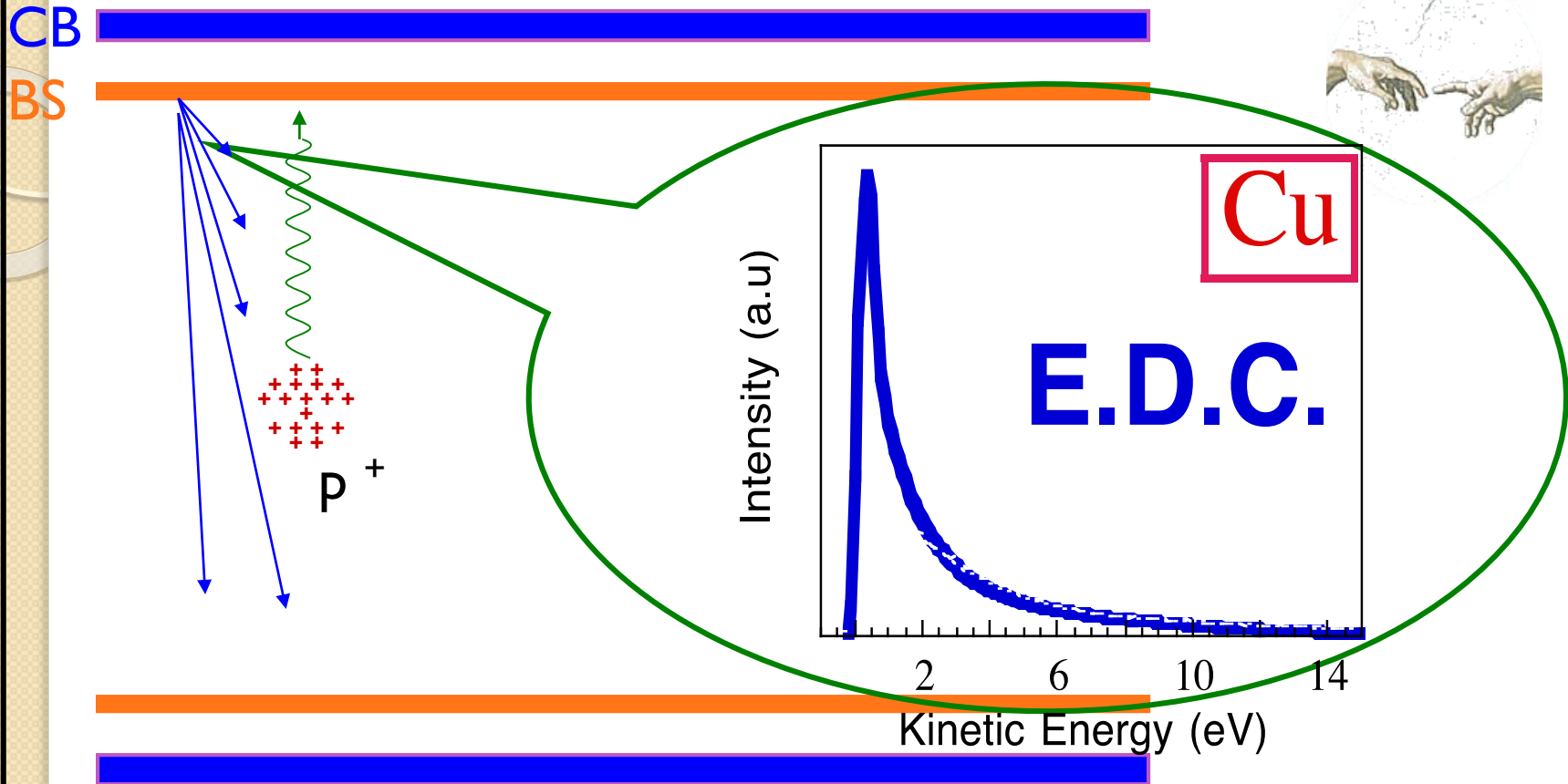


See:
L. Mether, et al. In FCC-Berlin 2017

Mainly electrons produced by photons absorbed on the top and bottom of beam screen can seed e-cloud build-up in dipoles and BS is optimized to reduce them.

PS: Reflected photons do NOT produce photoelectrons.
See: R. Cimino V. Baglin and F. Schäfers PRL 2015

Radial Distance



R. Cimino, V. Baglin, I. R. Collins. *Phys.Rev. ST-AB* 2 63201 (1999).

Time = 5 ns

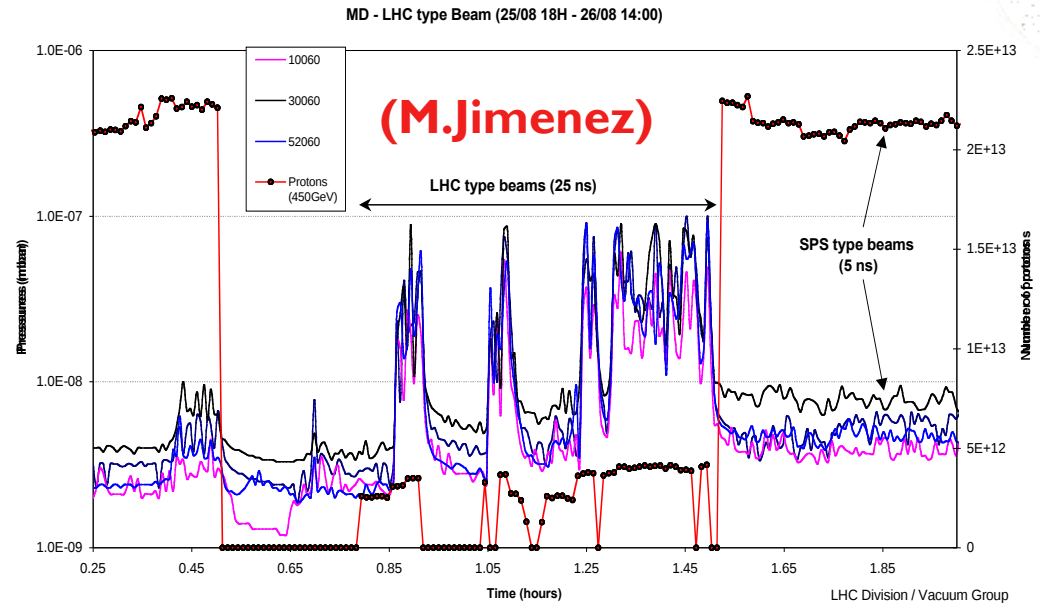
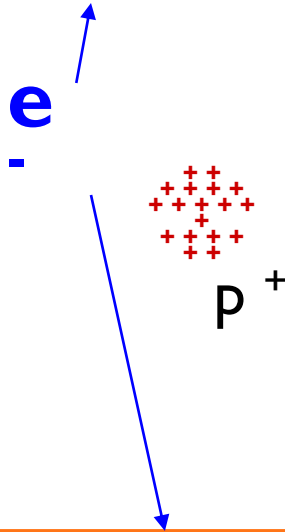
Produced e^- (PY): very important for single beam instabilities (K.Ohmi and F.Zimmermann PRL 2000)

Even in absence of SR:
 e^- from ionization of residual gas... etc



Radial Distance

SPS



LHC Division / Vacuum Group
 J.M. Jimenez
 SPS MD 26/08/99

Time = 5 ns

Beam induced multipacting is observed in SPS where
 no e^- are photoemitted.

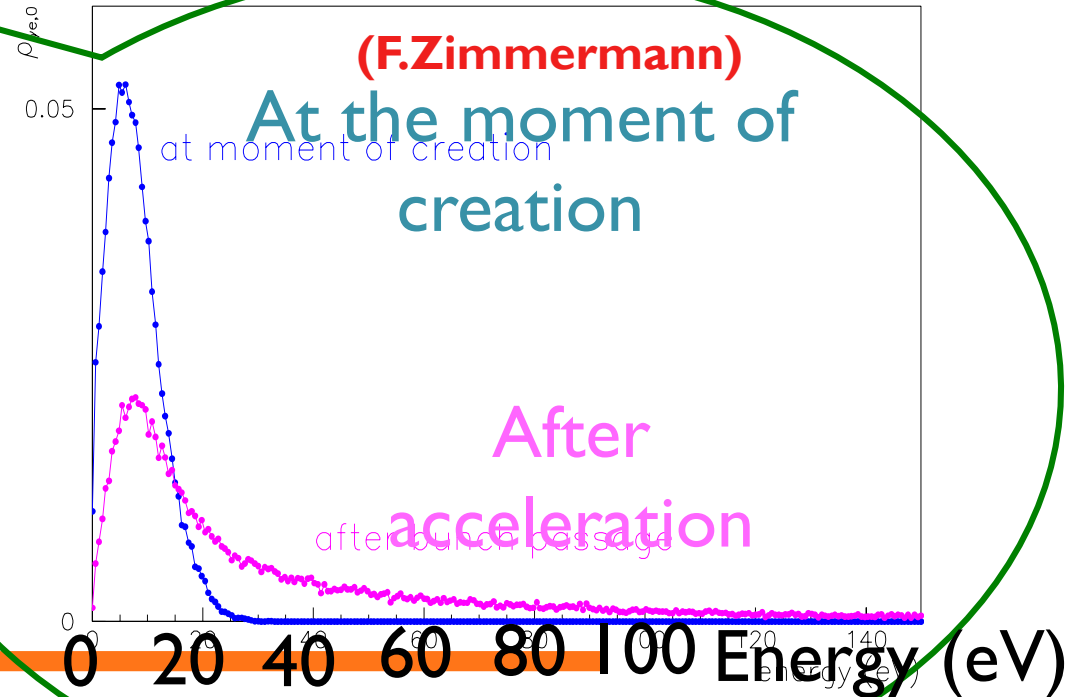
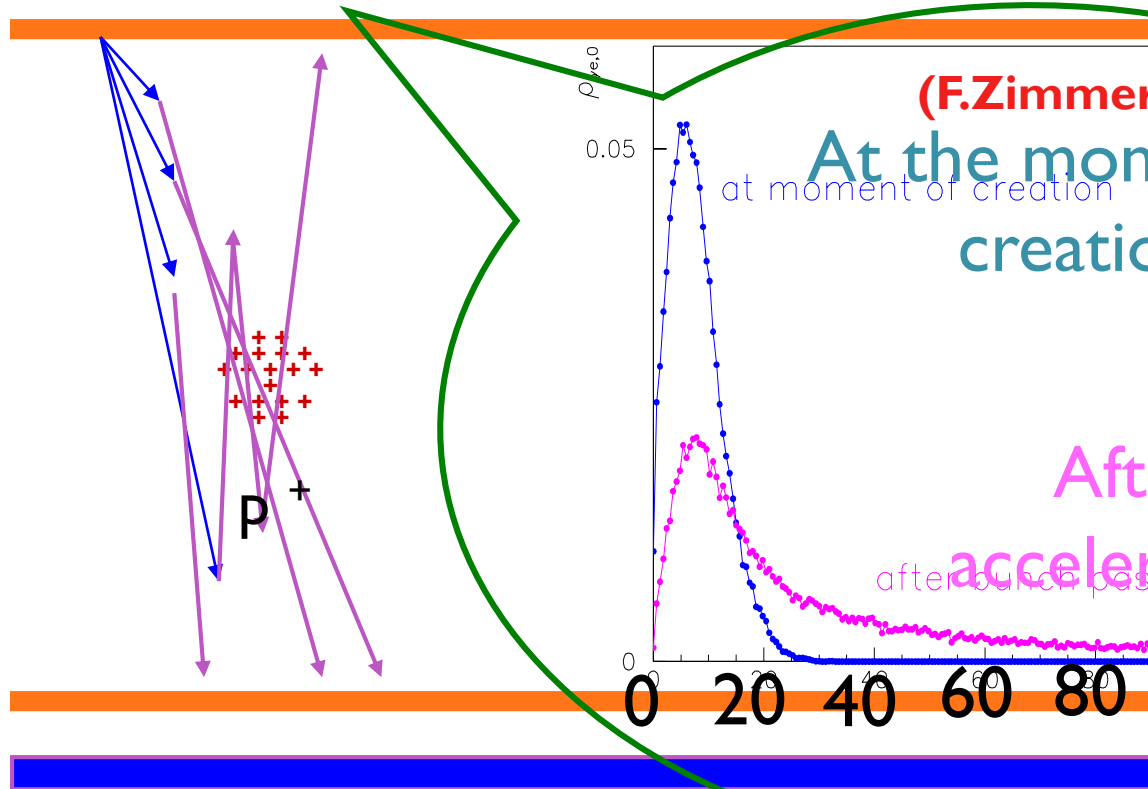
Beam induced el. acceleration

simulation

Radial Distance

CB

BS



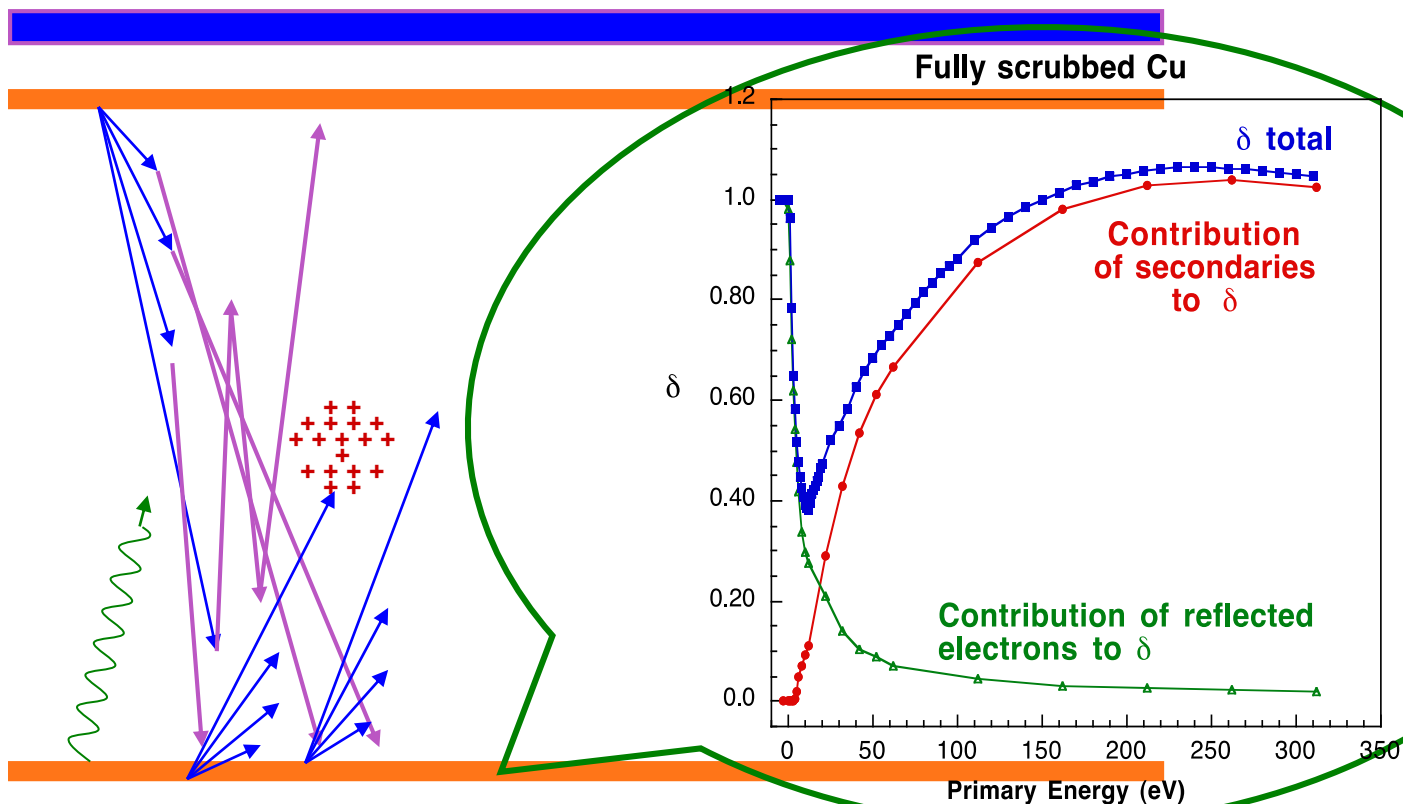
Time = 10 ns

e^- induced e^- emission

Radial Distance

CB

BS



R. Cimino et al *Phys. Rev. Lett.* 93, 14801 (2004).

Time = 15 ns

e^- induced e^- emission vs. E

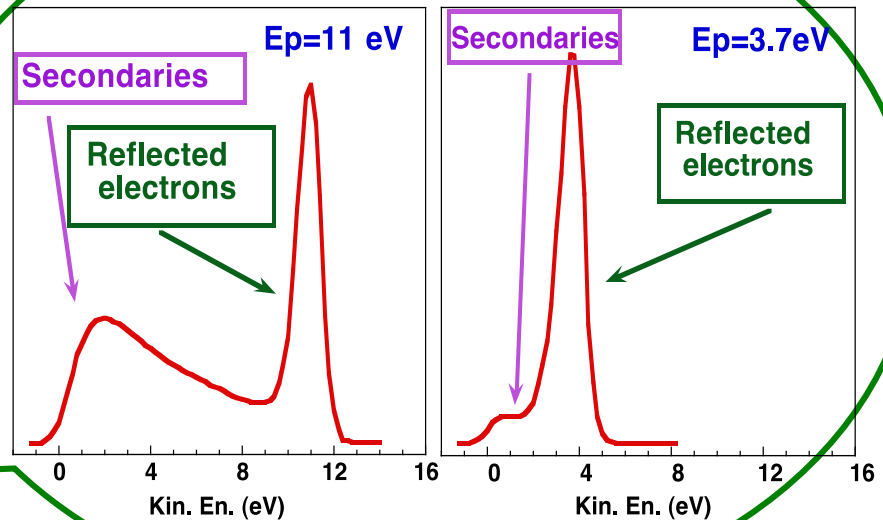
Surface Science

Radial Distance

CB

BS

Energy Distribution Curves as function of E_p



R. Cimino et al *Phys. Rev. Lett.* 93, 14801 (2004).

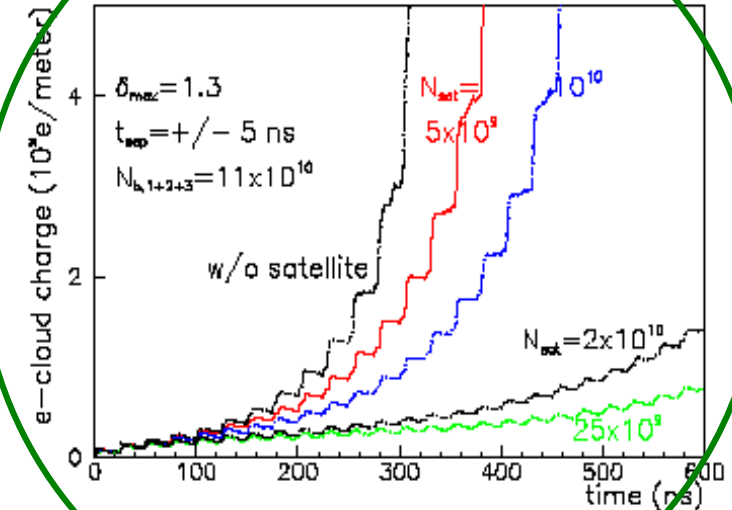
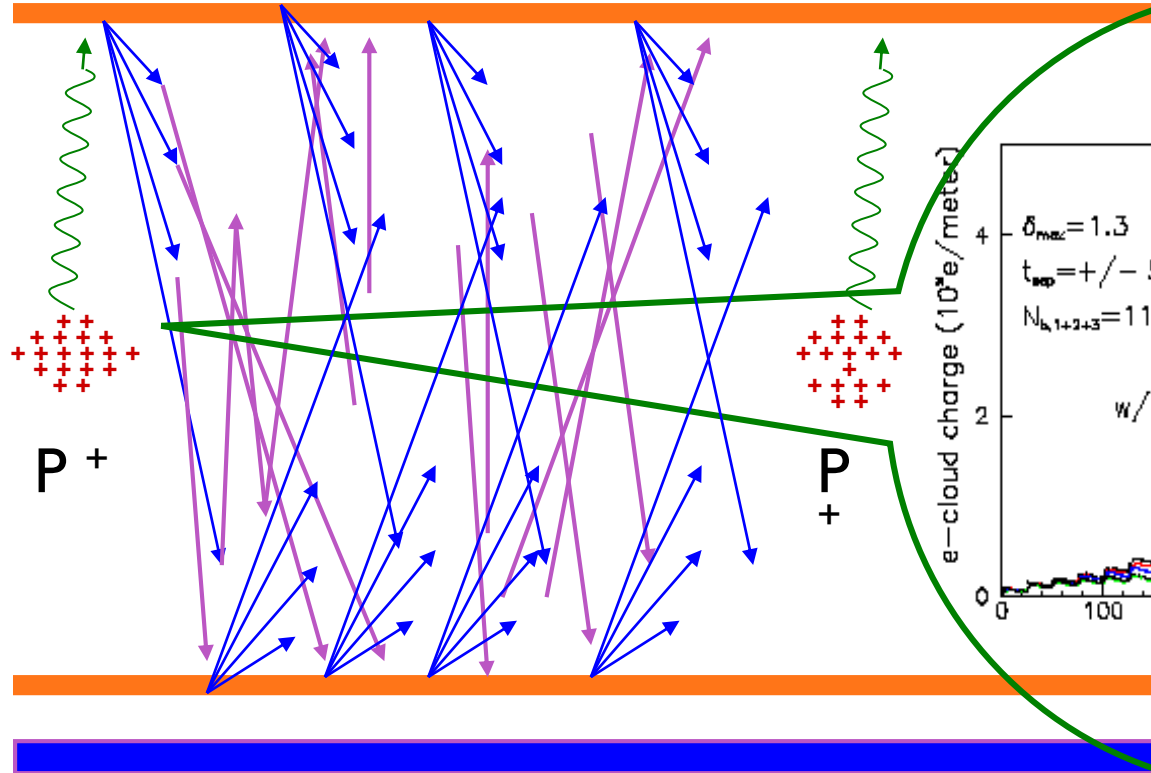
Time = 20 ns

e⁻ cloud Build-up

E- cloud simulation

Radial Distance

CB
BS



(F. Zimmermann)

Time structure vs.
Simulations.

Time = 25 ns

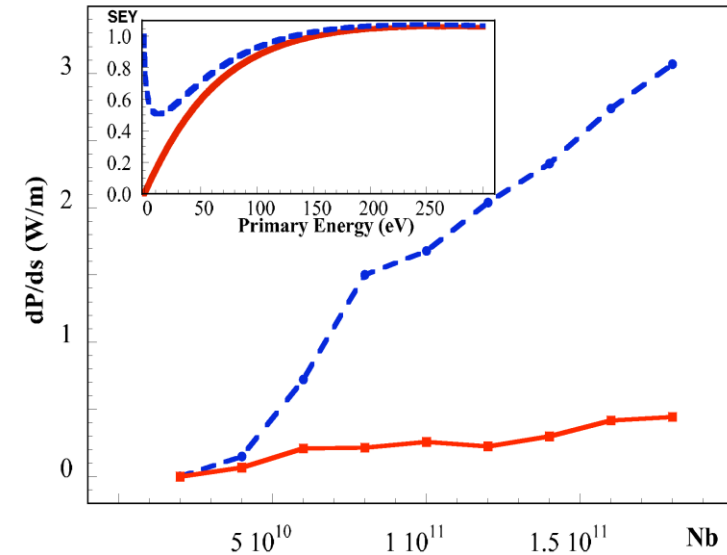
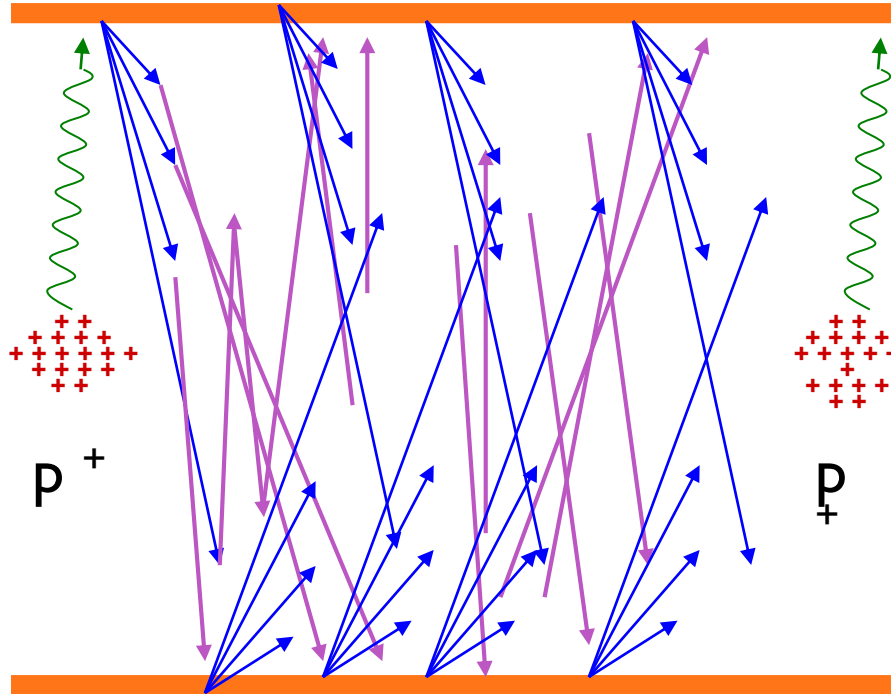
e^- induced heat load

Simulation

Radial Distance

CB

BS



R. Cimino et al *Phys. Rev. Lett.* 93, 14801 (2004).

Time = 25 ns

e^- cloud build up causes Heat load!

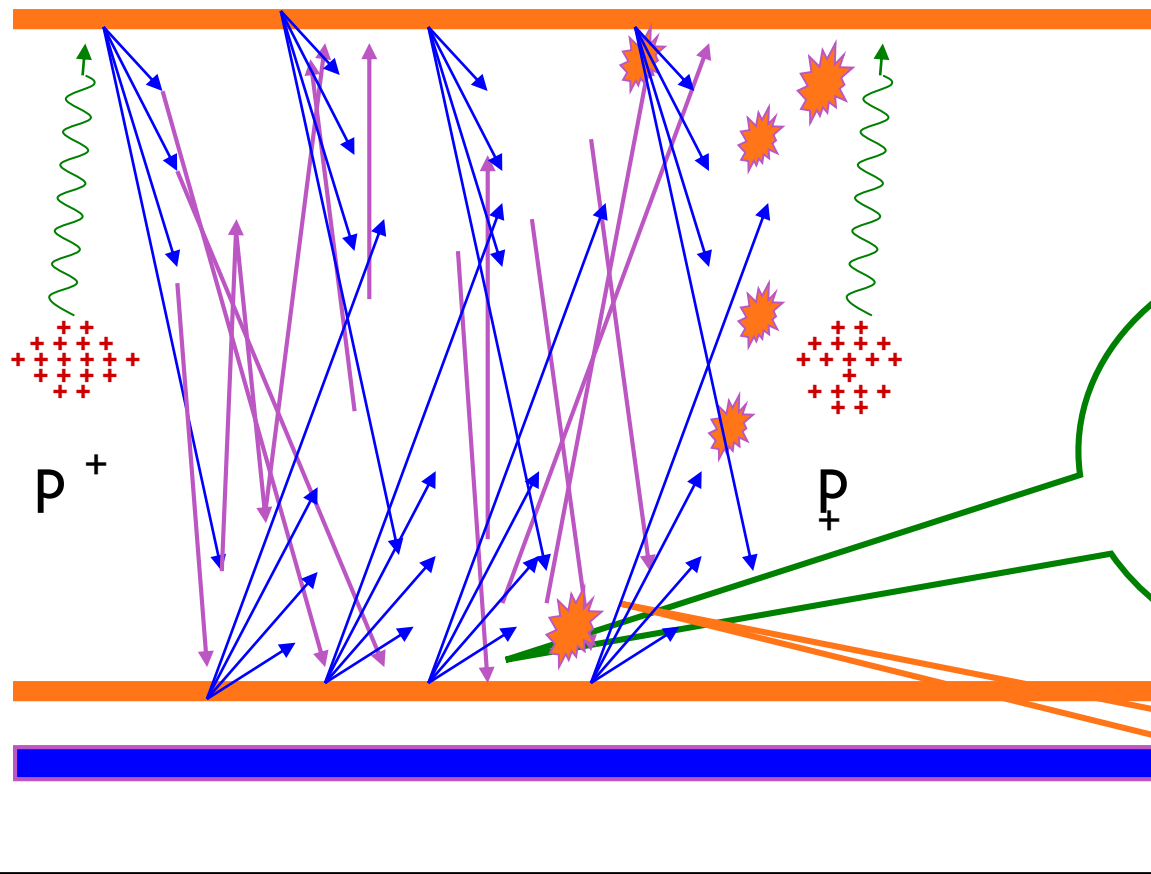
e^- induced gas desorption

Surface Science
and simulation

Radial Distance

CB

BS



See: talk from **O. Malyshev**

Time = 25 ns

It is a beam/Vacuum issue!

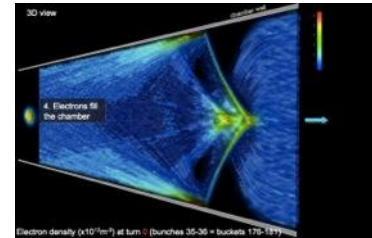
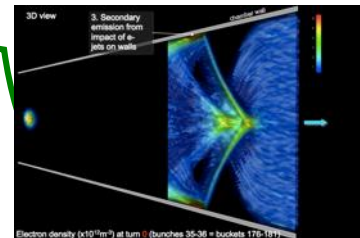
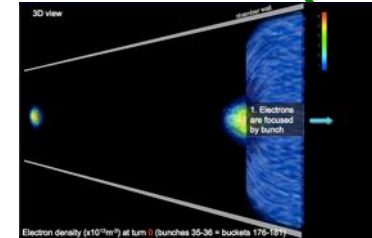
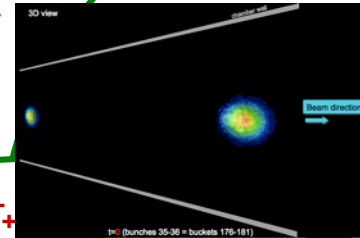
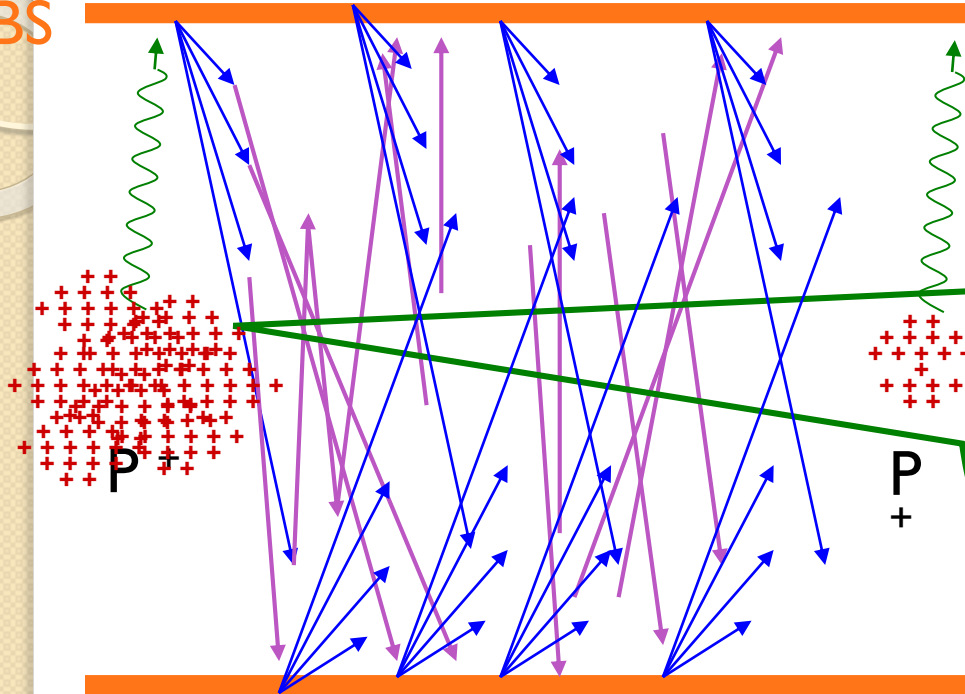
Beam blow up

E- cloud simulation

Radial Distance

CB

BS



Time structure vs Simulations.

It affects beam quality!

Jean-Luc Vay
IPAC'2012

Time = 25 ns

Electron cloud in accelerators

- Phenomenology:

What happens to the Vacuum beam pipe in presence of the beam? (LHC Example)

- Numerical model

- The Surface Science properties of relevance:

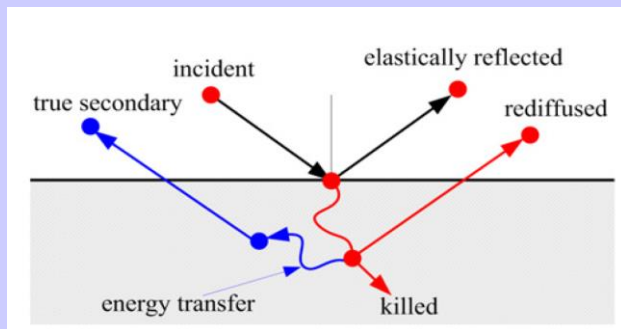
- ✓ SEY (Secondary Electron Yield);
- ✓ PY (Photo Yield);
- ✓ R (photon Reflectivity)

- Mitigation strategies

- Conclusion

R. Cimino and T. Demma
“Electron cloud in Accelerators”
Int. J. Mod. Phys. A 29 (2014)
1430023 (pag. 65).

Secondary Electron Yield (SEY)



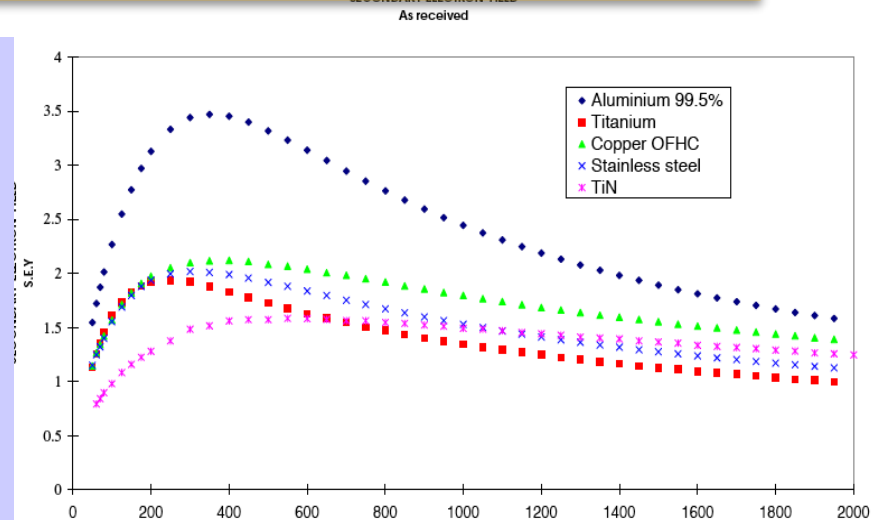
secondary electron emission

three-step process:

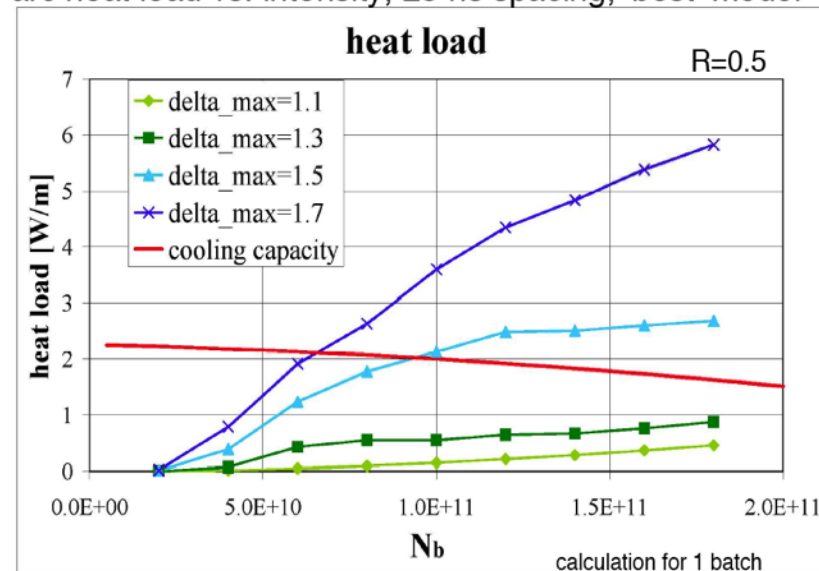
- production of SEs at a depth z
- transport of the SE toward the surface
- emission of SE across the surface barrier

It depend on the surface type and condition: has a big impact to simulations (see calculation for LHC).

See: R. Cimino and T. Demma, "Electron cloud in Accelerators" Int. Jou. of Modern Physics A Vol. 29, 1430023 (2014).



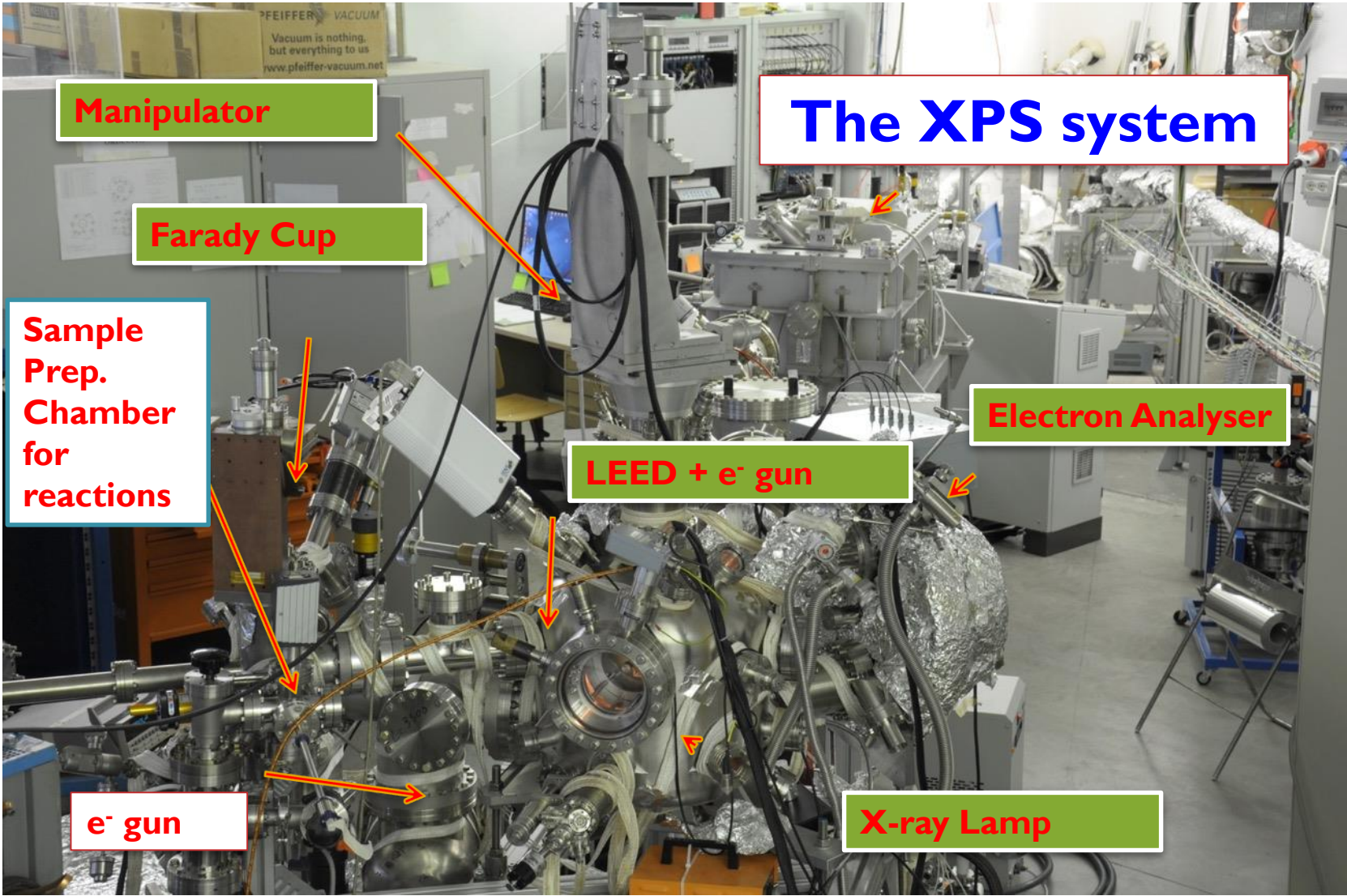
arc heat load vs. intensity, 25 ns spacing, 'best' model



heat load for quadrupoles higher in 2nd batch; still to be clarified

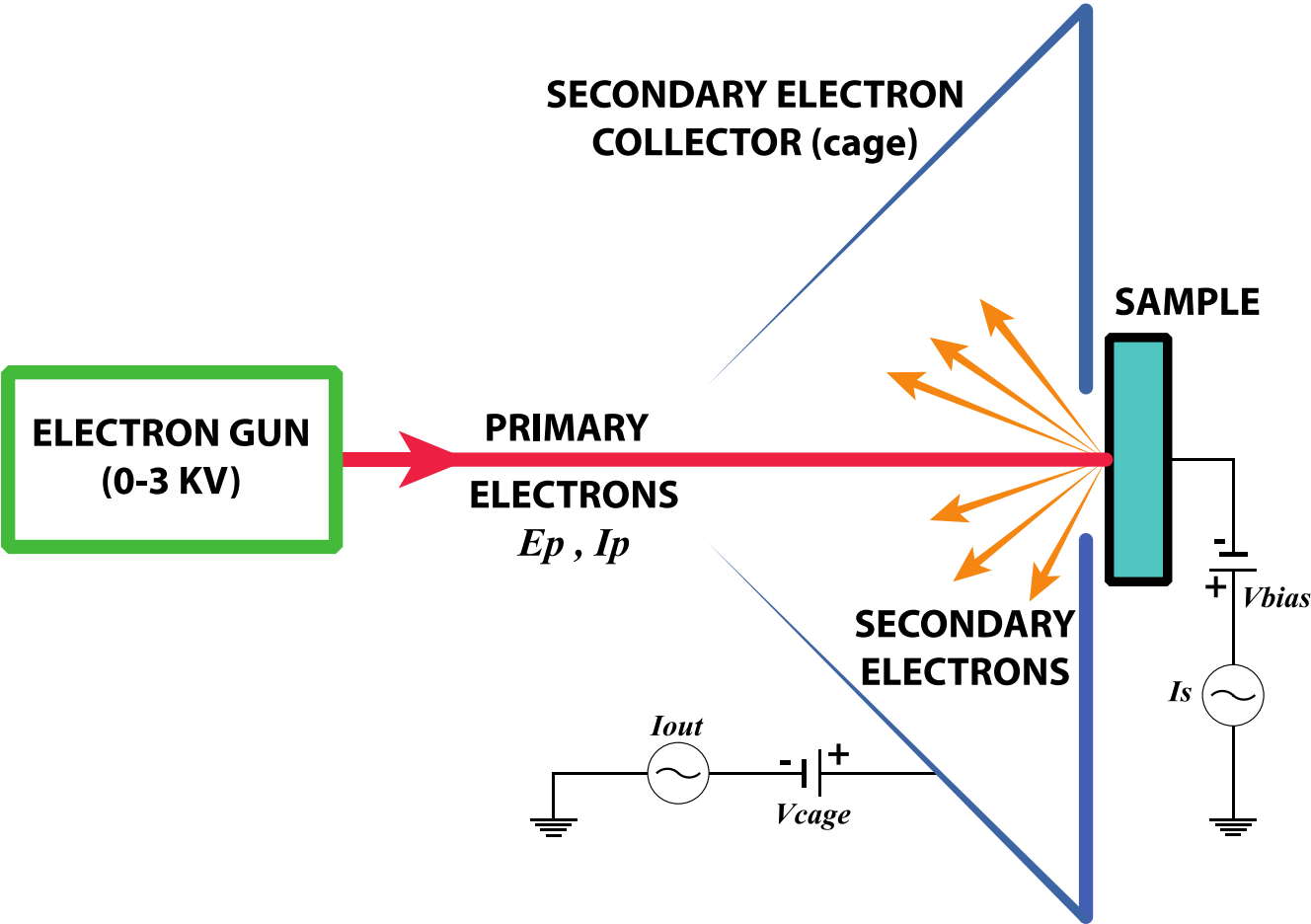
Frank Zimmermann, LTC 06.04.05

Need of “state of the art” Surface Science systems to study SEY



Measure of Secondary e⁻ Yield: 2 methods

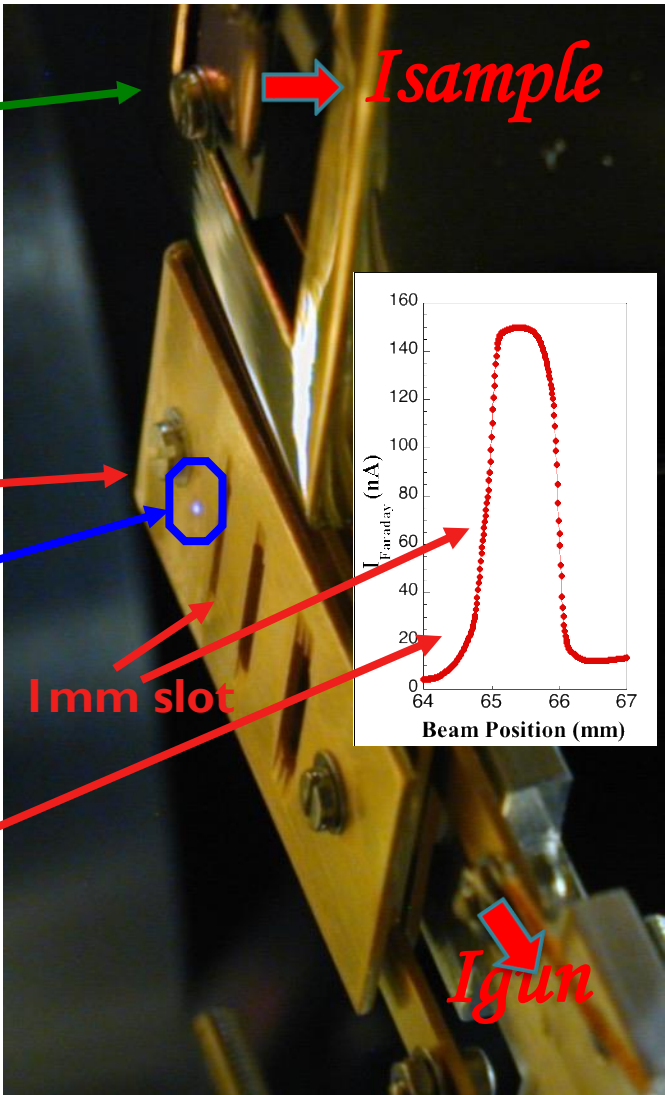
$$SEY = \delta = \frac{I_{out}}{I_{in}} = \frac{I_{gun} - I_{sample}}{I_{gun}}$$



2nd method: Measure of Secondary e⁻ Yield

- In a μ -metal chamber
 - sample manipulator (also at Low T)
 - Sample well insulated (to measure small current I_s)
 - A **Faraday cup**.
 - A Low energy electron gun
- e⁻ beam Stable between 30 - 500 eV
 - Currents from few nA to μ A ($20\mu\text{C/h/mm}^2$ - 20mC/h/mm^2)
 - Intense spot ($\phi < 0.5$ mm) with low background

$$SEY = \delta = \frac{I_{out}}{I_{in}} = \frac{I_{gun} - I_{sample}}{I_{gun}}$$



Measure of Secondary e⁻ Yield: 2 methods

$$SEY = \delta = \frac{I_{out}}{I_{in}} = \frac{I_{gun} - I_{sample}}{I_{gun}}$$

I_{out} and I_{in} (N. Hilleret)

Advantages:

- Simultaneously measure δ at each energy: very fast.
- Effective also for “dispersive samples” (i.e. Sponges)

Disadvantages

- Gun far from the sample (difficult to control LE e⁻)
- Big(er) spot and no LE-SEY
- Loose Normal emitted e⁻

I_{sample} and I_{in}

Advantages:

- Gun close to sample.
- Reduce noise for low current measurements (i.e. insulators)
- LE-SEY accessible!?!

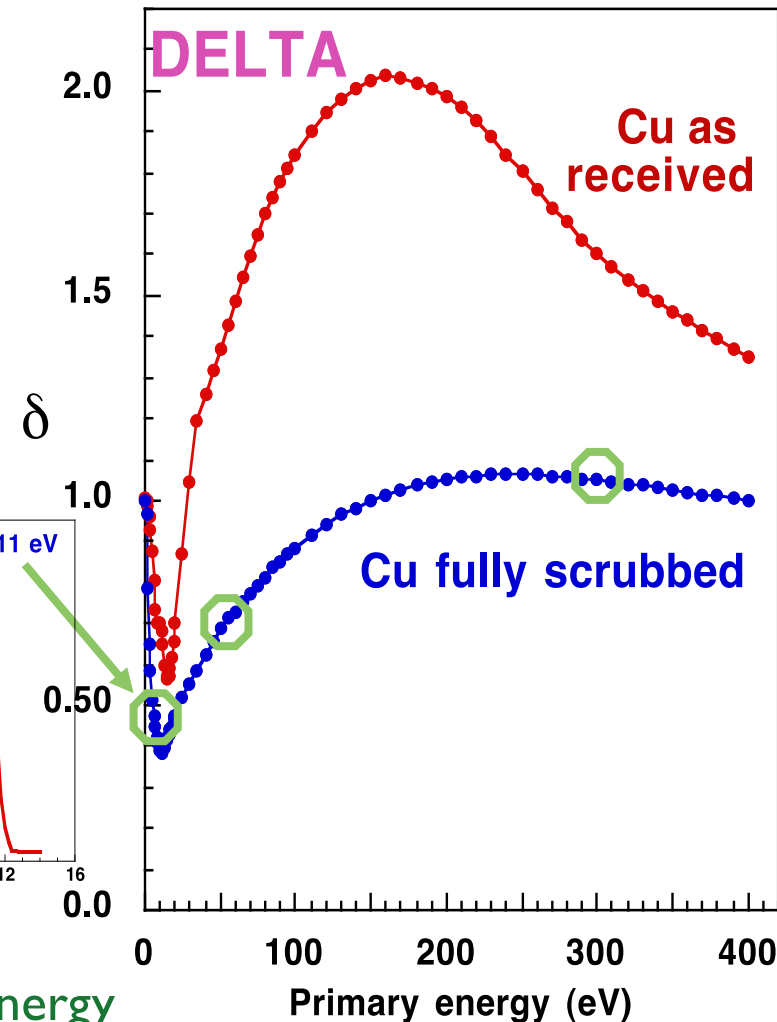
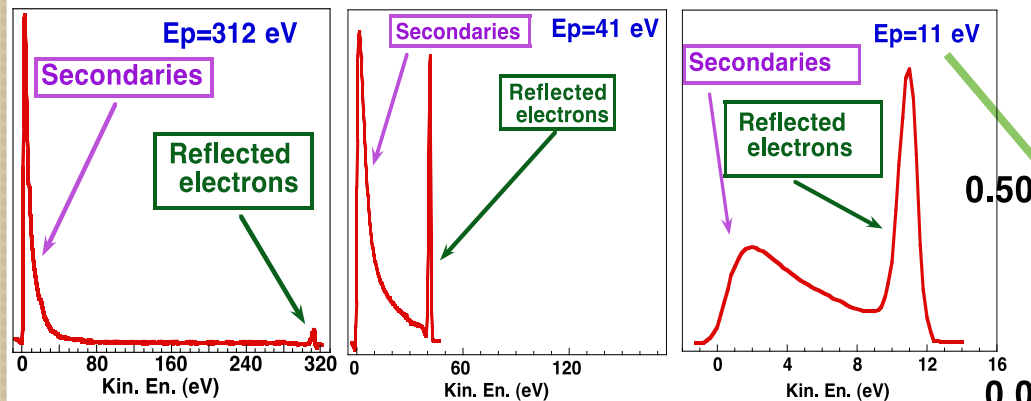
Disadvantages

- Gun need to be very stable (takes time)
- More work (2 separate runs)

Measure of Secondary e⁻ Yield

$$SEY = \delta = \frac{I_{gun} - I_{sample}}{I_{gun}}$$

At each Primary energy we measure I_{gun} (with the Faraday cup) and I_{sample} .



- Each point in δ is the integral of the energy distribution of the emitted electrons

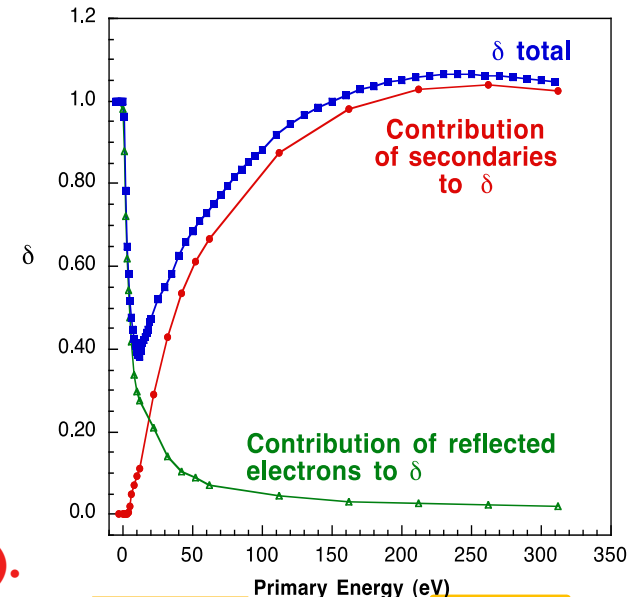
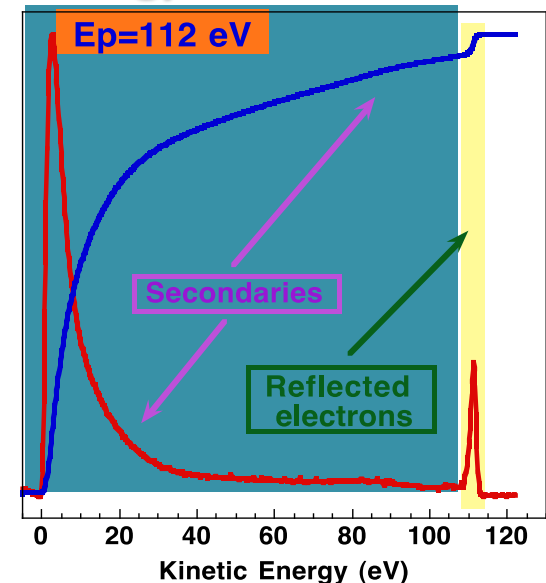
R. Cimino et al. *Phys. Rev. Lett.* **93**, 14801 (2004).

SEY of LHC Cu @ Low energy

Integrating the curves gives the Percentage of Secondaries and Reflected electrons

To separate “true secondaries from “re-diffused electrons is arbitrary and has not been considered in this analysis.

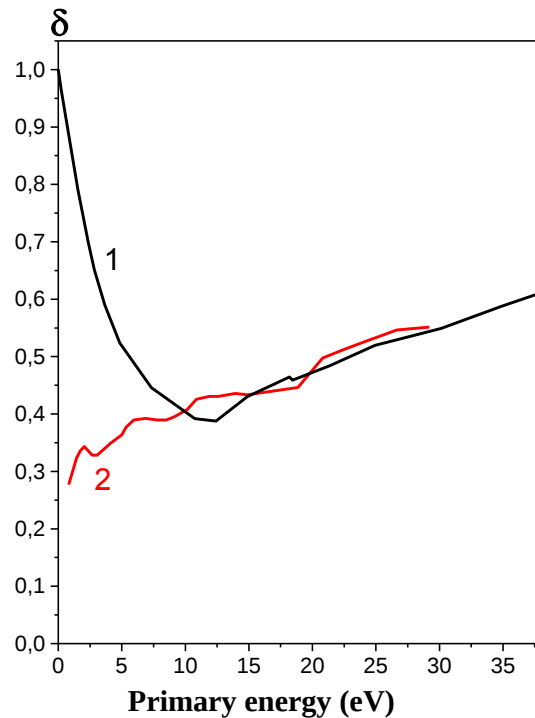
We observe that the contribution to of the **reflected electrons** at very low primary energy is, in this material, very high.



R. Cimino et al. *Phys. Rev. Lett.* **93**, 14801 (2004).

Addendum Such Low energy part of SEY was, up to recently, somehow controversial.

Total secondary electron yield of Cu as a function of incident electron energy. 1. from the letter for fully scrubbed Cu ($T=10$ K). 2. Experimental data for bulk Cu after heating in vacuum (room temperature).



From: A. N. Andronov, A. S. Smirnov, I. D. Kaganovich, E. A. Startsev, Y. Raitses, and V. I. Demidov, (in Proceedings of ECLOUD'12 (2013), CERN-2013-002, p. 161)

1. R. Cimino, et al, Phys. Rev. Lett. **93**, 014801 (2004).
2. I. M Bronshtein, B. S Fraiman. Secondary Electron Emission. Moscow, Russia: Atomizdat, p. 408 (1969).

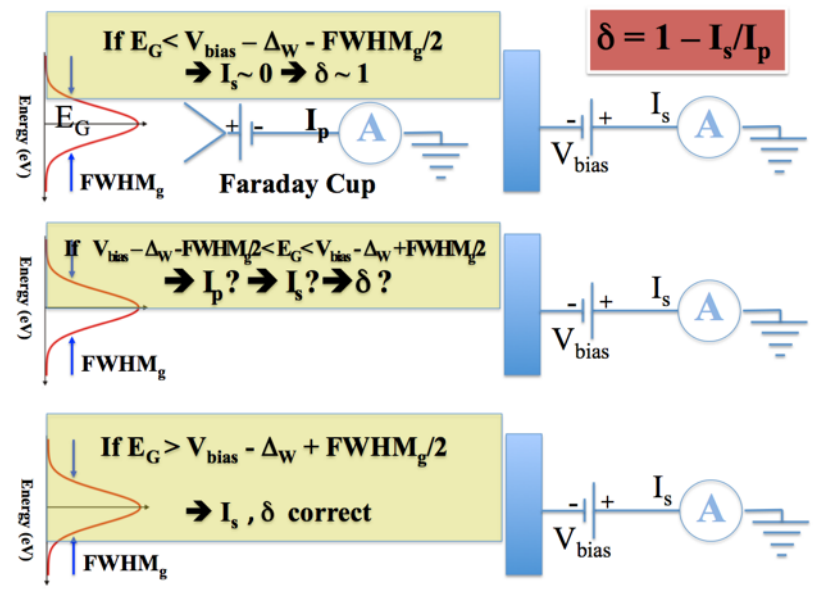
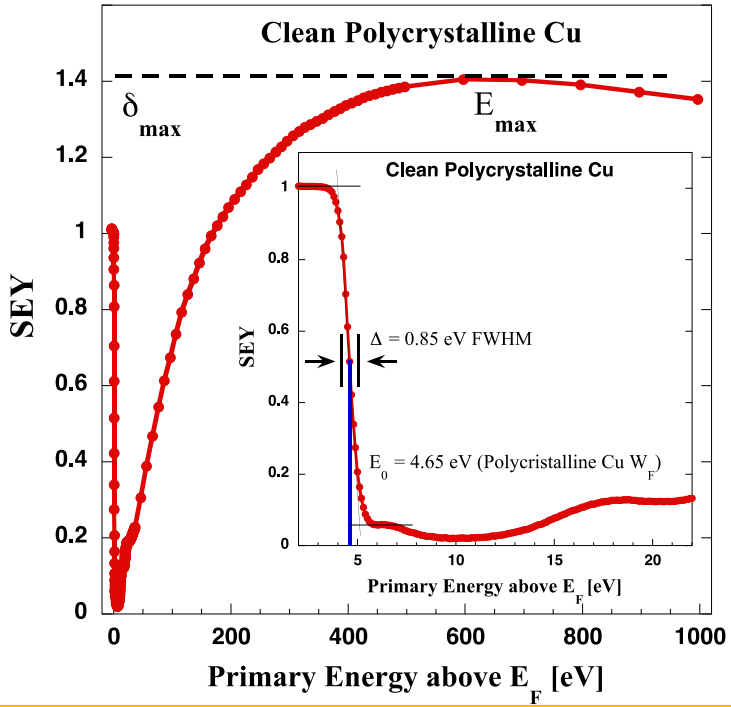
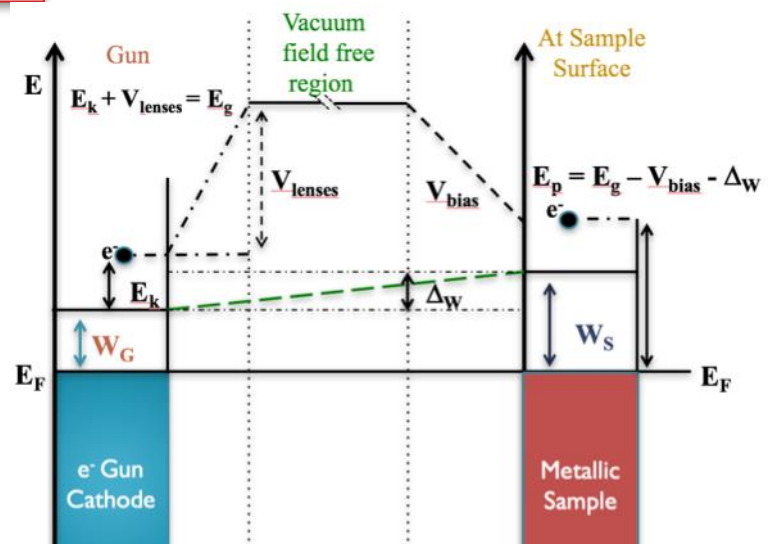
Other measurements reported the reflection coefficient of about 7% for incident electron energy below few electron volts for most pure metals.

I.H. Khan, J. P. Hobson, and R.A. Armstrong, Phys. Rev. **129**, 1513 (1963).

H. Heil, Phys. Rev. **164**, 887, (1967).

Z. Yakubova and N.A. Gorbatiy, Russian Physics Journal, **13** 1477 (1970).

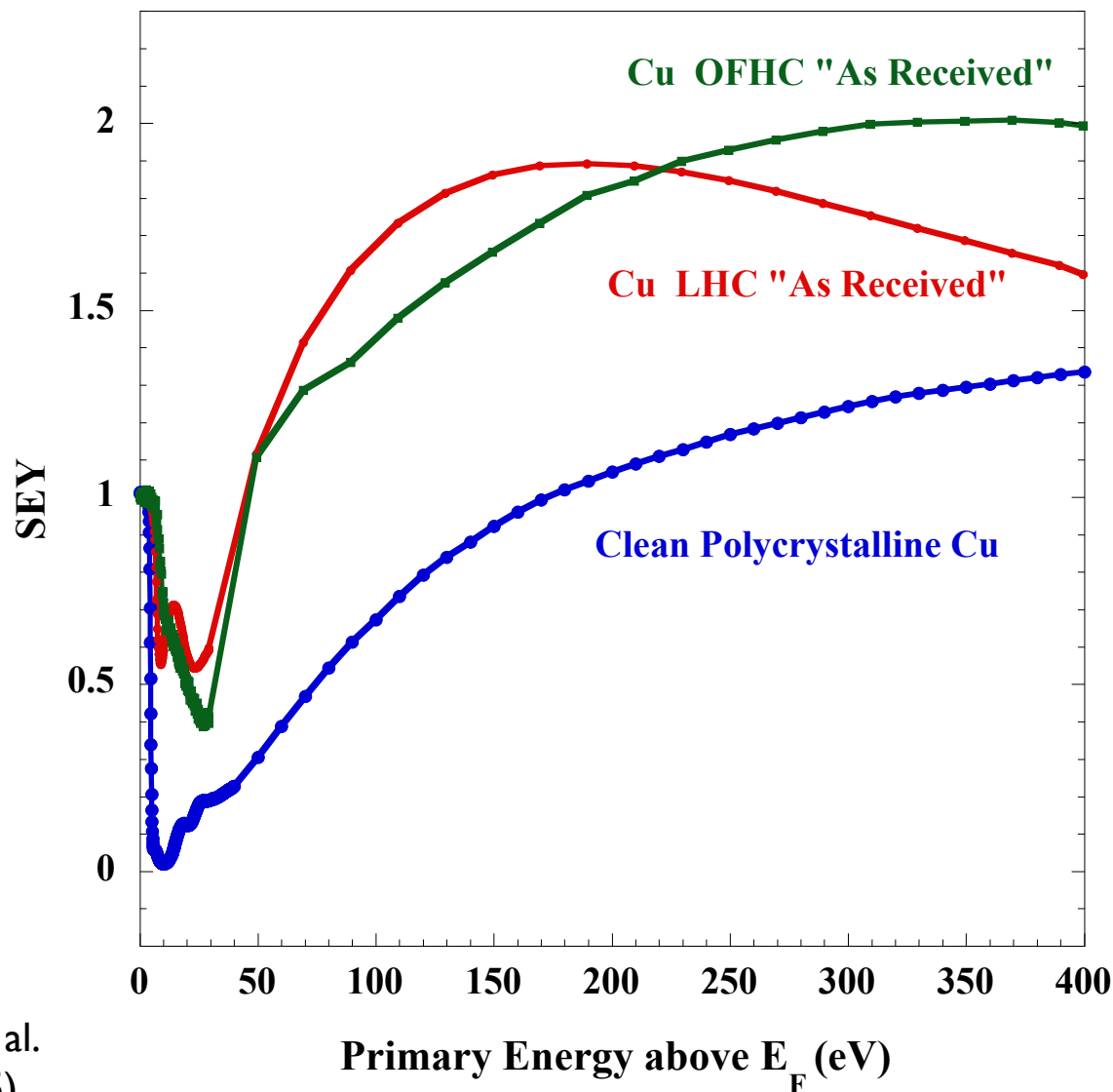
See: R. Cimino et al. PR ST **18**, 051002 (2015)



- Study in identical conditions (same geometry etc.) atomically clean (XPS) Cu obtained by cycles of Ar⁺ sputtering of the “as received” Cu.
- Compare it to “as received” Cu samples.
- “As received” is NOT a well defined chemical state!

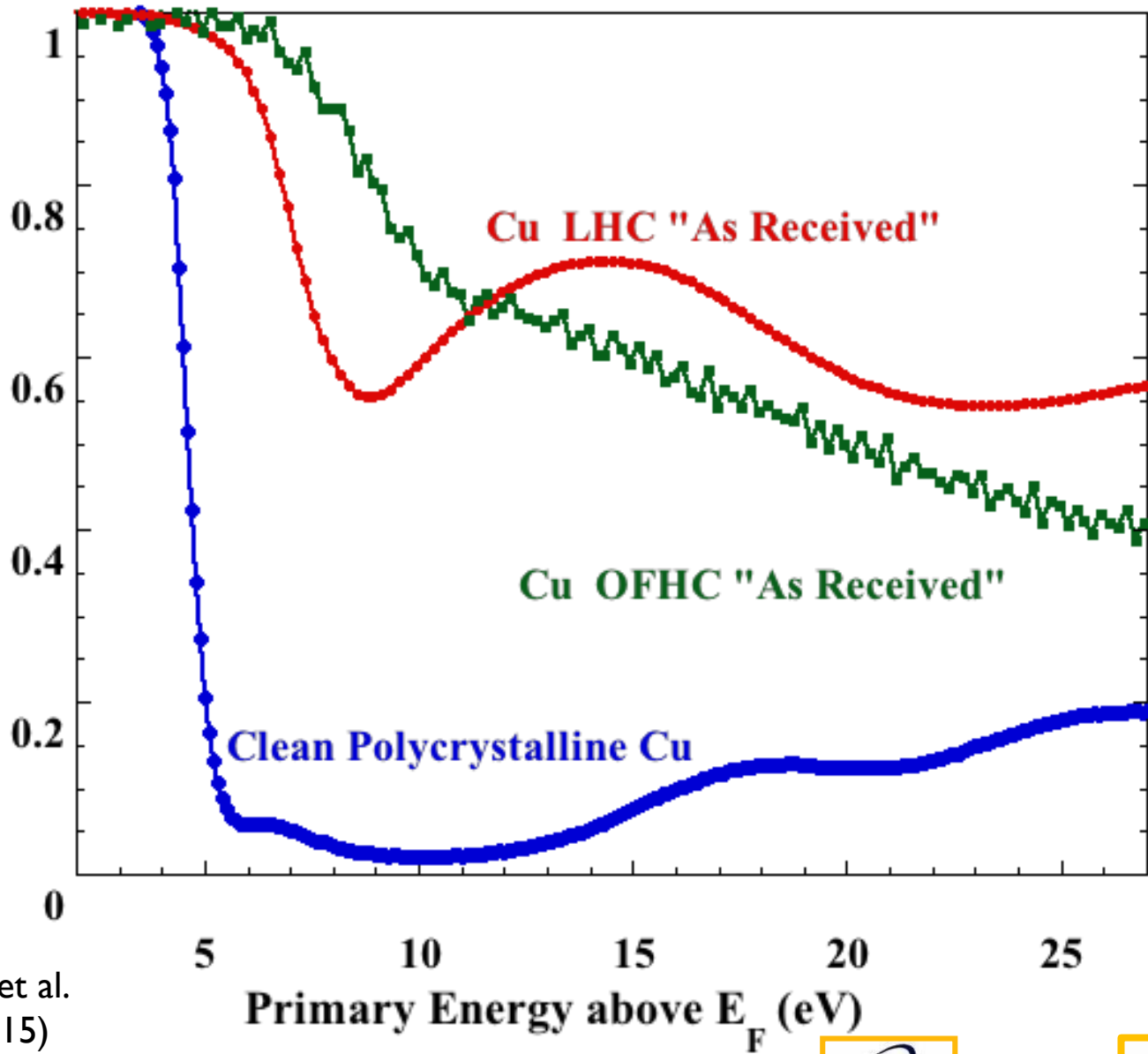
See: R. Cimino et al. PR ST (2015)

“As received” vs. Clean Cu



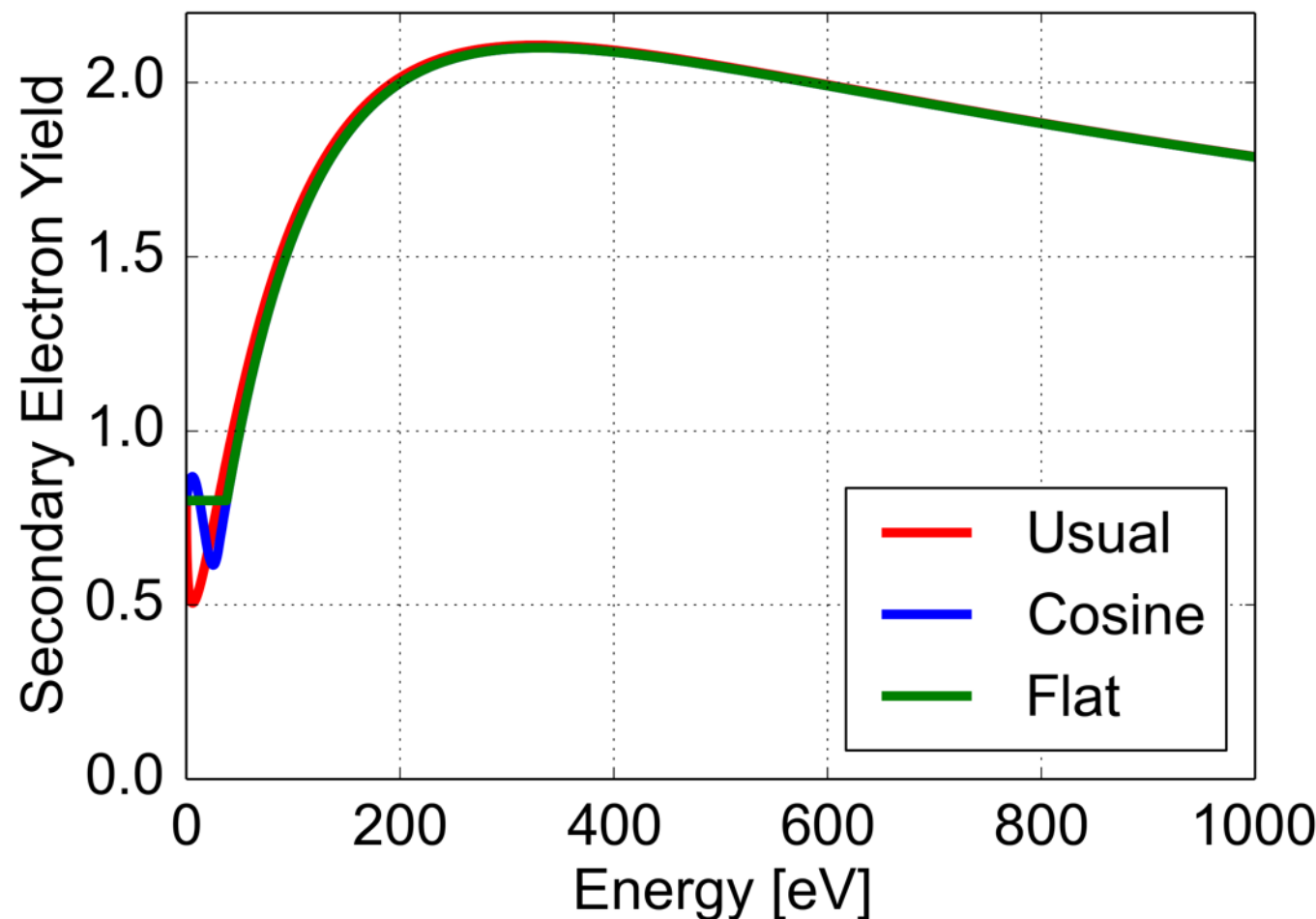
R. Cimino et al.
PR ST (2015)

“As received” vs. Clean Cu



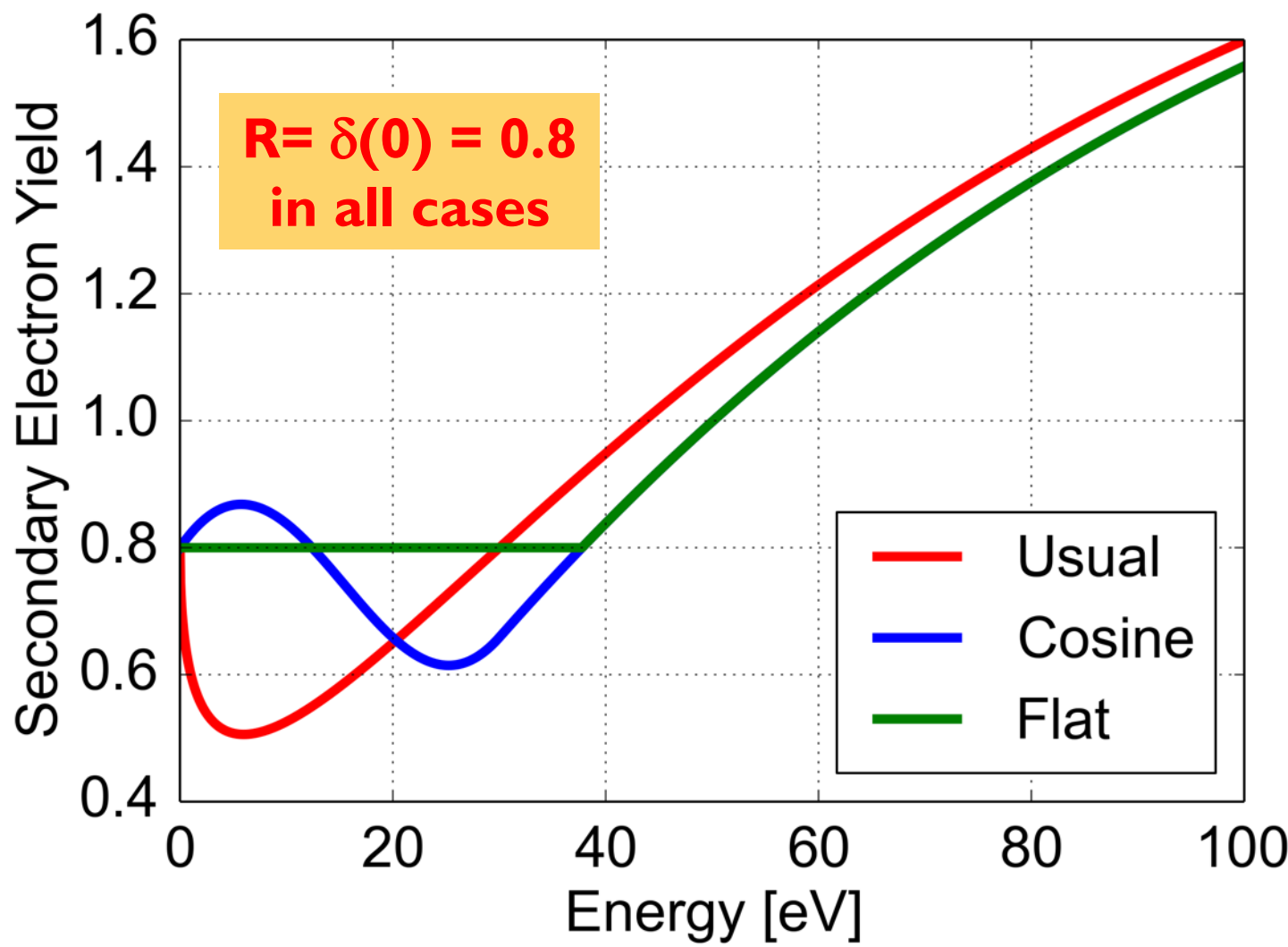
R. Cimino et al.
PR ST (2015)

For the LHC: test HL simulations.



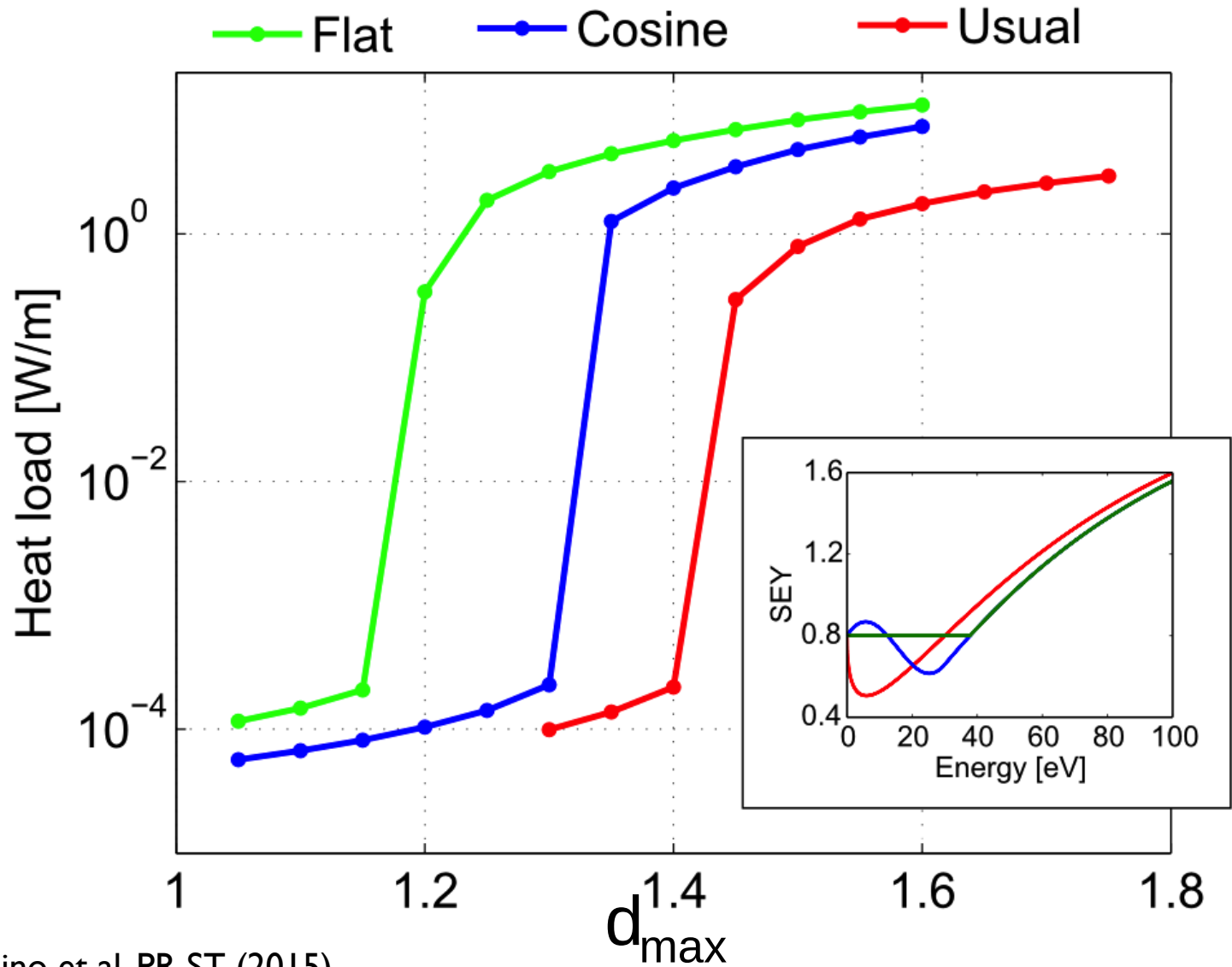
R. Cimino et al. PR ST (2015)

For the LHC: test HL simulations.



R. Cimino et al. PR ST (2015)

For the LHC: test HL simulations.



R. Cimino et al. PR ST (2015)

Electron cloud in accelerators

- Phenomenology:

What happens to the Vacuum beam pipe in presence of the beam? (LHC Example)

- Numerical model

- The Surface Science properties of relevance:

- ✓ SEY (Secondary Electron Yield);
- ✓ PY (Photo Yield);
- ✓ R (photon Reflectivity)

- Mitigation strategies

- Conclusion

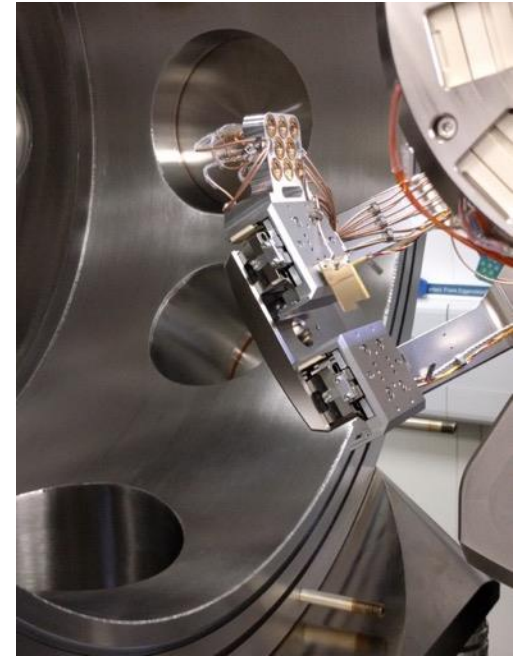
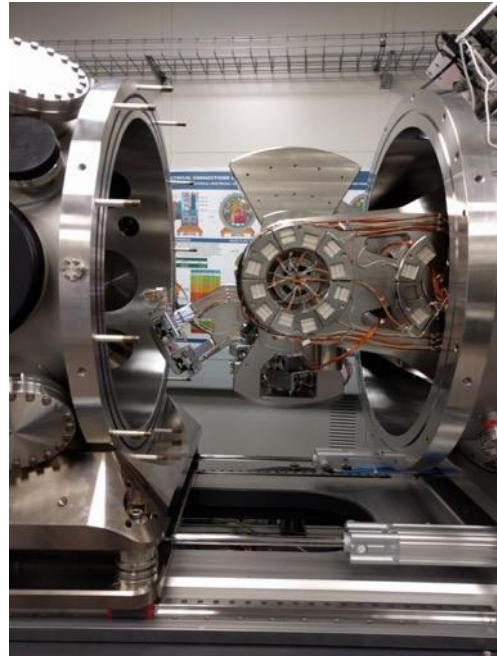
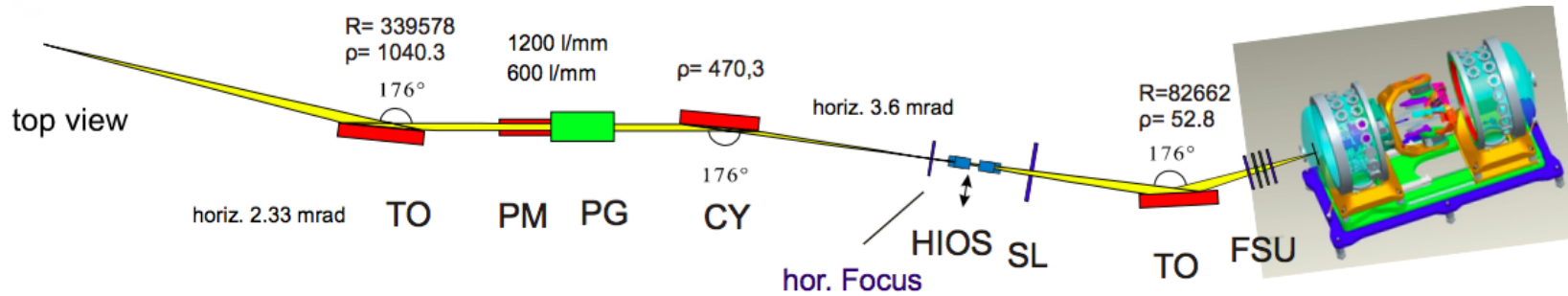
R. Cimino and T. Demma
“Electron cloud in Accelerators”
Int. J. Mod. Phys. A 29 (2014)
1430023 (pag. 65).

Why?

- Not only to study the input parameters used in simulations of multipacting and e-cloud build-ups, related instabilities
- But also to simulate and prevent single bunch instabilities just connected to the mere existence of a certain density of e^- in the accelerator chambers.

(K. Ohmi and F. Zimmermann PRL 2000)

Experimental set up to measure R & PY @ BESSY II - Optic Beamline and Reflectometer



A.A.Sokolov, et al, Proc. of SPIE 92060J-1-13 (2014)

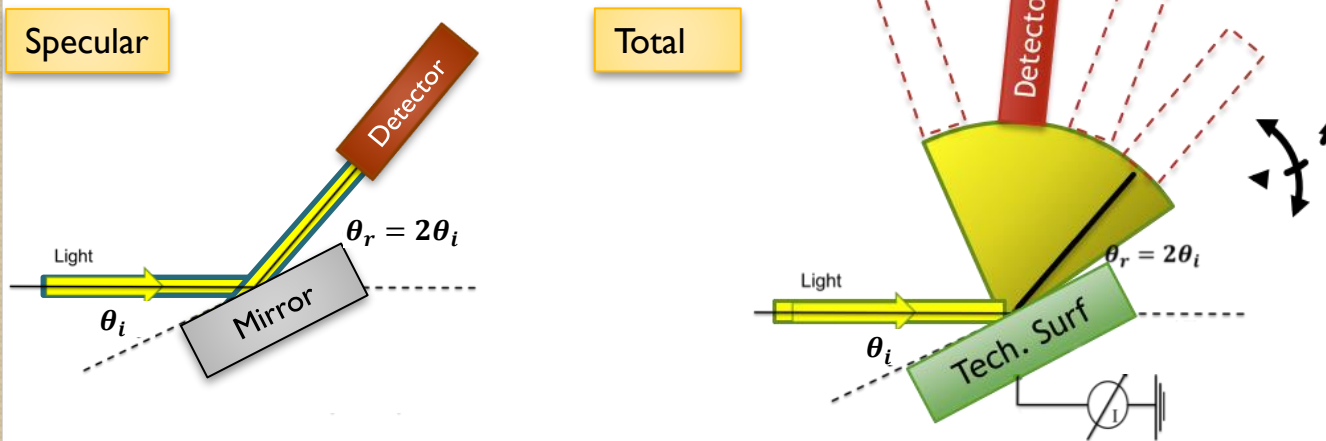
See: Eliana La Francesca @ FCC Week 2017, Berlin

Reflectivity and PY Measurements

- Photon Energy range 35÷1800 eV
- Beam height $h=0.3$ mm
- Incident Beam measurement
- GaAsP Photodiodes (4x4mm) (1.2*4mm)
- Incidence angle 0.25, 0.5 deg
- Reflectivity measurement

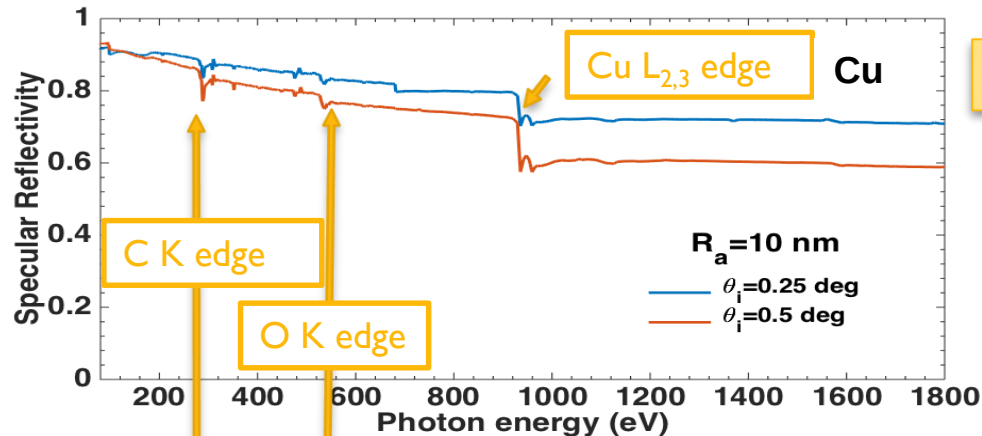
Photo Yield:
 $PY = N_e / N_\gamma$

Specular Reflectivity
Scattered Light

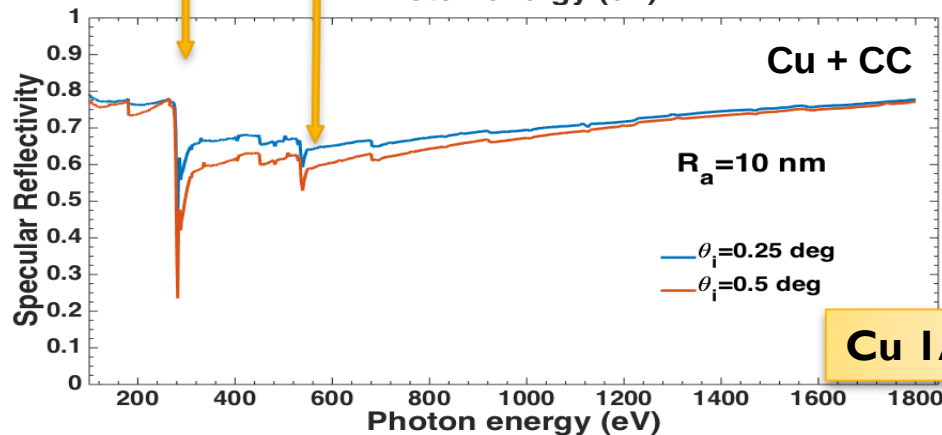
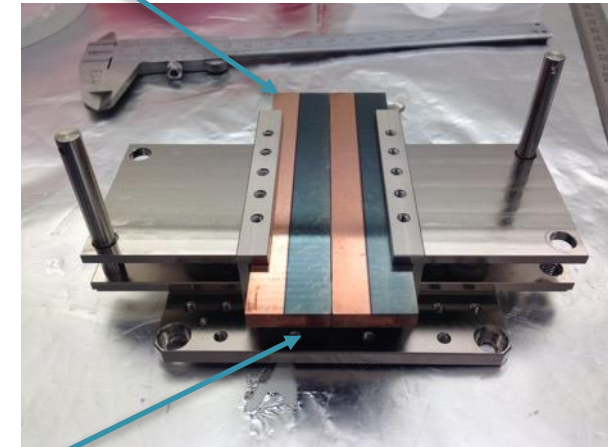
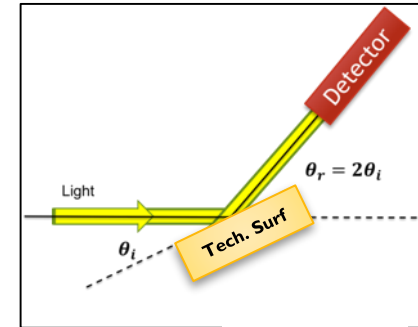


See: Eliana La Francesca @ FCC Week 2017, Berlin

Specular Reflectivity VS Photon energy



Cu IA



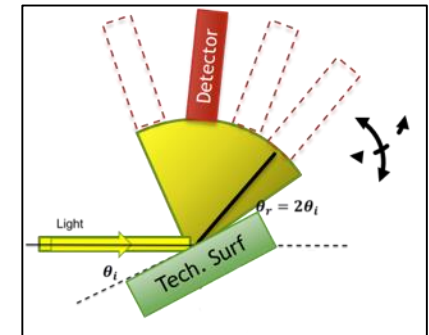
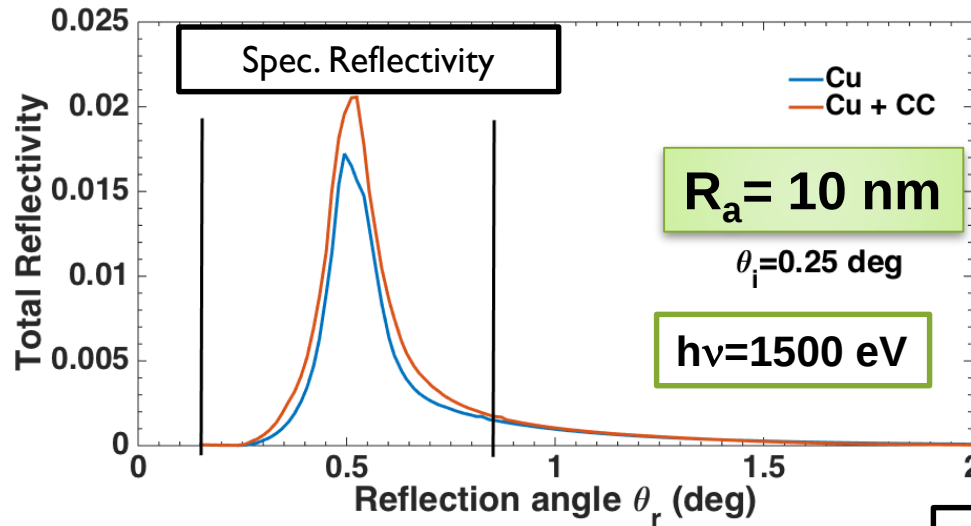
Cu IA + CC

At grazing incidence angle,
contaminants are
influencing Cu Reflectivity

At high energy reflectivity
is significantly enhanced

See: Eliana La Francesca @ FCC Week 2017, Berlin

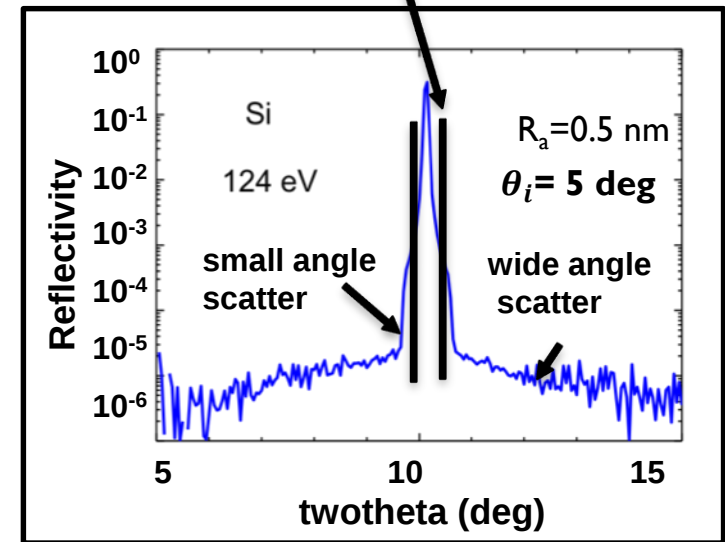
Total Reflectivity VS Specular Reflectivity



specular reflection

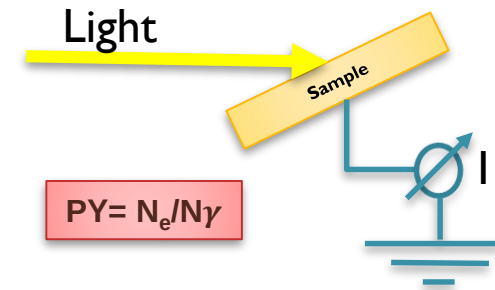
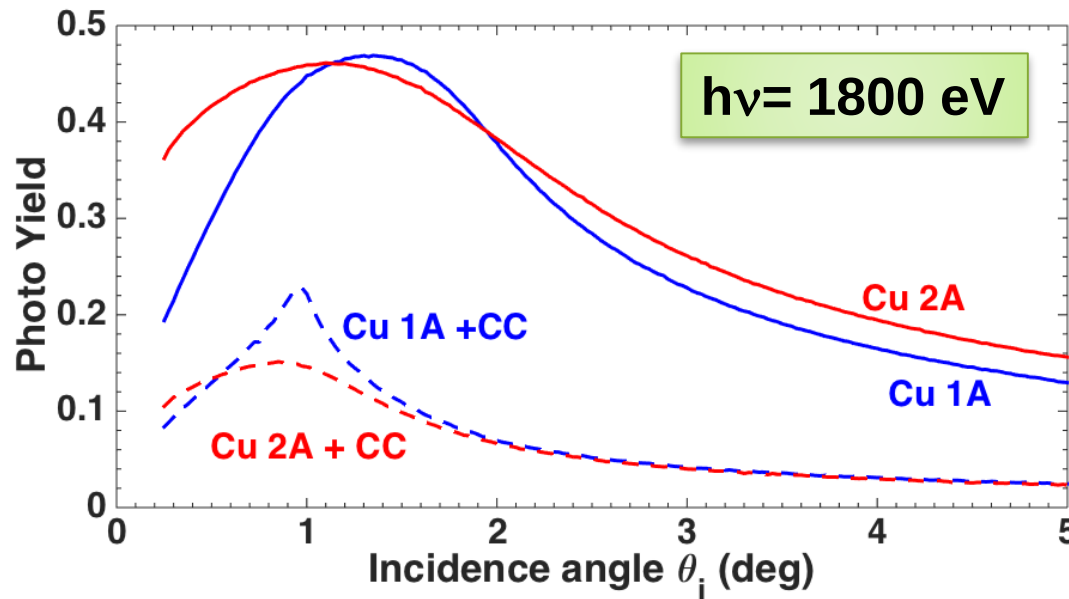
Sample	Specular Reflectivity	Total Reflectivity
Cu IA	0.61	0.73
Cu IA + CC	0.78	0.90

Scattered photons goes top & bottom



See: Eliana La Francesca @ FCC Week 2017, Berlin

Photo Yield VS Incidence angle



I Sample need to be normalised to N_γ to be a Yield

Preliminary Results:

- little dependence on roughness
- Carbon coating seems to reduce PY

Sample	Cu 1A ($R_a=10$ nm) Max value	Cu 2A ($R_a=30$ nm) Max value
Cu	0.47	0.46
Cu + CC	0.23	0.15

See: Eliana La Francesca @ FCC Week 2017, Berlin

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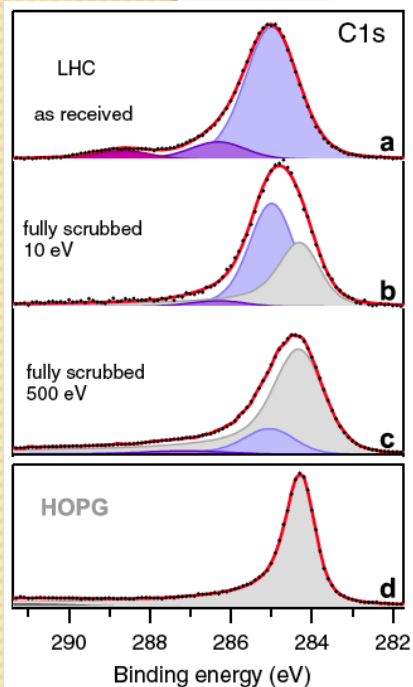
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R. Cimino and T. Demma
“Electron cloud in Accelerators”
Int. J. Mod. Phys. A 29 (2014)
1430023 (pag. 65).

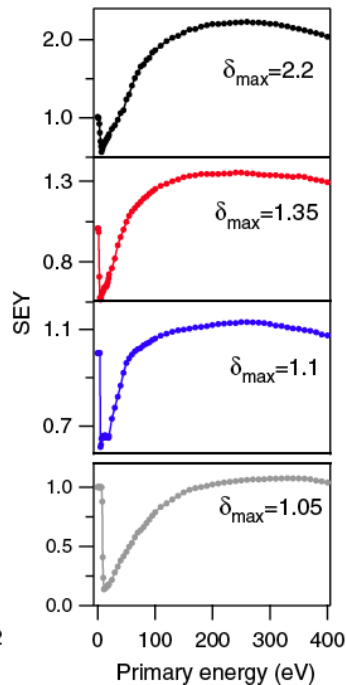
Towards mitigation Strategies....

- ✓ We measure and feed material parameters (**R**, **PY**, and **SEY**) into simulations.
- ✓ Understand their profound nature to:
- ✓ Optimize chemical (mech.) processes to reduce their detrimental influence on beam.
- ✓ Search for new material / coatings with intrinsically “good” parameters.

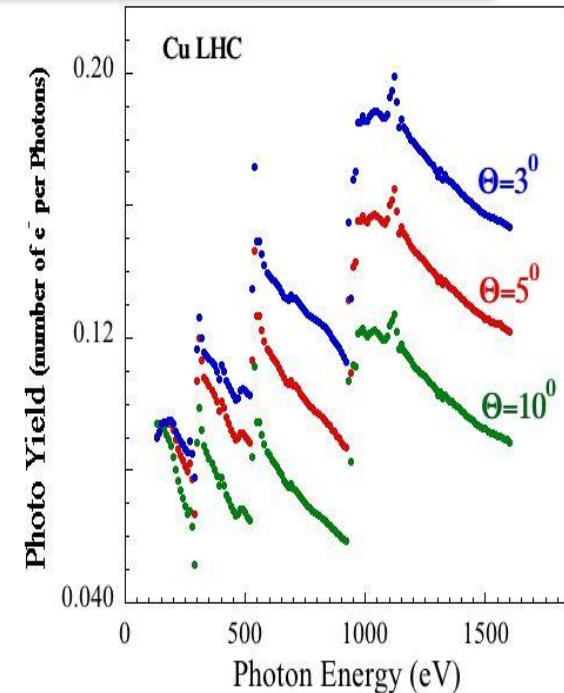
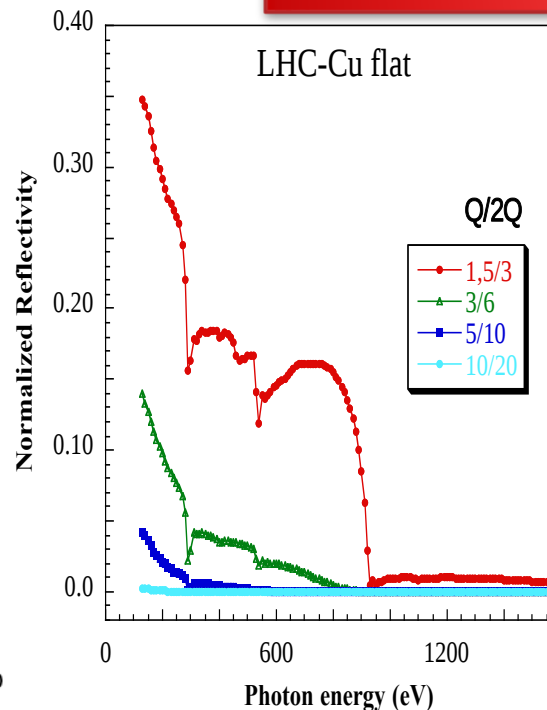
XPS



SEY



SR Reflectivity and PY (@BESSY-II)



Most of the existing and planned accelerator machines base the reaching of their design parameters to the capability of obtaining walls with a SEY ~ 1.3 or below!

Mitigation Strategies

External solenoid field

Electrodes in the lattice

Surface Scrubbing
(or conditioning)

Intrinsically low
SEY material

Geometrical modifications

External solenoid
field.



Not always possible...

Electrodes in the
lattice.



If possible...
(Impedance, costs.)

Scrubbing
(or conditioning)



-Efficiency
(time & final SEY)...

Intrinsically low
SEY material



Stability and material
choice...

Geometrical
modifications



Impedance. Space,
Machining costs.

External solenoid
field.



Not always possible...

Electrodes in the
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Impedance. Space,
Machining costs.

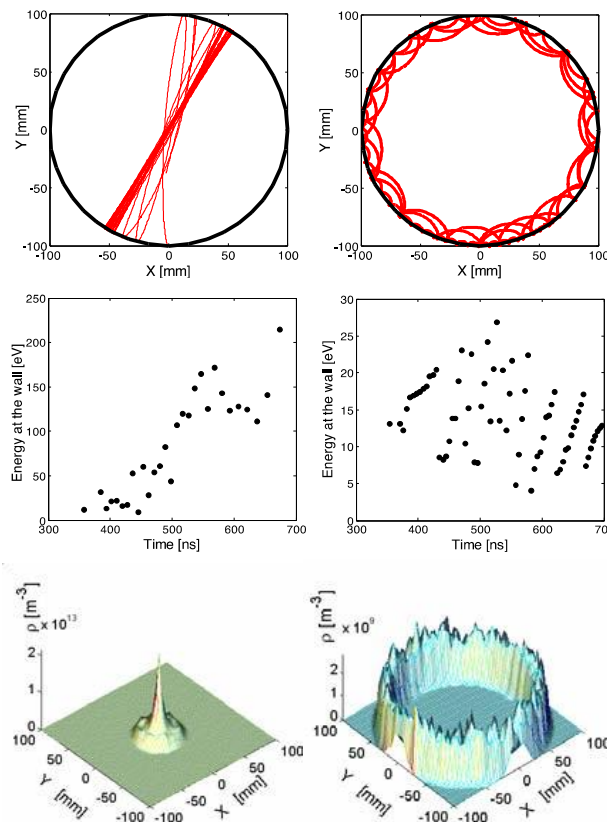
SOLENOID EFFECTS ON AN ELECTRON CLOUD

L. Wang, BNL, Upton, NY 11973, USA

S. Kurokawa, H. Fukuma, S.S. Win, Tsukuba, KEK, Japan

A. Chao, SLAC, Menlo Park, California, USA

No field



60 Gauss
solenoid
field

Adopted solution
for SuperKEK
bellows

Figure 2: Electron orbit (top row), energy at the wall (middle row), and electron-cloud distribution (bottom row) with 0 G (left column) and 60G (right column) solenoid fields in the SNS's accumulator drift region

External solenoid field.



Not always possible...

Electrodes in the lattice.



If possible...
(Impedance, costs.)

Scrubbing
(or conditioning)



-Efficiency
(time & final SEY)...

Intrinsically low
SEY material



Stability and material
choice...

Geometrical
modifications



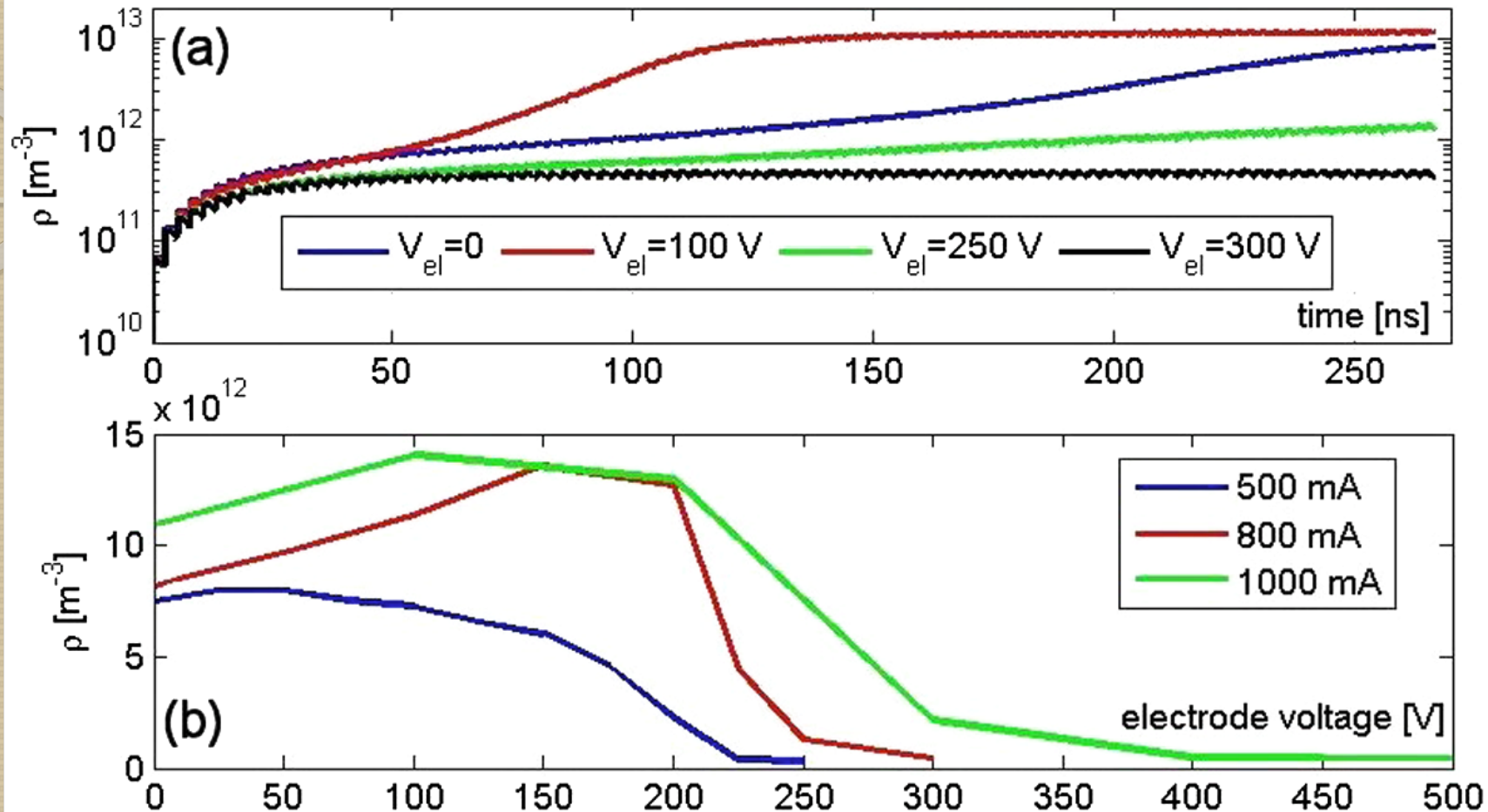
Impedance. Space,
Machining costs.

Electrodes at DAΦNE



D. Alesini et al. *Phys. Rev. Lett.* **110**, 124801 (2013)

Electrodes at DAΦNE



(a) Evolution of the averaged cloud density for different values of the electrode voltage. (b) e⁻ cloud density at the end of the bunch train.

D. Alesini et al. *Phys. Rev. Lett.* **110**, 124801 (2013)

External solenoid field.



Not always possible...

Electrodes in the lattice.



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Stability and material
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Geometrical
modifications

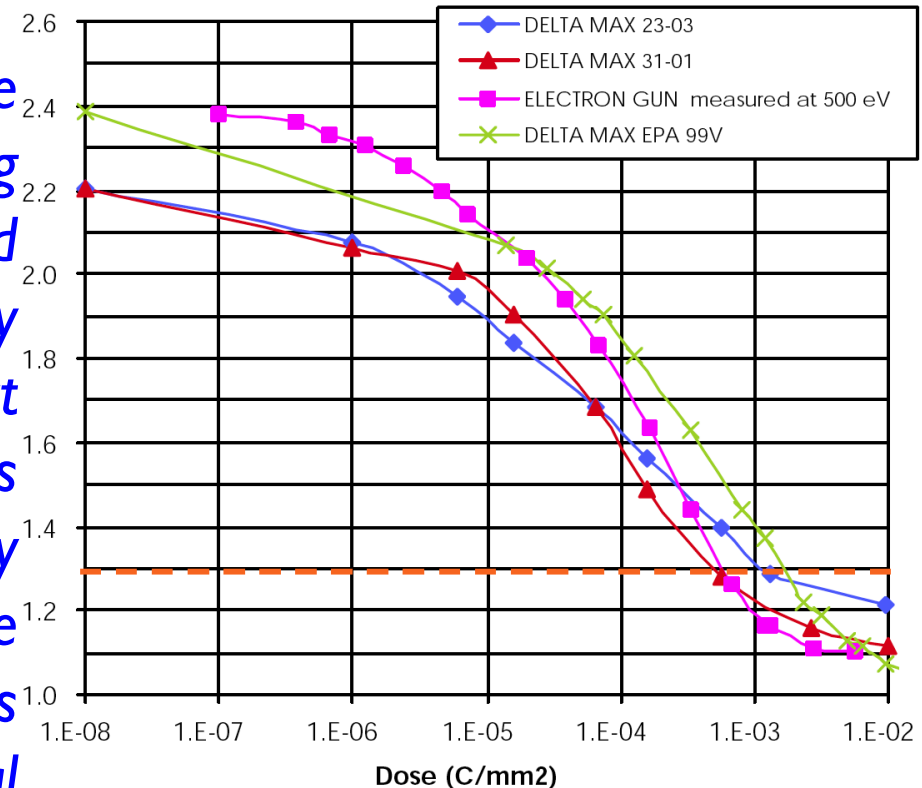


Impedance. Space,
Machining costs.

The Beam “scrubbing” effect is the ability of a surface to reduce its SEY after e^- bombardment.

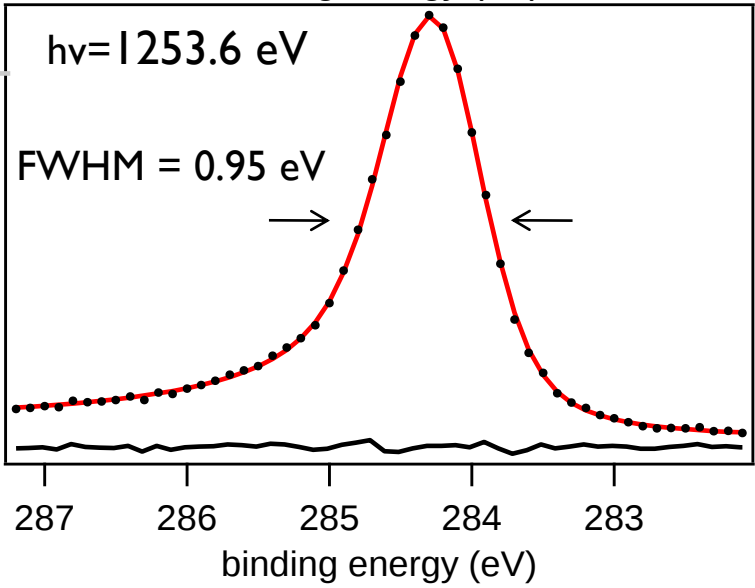
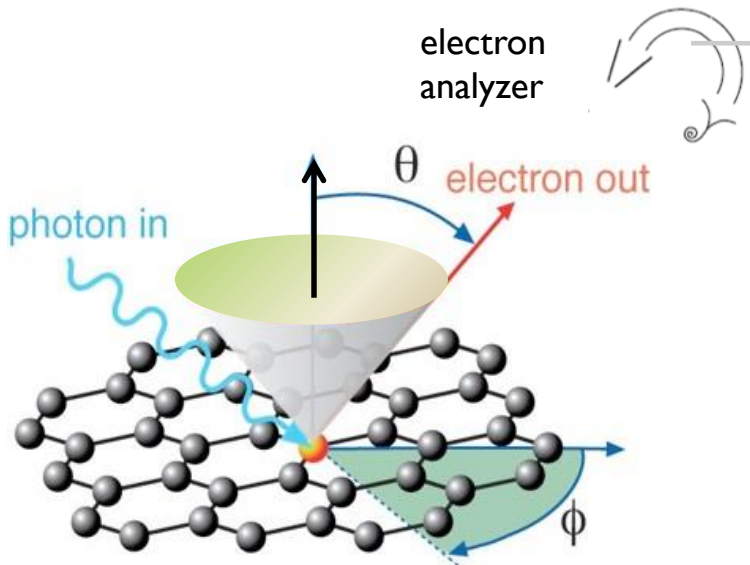
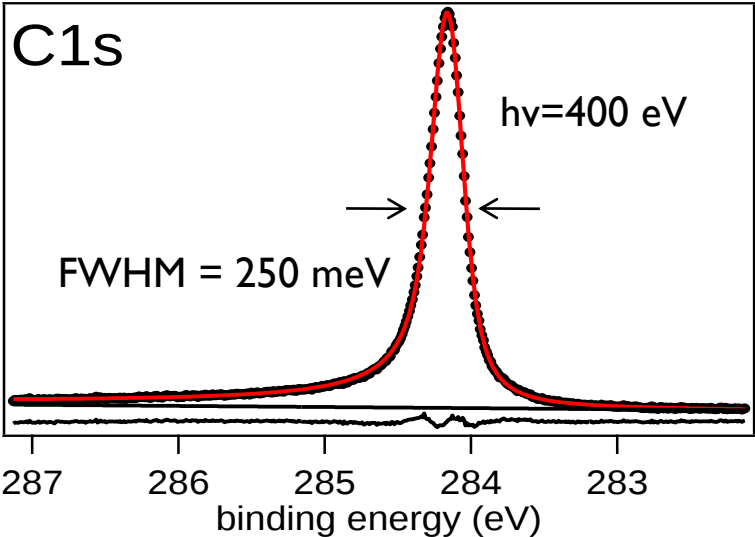
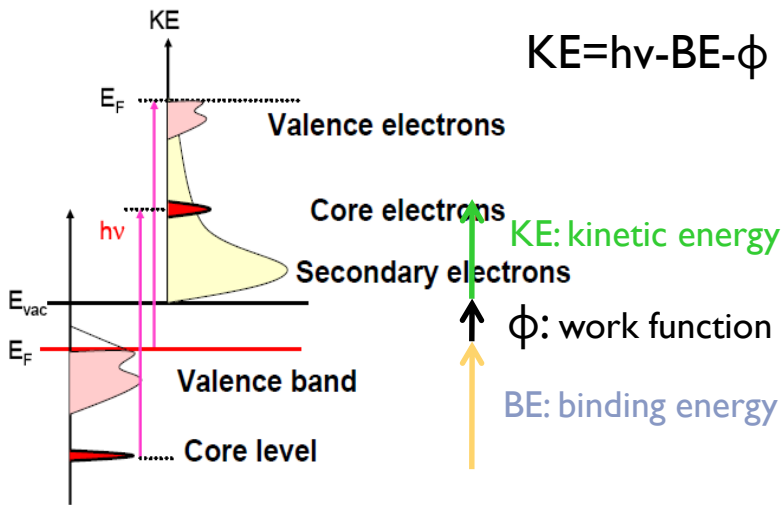
from LHC PR 472 (Aug. 2001):

“...Although the phenomenon of conditioning has been obtained reproducibly on many samples, the exact mechanism leading to this effect is not properly understood. This is of course not a comfortable situation as the LHC operation at nominal intensities relies on this effect...”



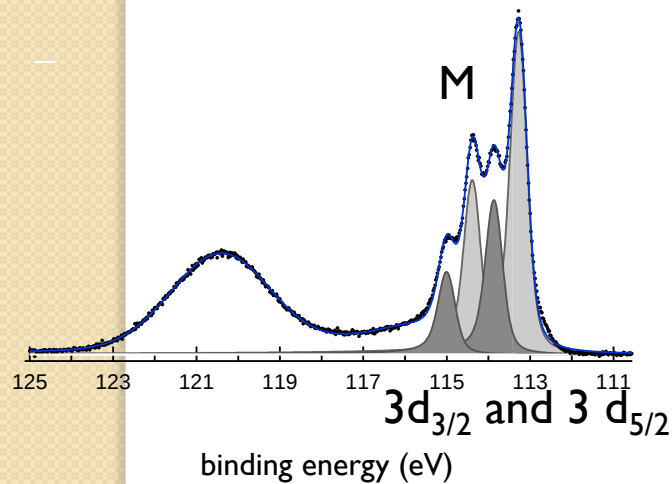
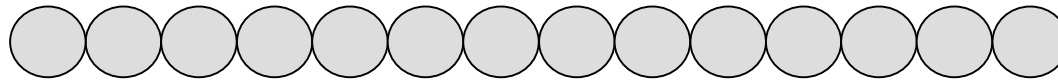
V. Baglin et al, LHC Project Report 472, CERN, 2001.

X-ray photoelectron spectroscopy $\theta_{\text{emiss}}=0^\circ$

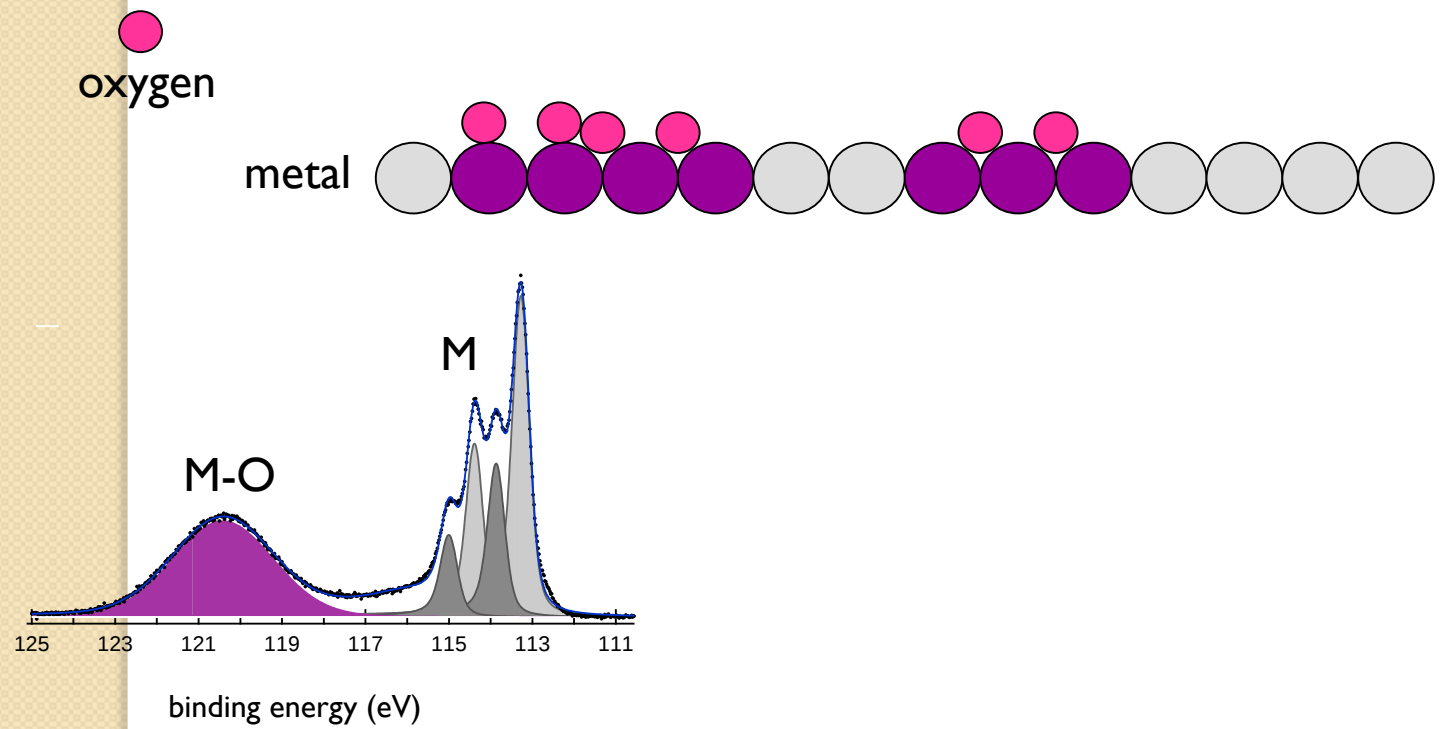


XPS spectroscopy of technical samples

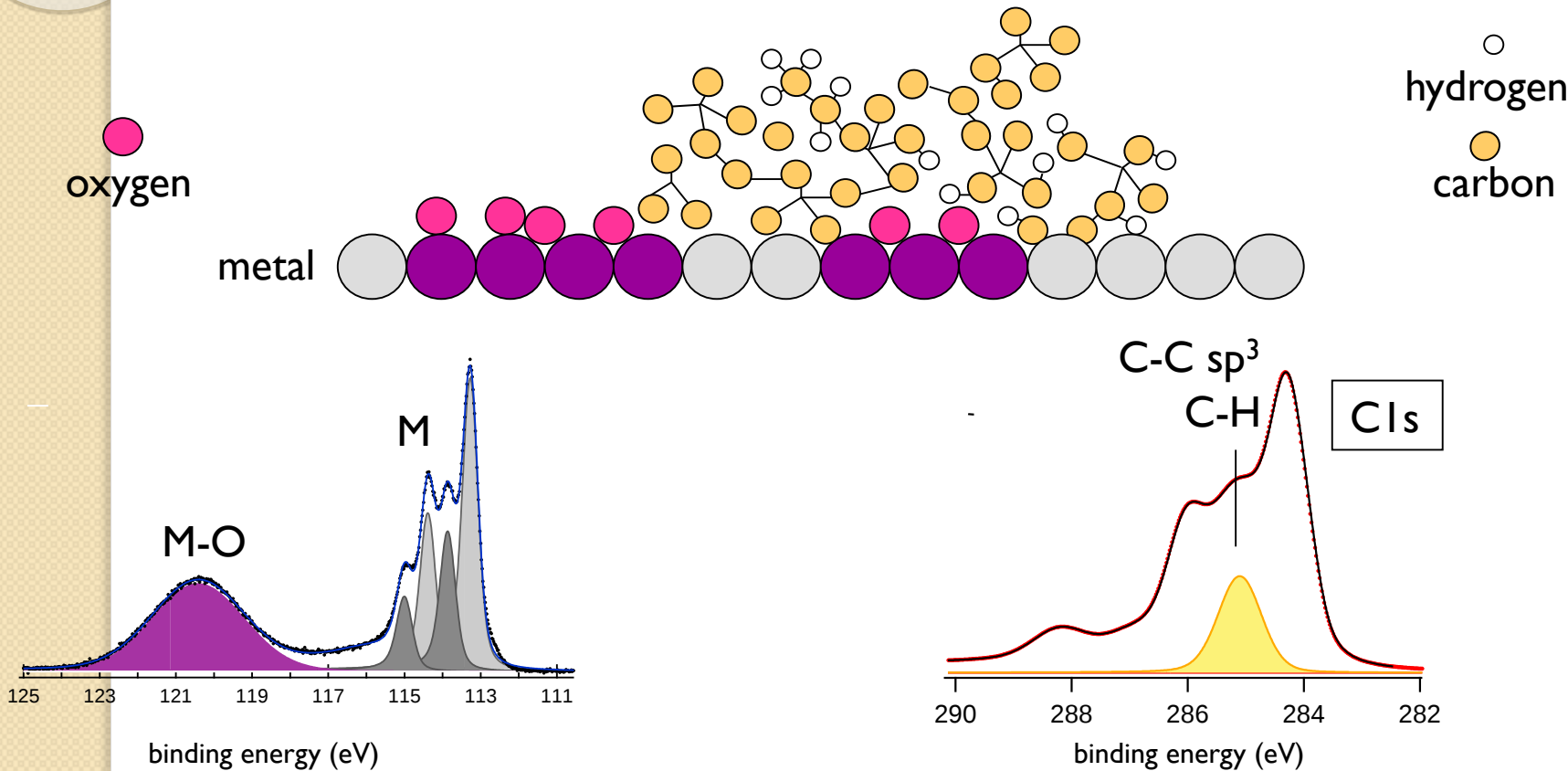
Metal
(Rb)



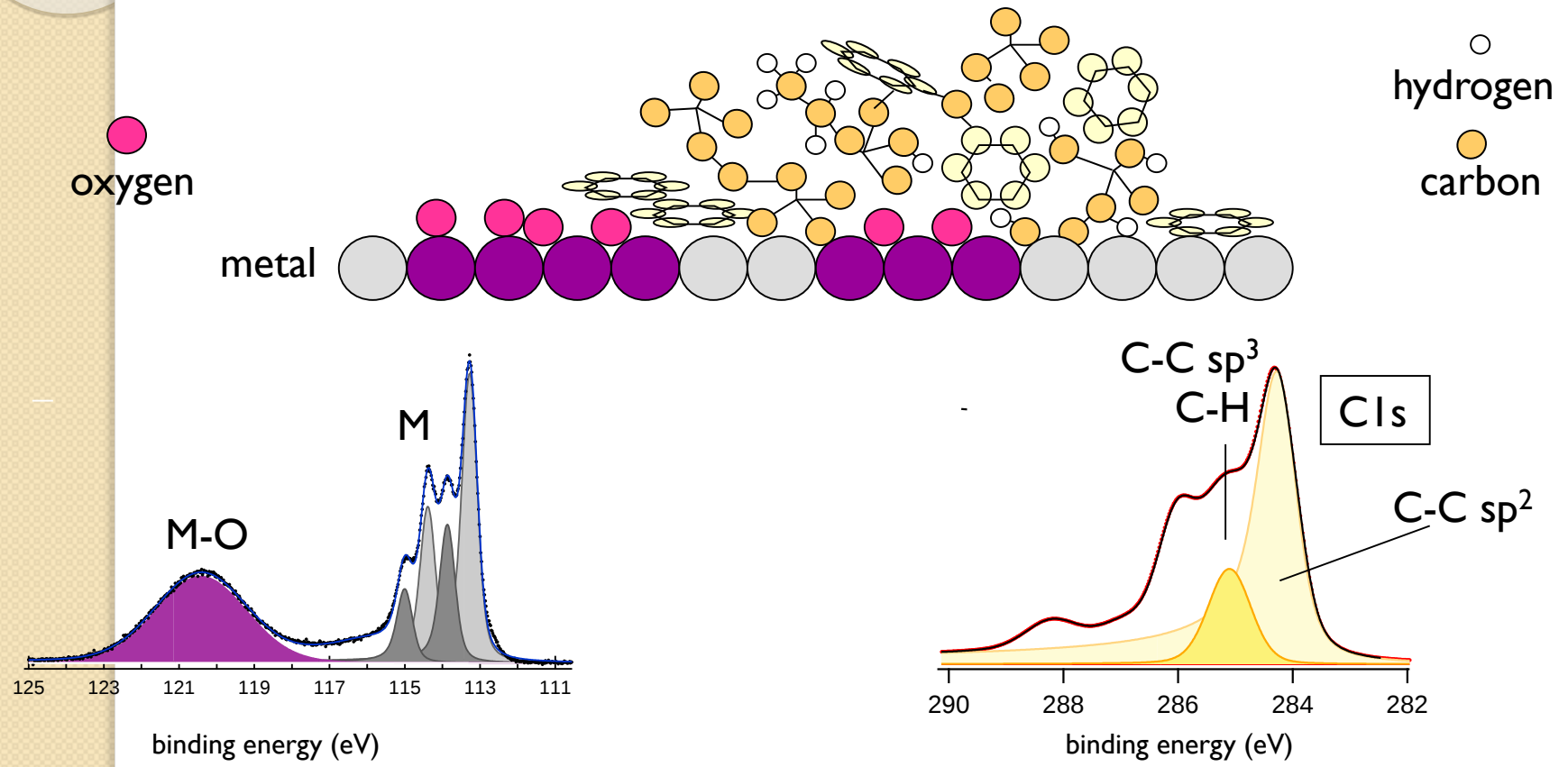
XPS spectroscopy of technical samples



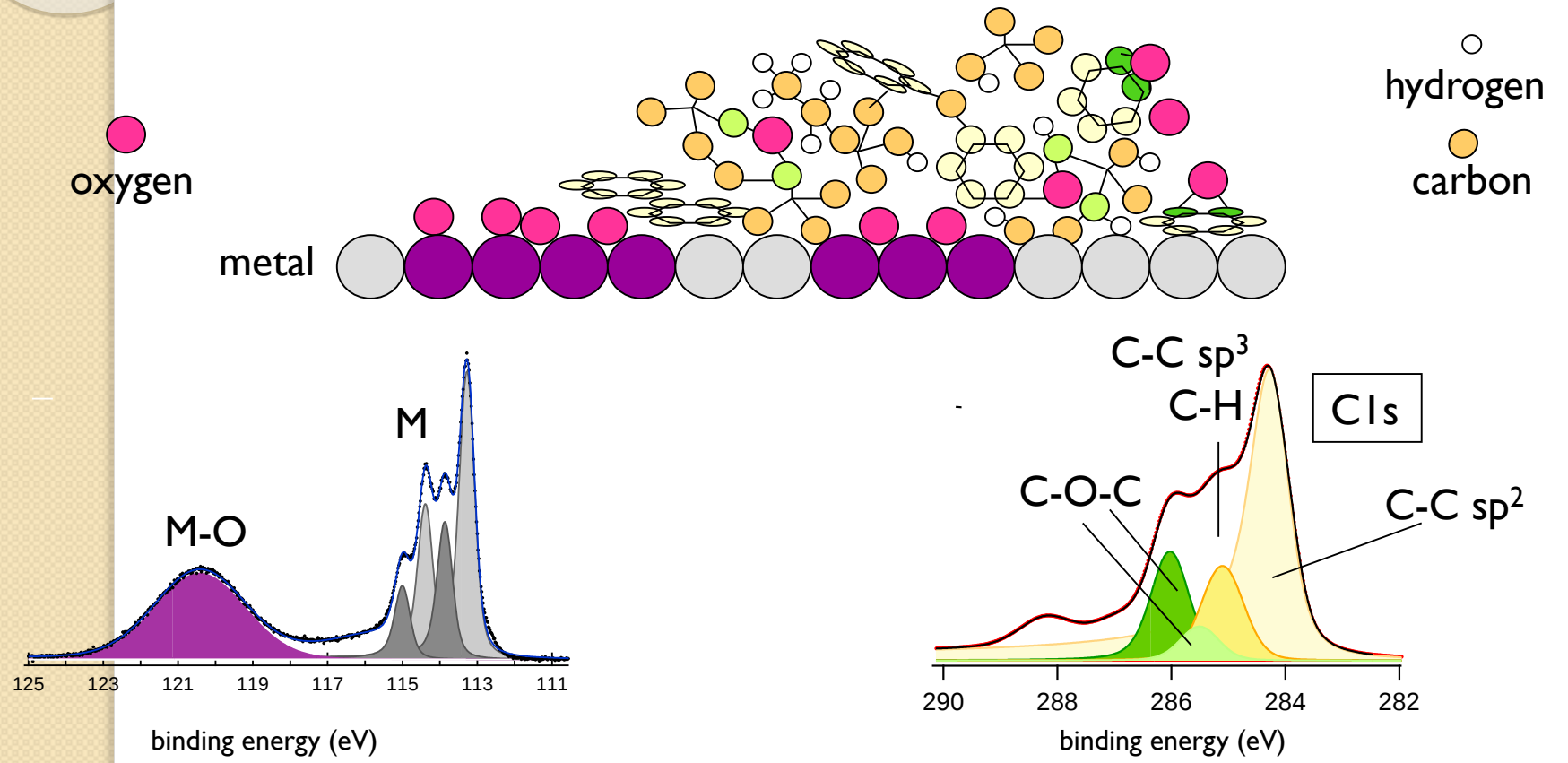
XPS spectroscopy of technical samples



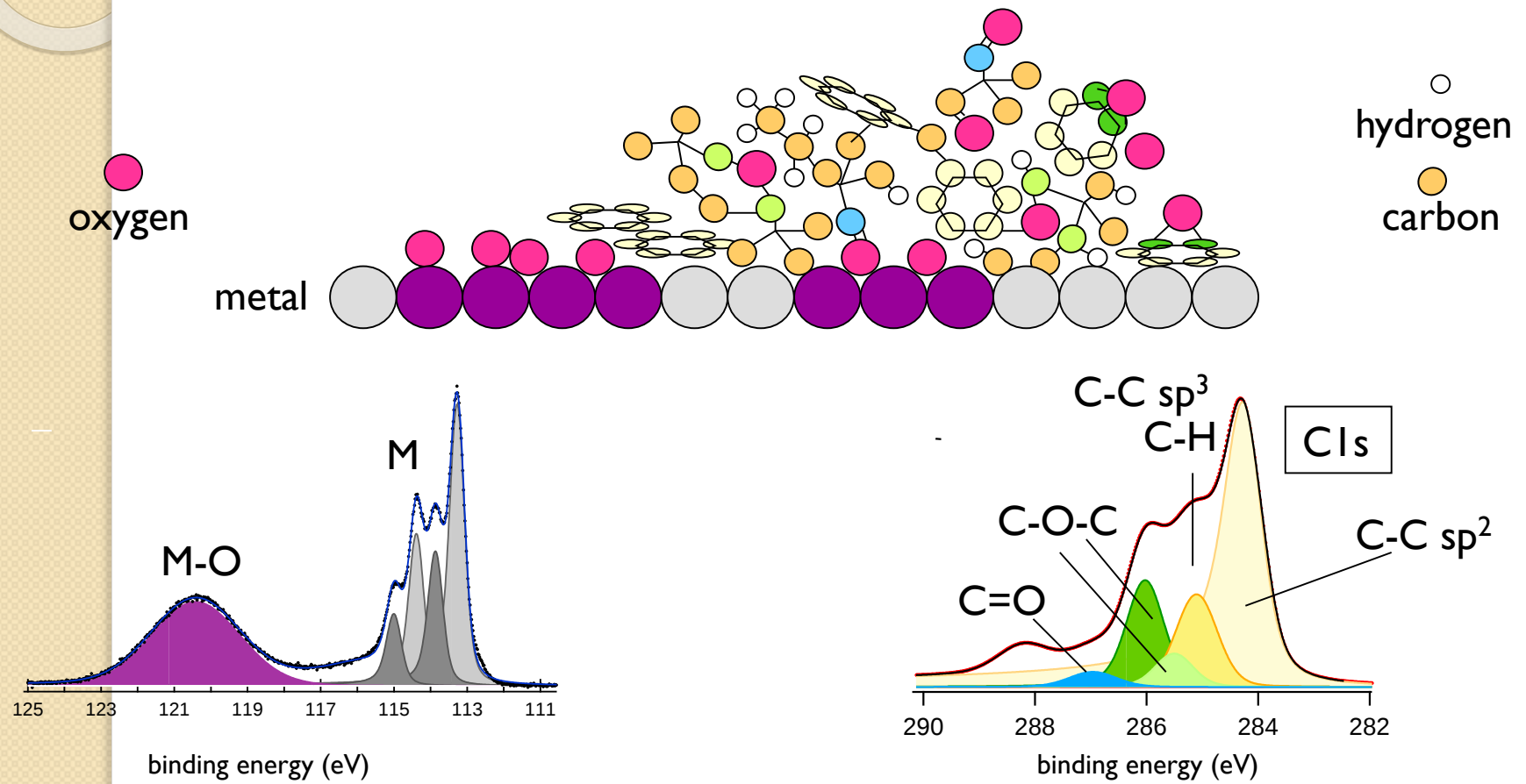
XPS spectroscopy of technical samples



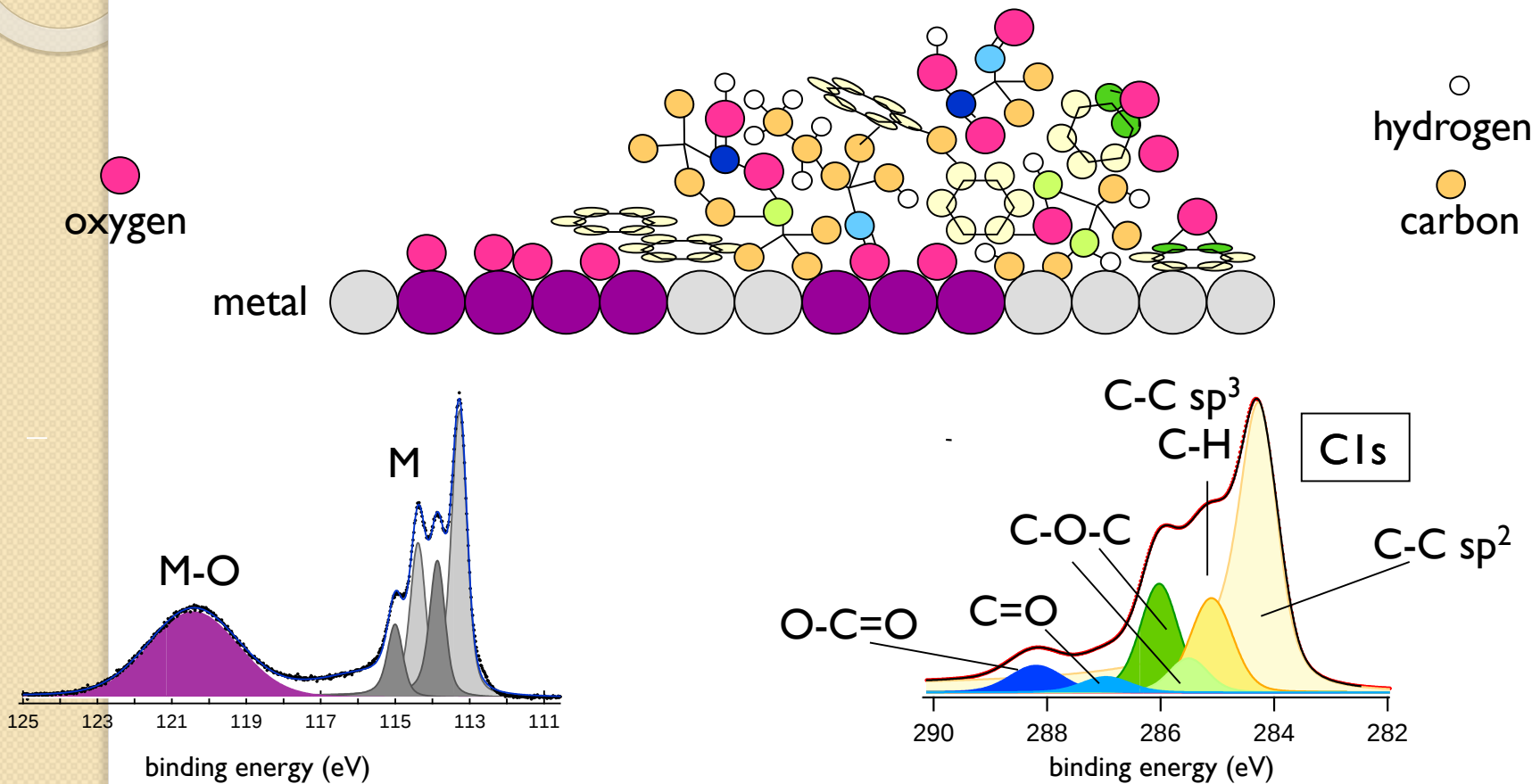
XPS spectroscopy of technical samples



XPS spectroscopy of technical samples

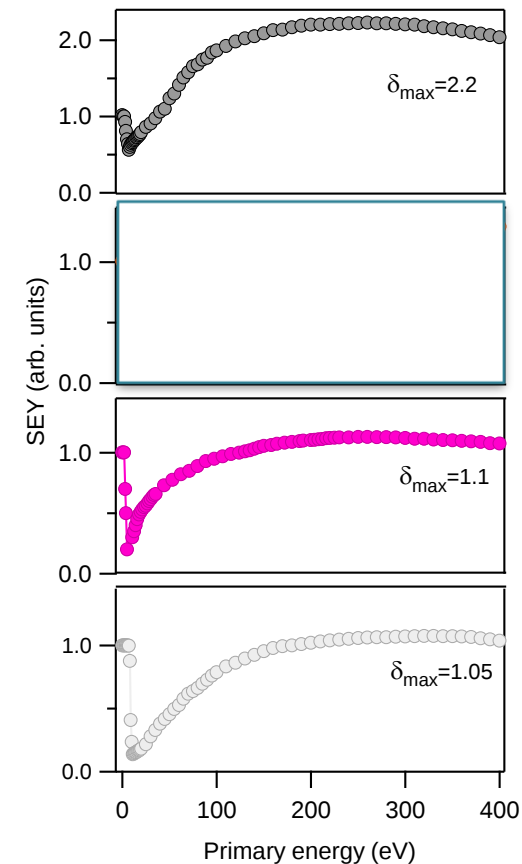
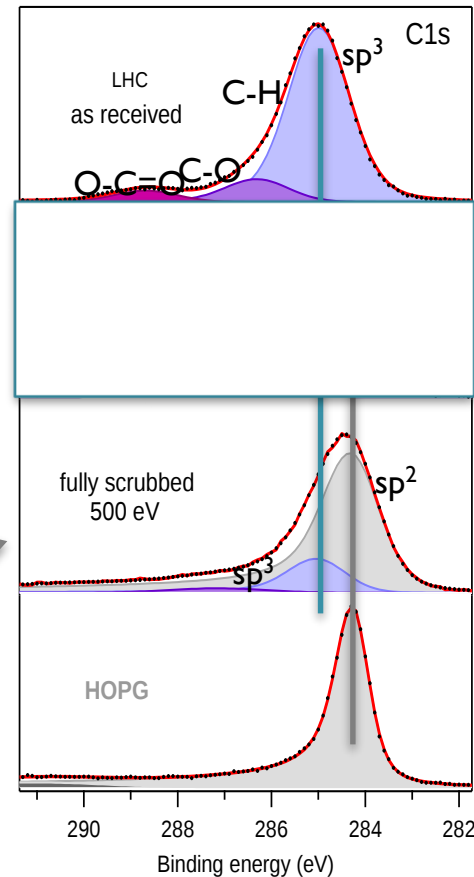
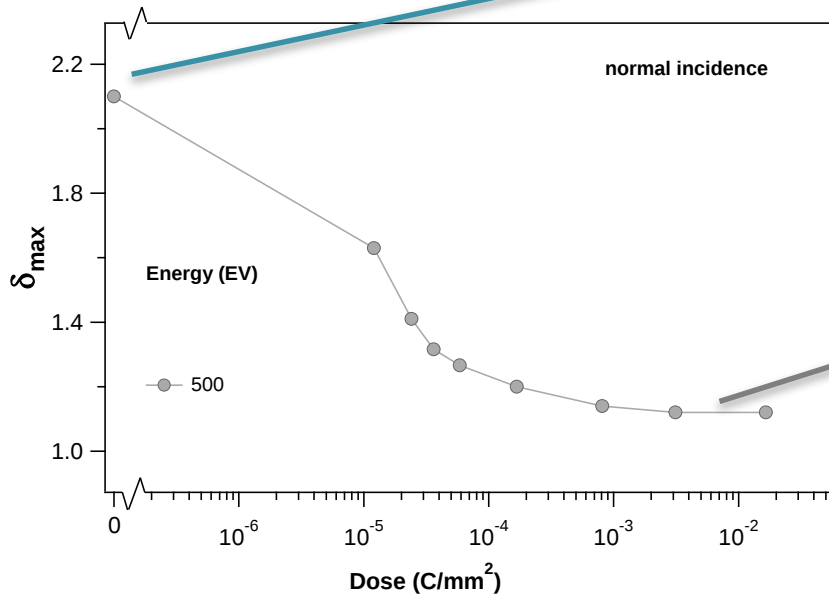


XPS spectroscopy of technical samples



co-laminated Cu for LHC: fully scrubbed

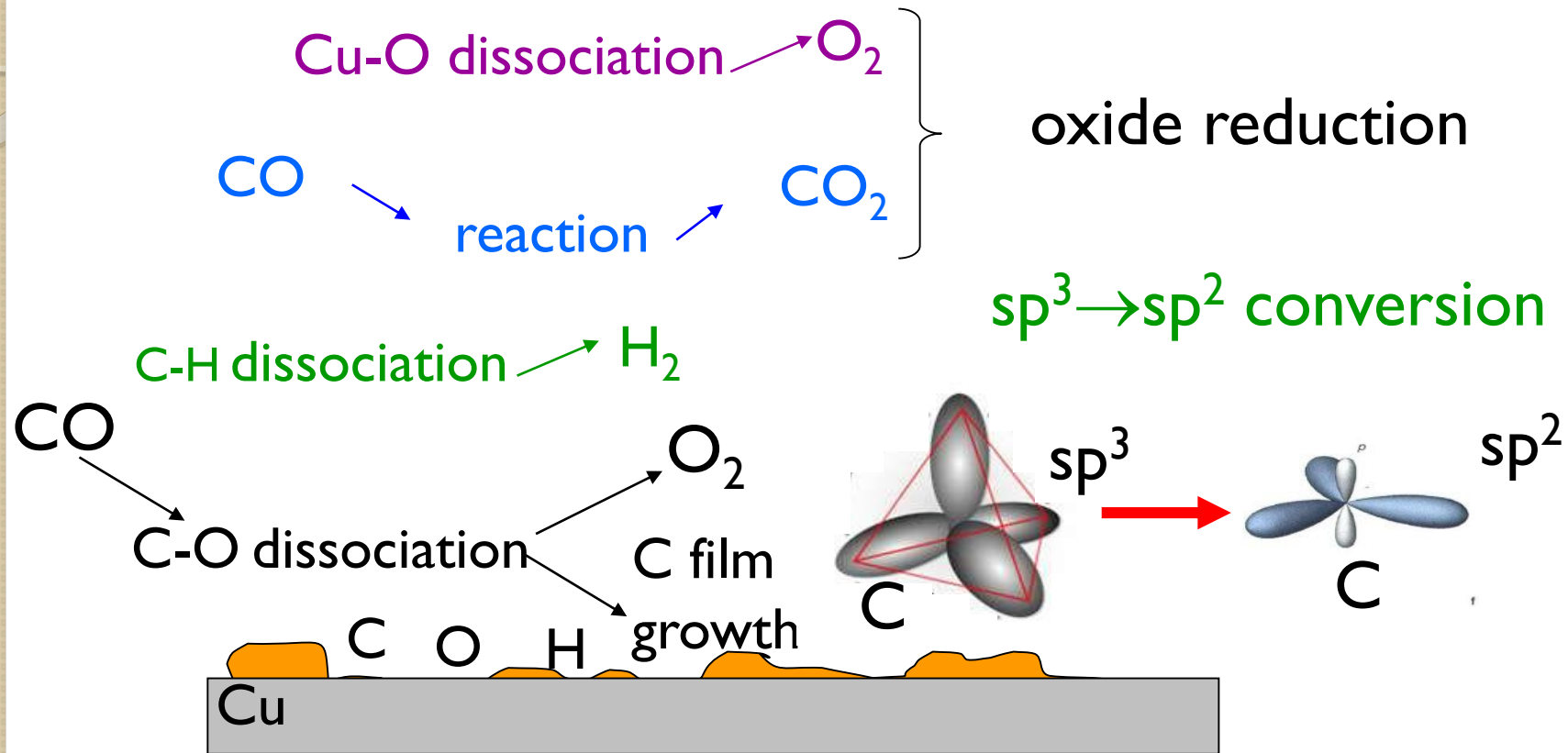
R. Cimino et al. PRL
109 064801 (2012)



SEY and XPS are directly related

e^- beam induced surface reactions

R. Cimino et al. PRL (2012) & R. Larciprete PR ST (2013)

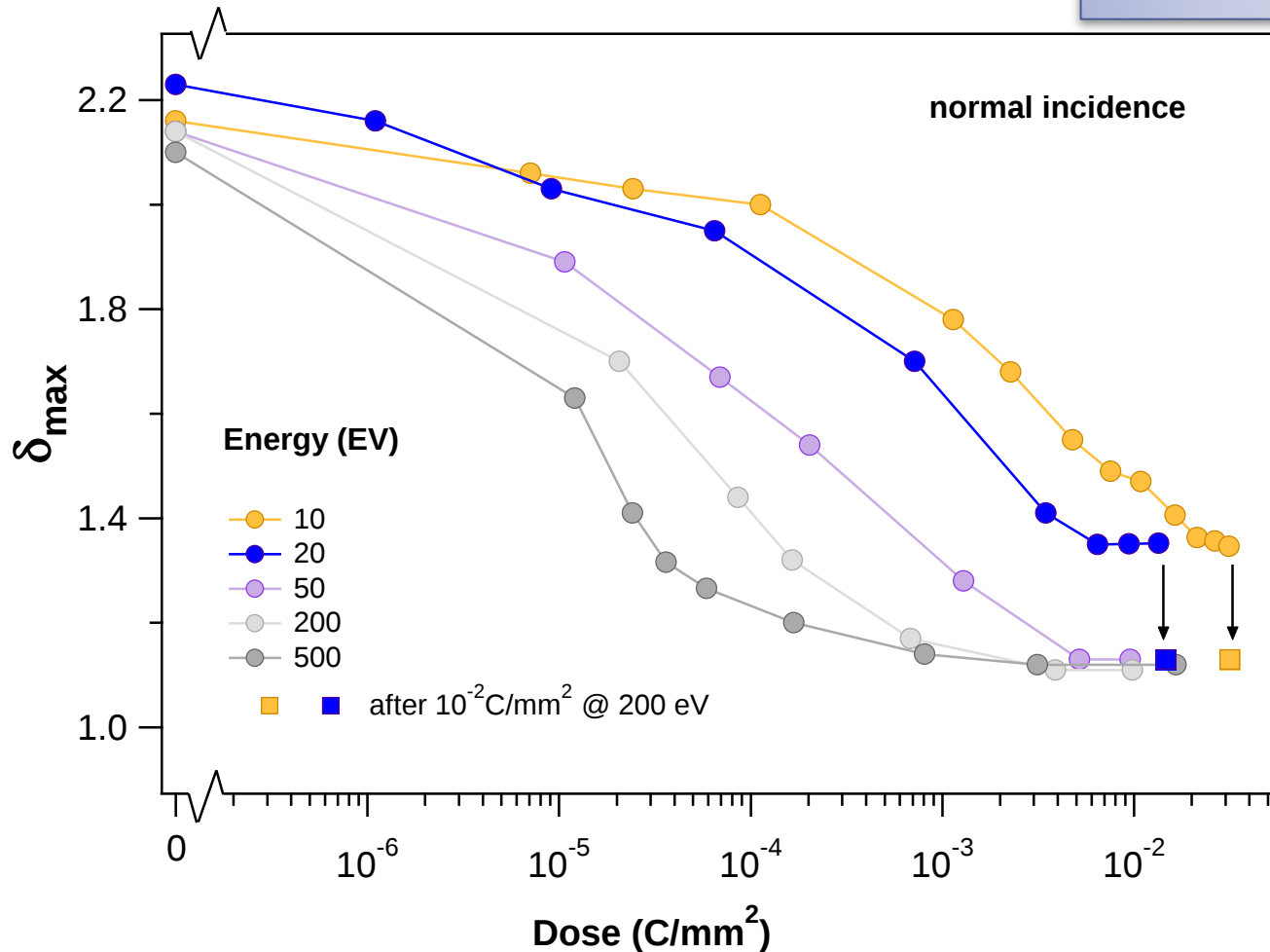


the contribution of all electron-induced surface reaction reduces $\delta_{\max}$ from 2.2 to 1.1

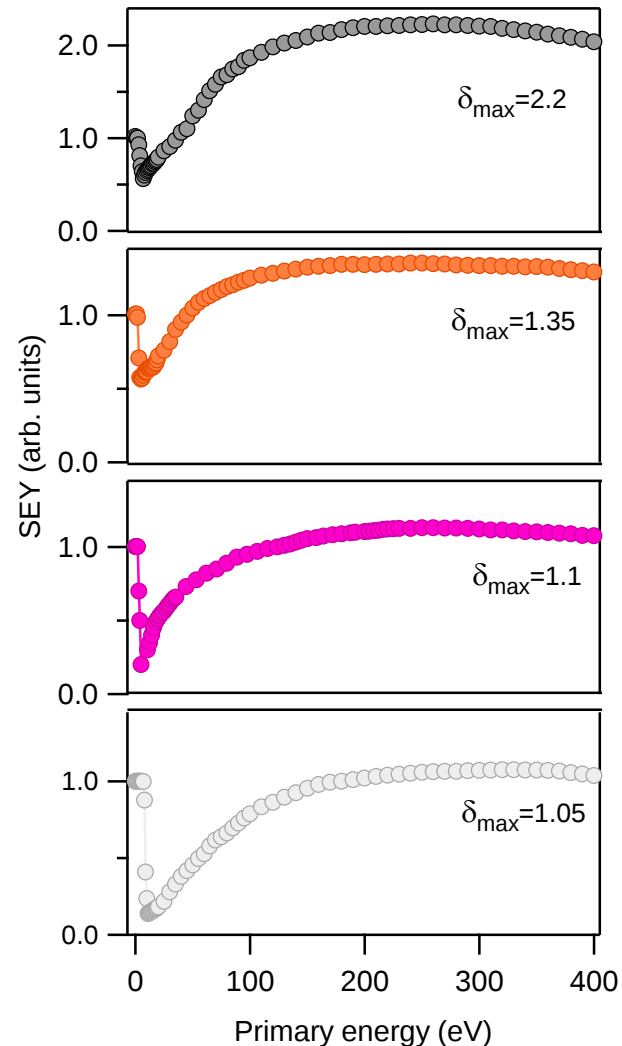
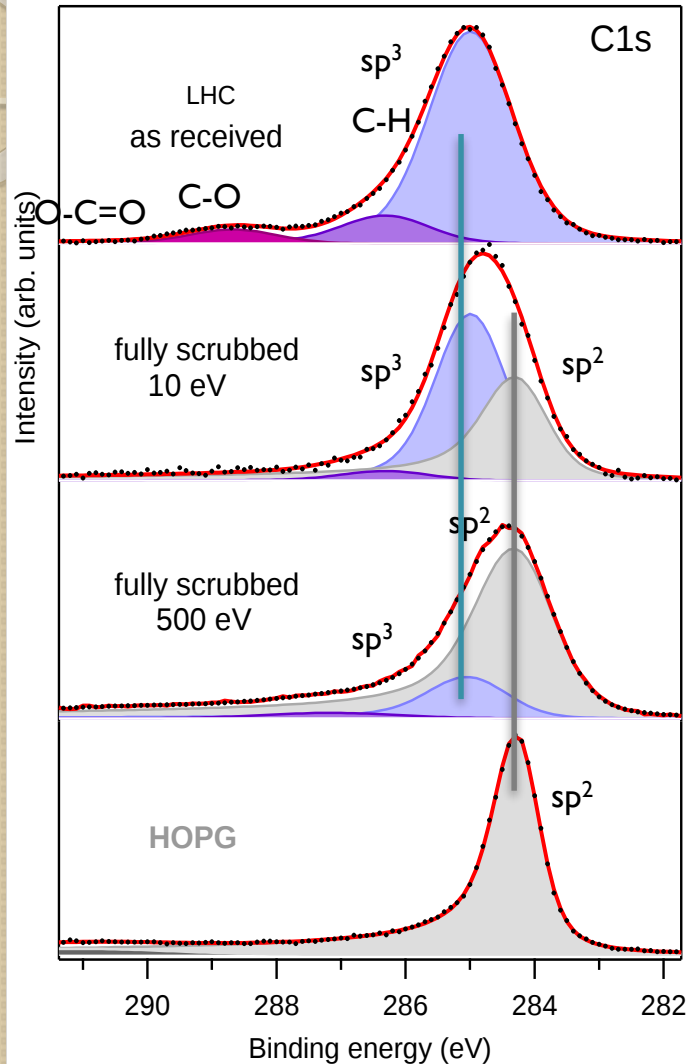
co-laminated Cu for LHC beam screen

R. Cimino et al. PRL **109 064801 (2012)**

e^- Beam energy counts!



co-laminated Cu for LHC beam screen



R. Cimino et al. PRL
109 064801
(2012)

Table 1: Parameters used for ECLOUD simulations.

parameter	units	value
beam particle energy	GeV	7000
bunch spacing t_b	ns	25; 50; 75
bunch length	m	0.075
number of trains N_t	-	4
number of bunches per train N_b	-	72; 36; 24
bunch gap N_g	-	8
no. of particles per bunch	10^{10}	10; 3.0
length of chamber section	m	1
chamber radius	m	0.02
circumference	m	27000
primary photo-emission yield	-	$7.98 \cdot 10^{-4}$
maximum SEY δ_{max}	-	1.2(0.2)2.0
energy for max. SEY E_{max}	eV	237

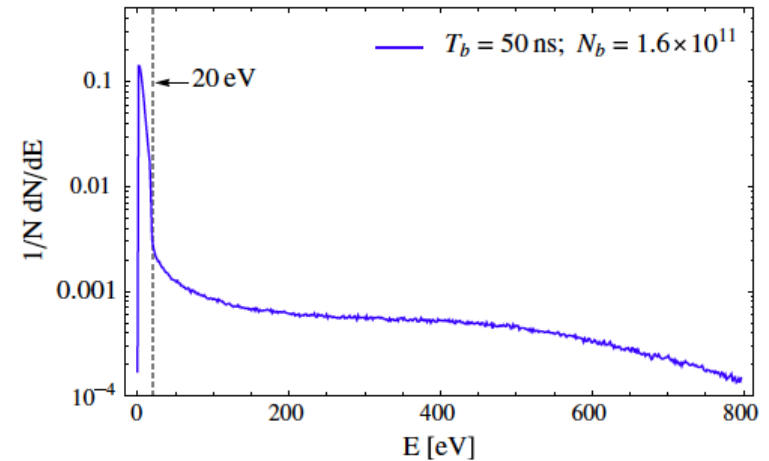
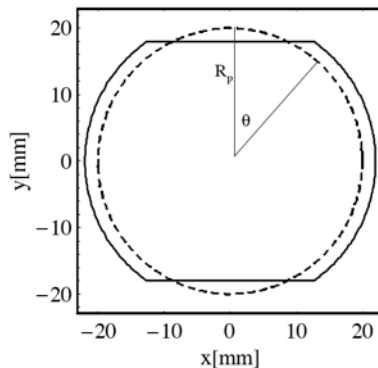


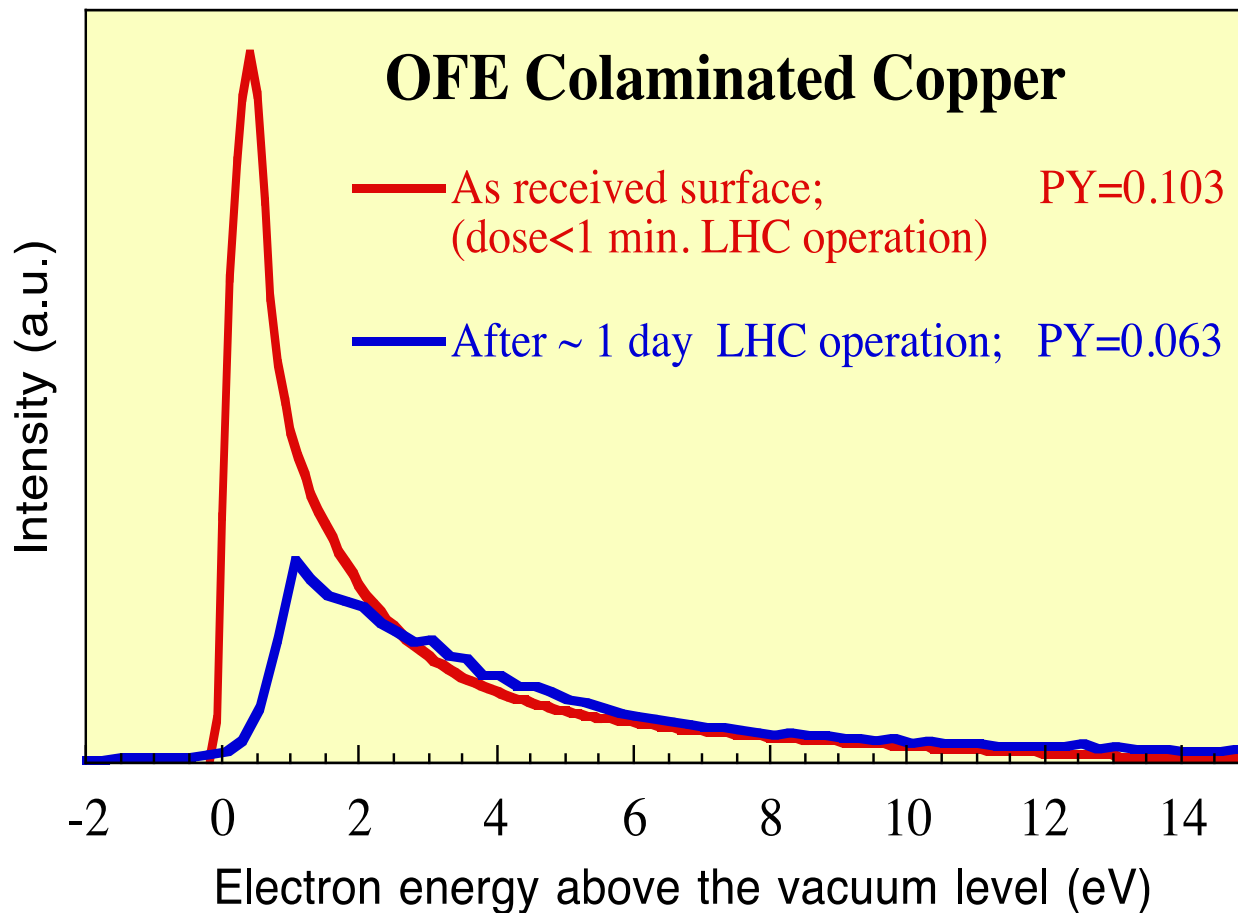
FIG. 3 (color online). Calculated electron energy distribution at the LHC accelerator wall. The number of electrons below and above 20 eV (dotted line) is nearly equal.



- optimize the “scrubbing” process @ LHC with beam parameters enhancing the presence, in the cloud, of higher energy el.
- Give a more reliable estimate of the needed scrubbing time.

R. Cimino et al. PRL **109** 064801 (2012)

Beam scrubbing effect with photon



See: R. Cimino et al Phys. Rev. AB-ST 2 063201 (1999)

External solenoid field.



Not always possible...

Electrodes in the lattice.



If possible...
(Impedance, costs.)

Scrubbing
(or conditioning)



-Efficiency
(time & final SEY)...

Intrinsically low
SEY material



Stability and material
choice...

Geometrical
modifications



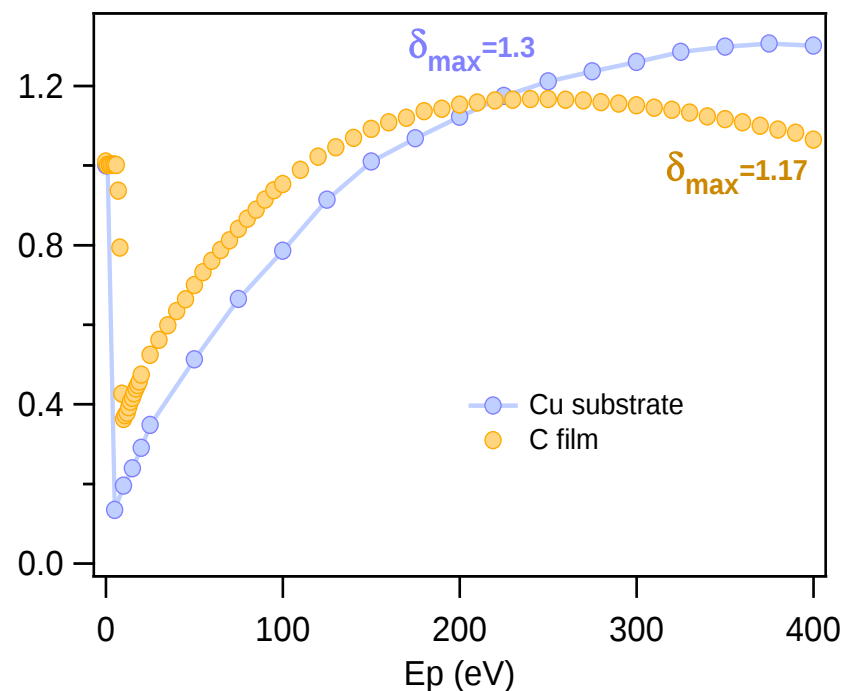
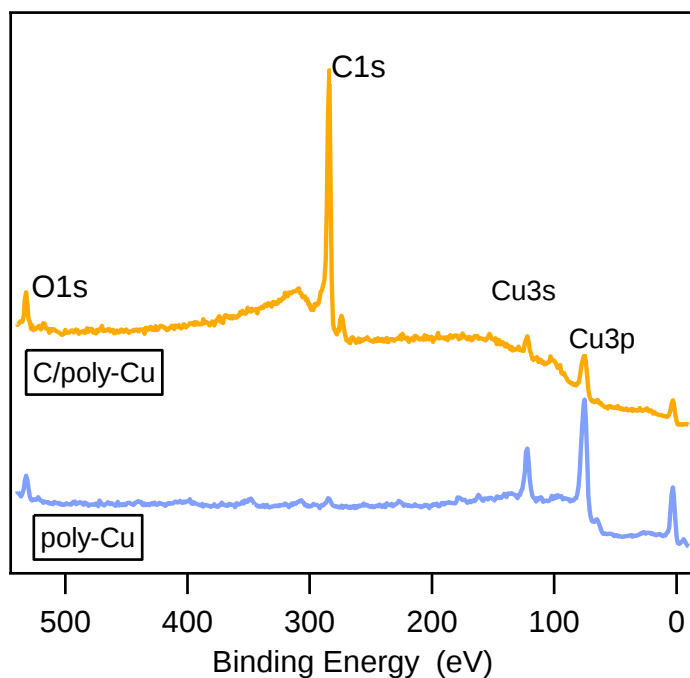
Impedance. Space,
Machining costs.

C films on polycrystalline Cu

a-C films

magnetron sputtering @ RT
 $p(\text{Ar}) = 10^{-2}$ mbar $\Delta t = 2$ min

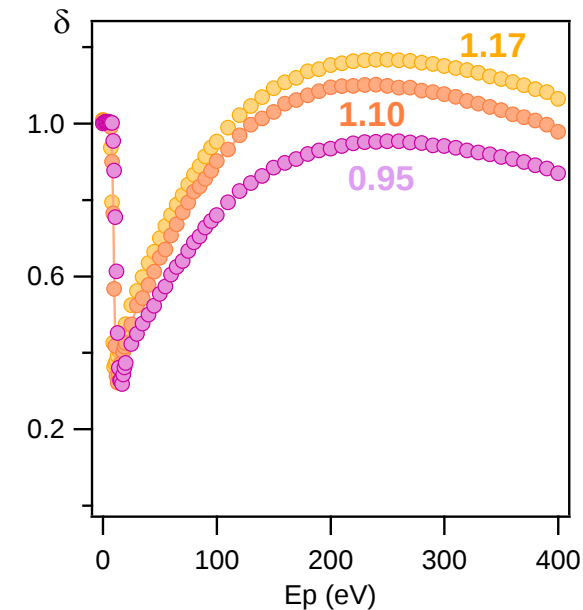
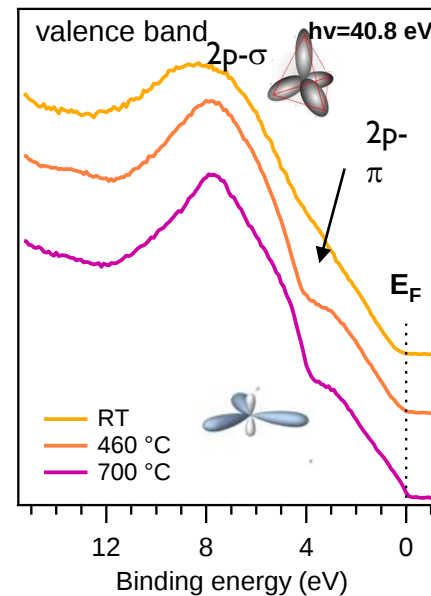
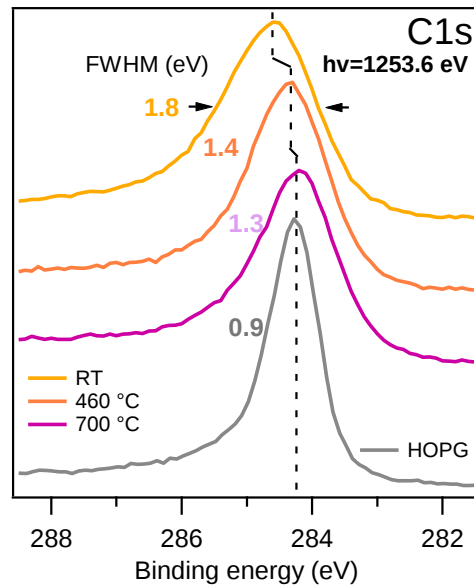
C film thickness 2-3 nm



R. Larciprete et al, App. Surf. Science 2015

C films on polycrystalline Cu

the graphitization of the C films corresponds to a lower SEY



a-C bases its stability on its low reactivity

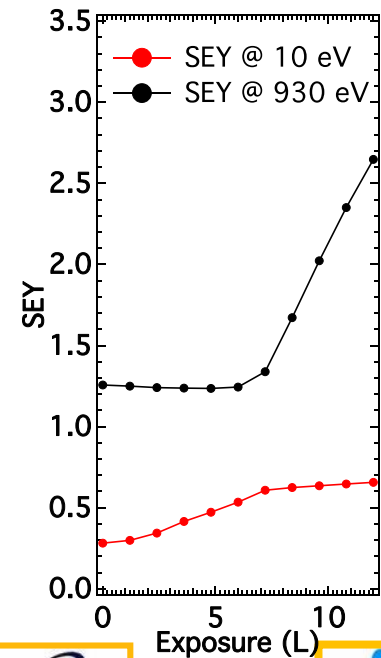
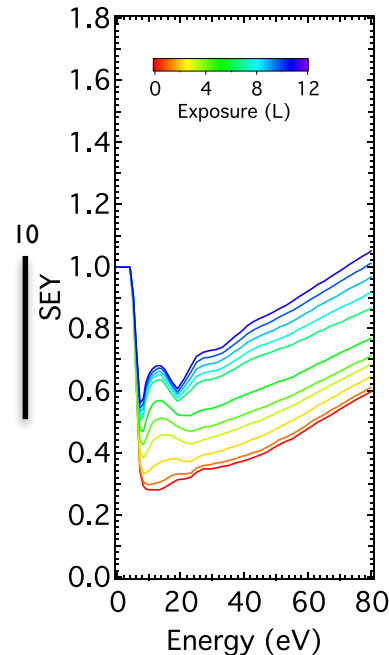
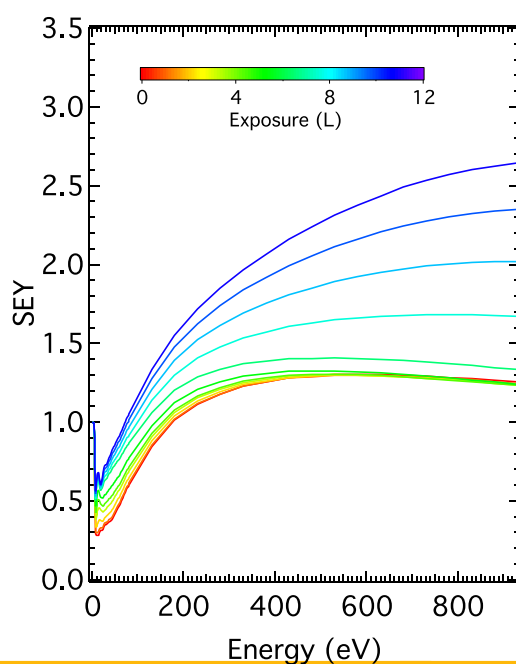
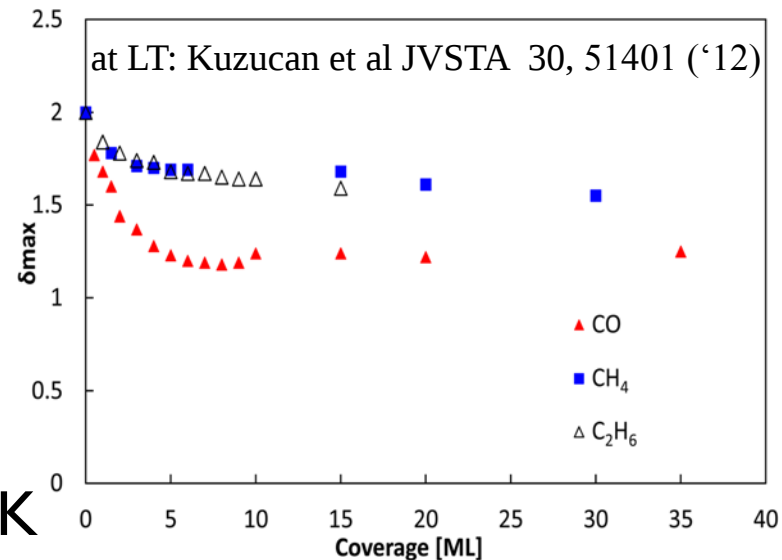
R. Larciprete et al, App. Surf. Science 2015

**If condensed gas is
physi-sorbed on a cold
the surface the
resulting SEY will be
the one of the
contaminant layer.**

Argon on Clean Cu sample at 10 K

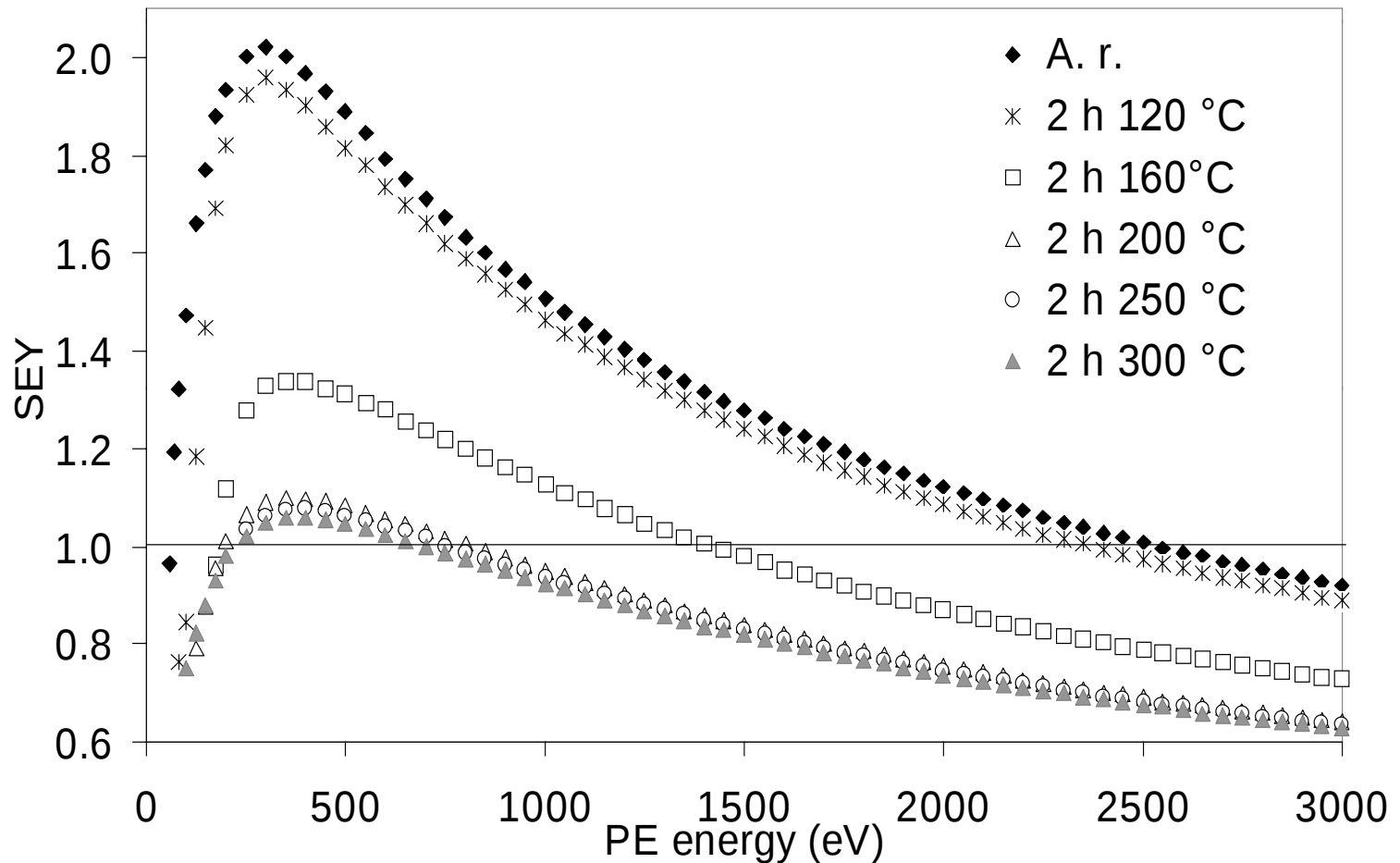
(see M. Angelucci et al: EuroCirCol coll and

@ Beam Dynamics meets Vacuum, Collimations, and Surfaces 2017)



If annealing (@ ~ 200 °C) is possible: TiZrV

Scheuerlein et al. *Appl. Surf. Sci.* 172 (2001) 95-102



**Activated NEG: it pumps, low SEY, stable: ideal mitigator
... If Resistive Wall Impedance is acceptable.**

External solenoid field.



Not always possible...

Electrodes in the lattice.



If possible...
(Impedance, costs.)

Scrubbing
(or conditioning)



-Efficiency
(time & final SEY)...

Intrinsically low
SEY material



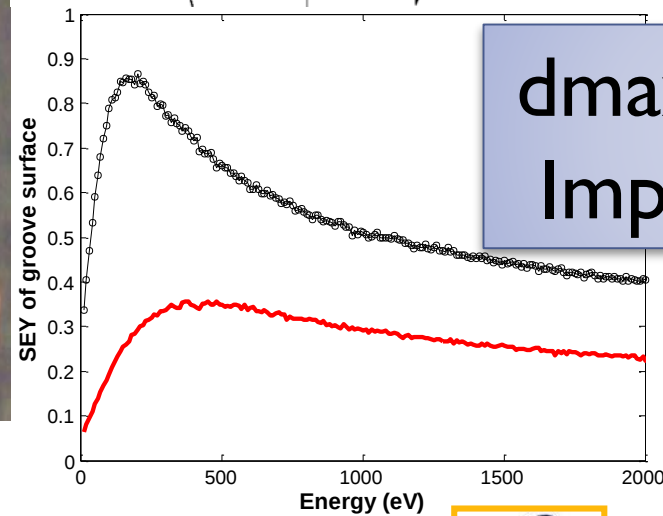
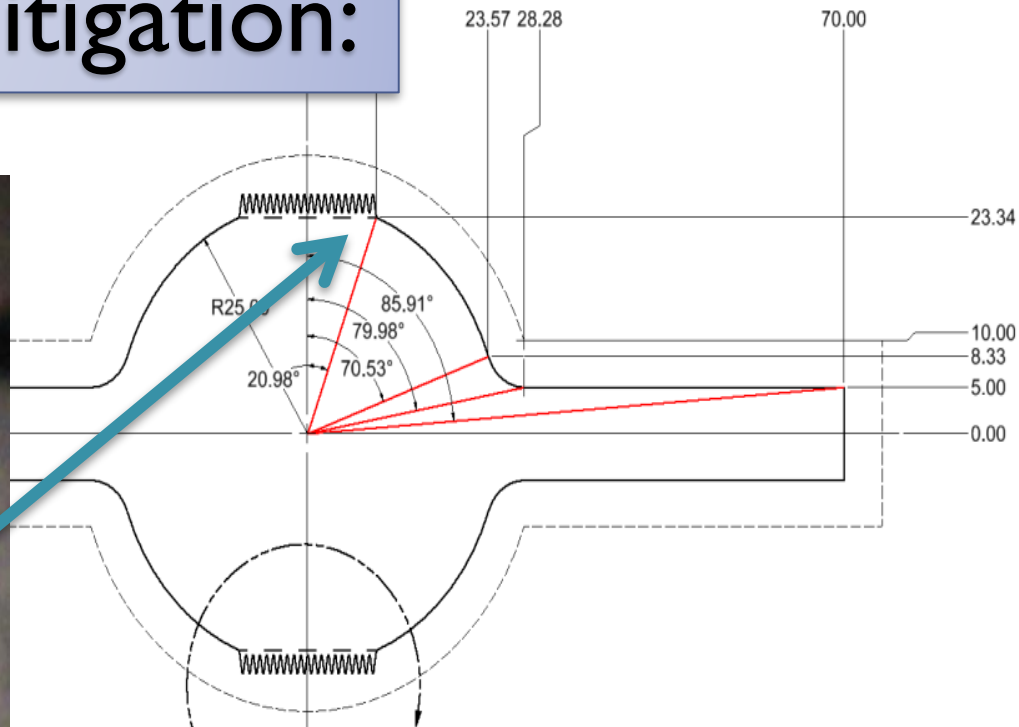
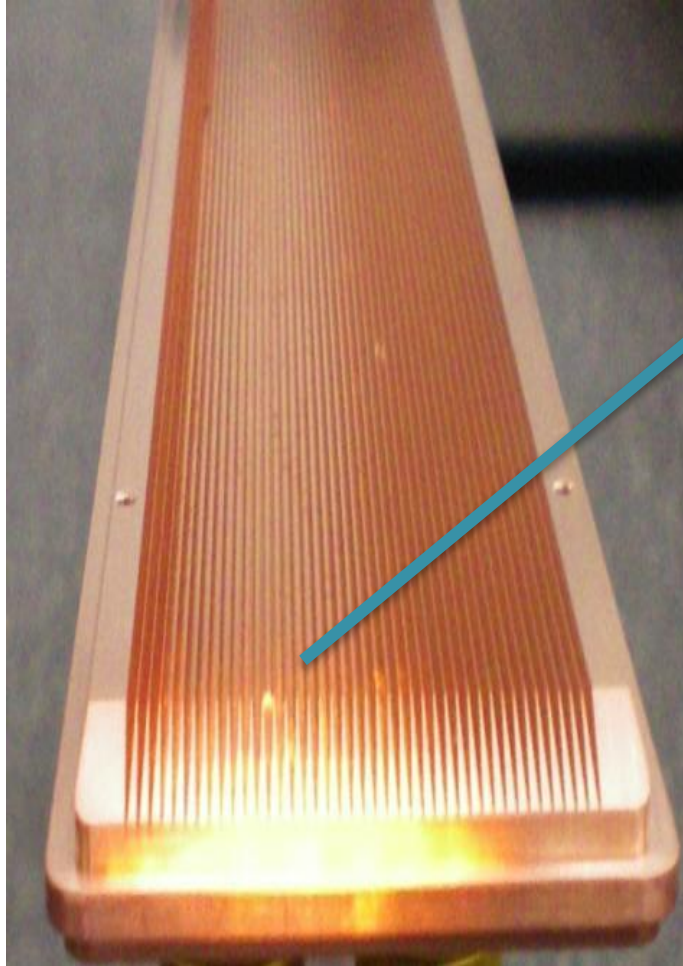
Stability and material
choice...

Geometrical
modifications



Impedance. Space,
Machining costs.

Geometrical Mitigation:



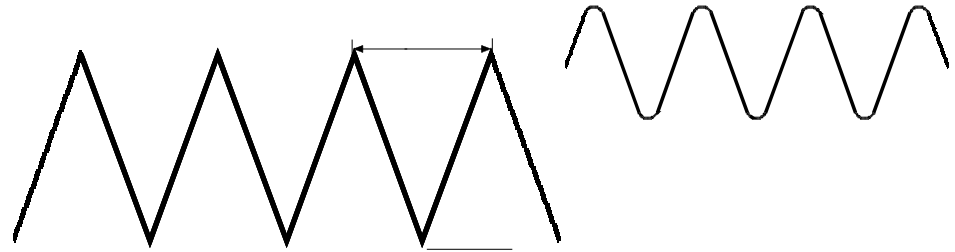
$d_{max} < .8 \dots$
Impedance?

See: .A. Krasnov, Vacuum 73, 195 (2004).
M. T. F. Pivi et al., J. Appl. Phys. 104, 104904 (2008).

Impedance enhancement factor

(Code : Finite Element Method, PAC07 THPAS067, L Wang)

$$h = \frac{Z_{\text{grooved surface}}}{Z_{\text{smooth surface}}} = \frac{\oint H^2 ds}{H_0^2 W}$$



*The total impedance enhancement = η * percentage of grooved surface*

$p = 1.25\text{mm}$ (period)

$d = 2.5\text{mm}$ (depth)

$t = 0.125\text{mm}$ (thickness)

$$h = 1.64$$

$p = 1.25\text{mm}$

$d = 2.5\text{mm}$

$t = 0.25\text{mm}$

$$h = 1.42$$

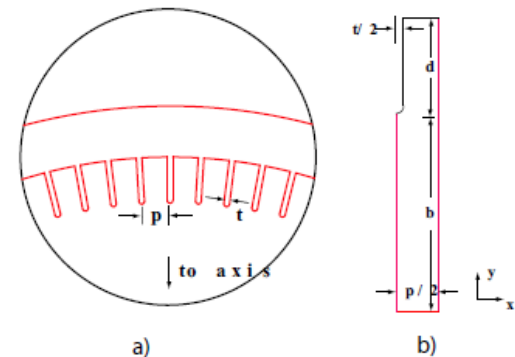
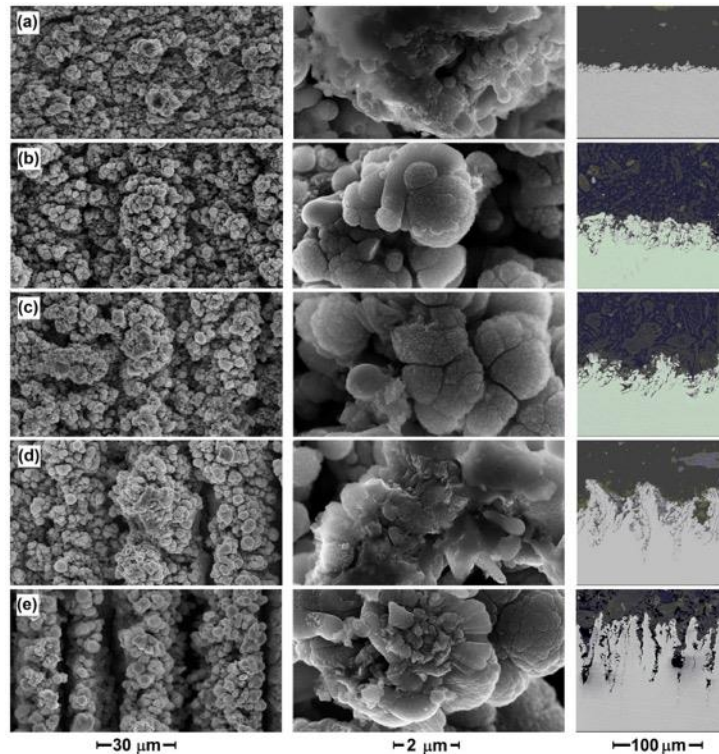


Figure 1: a) detail of the grooved vacuum chamber wall; dimensions shown are period p and fin thickness t ; b) cross-section of the grooved vacuum chamber wall showing dimensions $p/2$, d , b , and $t/2$.

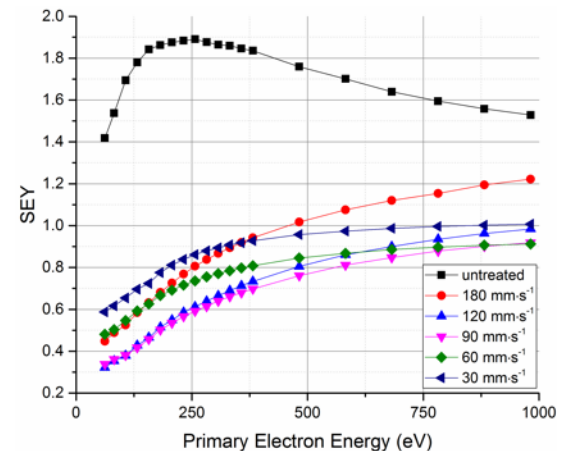
micro/nano geometrical effects

laser treatment for e⁻cloud mitigation



Investigation at **STFC** includes:

- Laser scan speed
- Laser wavelength



See: R.Valizadeh, O.B. Malyshev, S.Wang, T. Sian, M. D. Cropper and N. Sykes. Reduction of Secondary Electron Yield for E-cloud Mitigation by Laser Ablation Surface Engineering. Appl. Surf. Sci. 404 (2017) 370–379

See also: I85. I. Montero et al., in Proc. ECLLOUD'12, CERN-2013-002

Conclusion

- The beam interact with the accelerator wall and the accelerator wall interact with the beam.
- Electron-Cloud is and will be an important issue in circular accelerators in years to come!
- Numerical simulations are able to predict observed effects.
- Mitigation techniques are developing.
- **Synergic efforts, dedicated Surface, Material and Vacuum science laboratories are required to reach desired performances.**
- **Still a lot of interesting R&D!**

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Amolo, G.

at. Lab., USA

Institute for Nanometre Optics
gy (INT) Berlin

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which will reconvene in Isola D'Elba
The 2-7 June 2018

Amolo, G.

at. Lab., USA

Institute for Nanometre Optics
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